

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				2 *****
				3 *
				4 * Zvector E7 instruction tests for VRR-a encoded:
				5 *
				6 * E75C VISTR - Vector Isolate String
				7 *
				8 * James Wekel February 2025
				9 *****
				11 *****
				12 *
				13 * basic instruction tests
				14 *
				15 *****
				16 * This program tests proper functioning of the z/arch E7 VRR-a
				17 * Vector Isolate String instruction.
				18 * Exceptions are not tested.
				19 *
				20 * PLEASE NOTE that the tests are very SIMPLE TESTS designed to catch
				21 * obvious coding errors. None of the tests are thorough. They are
				22 * NOT designed to test all aspects of any of the instructions.
				23 *
				24 *****
				25 *
				26 * *Testcase zvector-e7-08-VISTR
				27 * *
				28 * * Zvector E7 instruction tests for VRR-a encoded:
				29 * *
				30 * * E75C VISTR - Vector Isolate String
				31 * *
				32 * * # -----
				33 * * # This tests only the basic function of the instruction.
				34 * * # Exceptions are NOT tested.
				35 * * # -----
				36 * *
				37 * main size 2
				38 * numcpu 1
				39 * sysclear
				40 * archlvl z/Arch
				41 * *
				42 * loadcore "\$(testpath)/zvector-e7-08-VISTR.core" 0x0
				43 * *
				44 * diag8cmd enable # (needed for messages to Hercules console)
				45 * runtest 10 #
				46 * diag8cmd disable # (reset back to default)
				47 * *
				48 * *Done
				49 * *
				50 *****

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				52 *****
				53 * FCHECK Macro - Is a Facility Bit set?
				54 *
				55 * If the facility bit is NOT set, an message is issued and
				56 * the test is skipped.
				57 *
				58 * Fcheck uses R0, R1 and R2
				59 *
				60 * eg. FCHECK 134, 'vector-packed-decimal'
				61 *****
				62 MACRO
				63 FCHECK &BITNO, &NOTSETMSG
				64 . * &BITNO : facility bit number to check
				65 . * &NOTSETMSG : 'facility name'
				66 LCLA &FBBYTE Facility bit in Byte
				67 LCLA &FBBIT Facility bit within Byte
				68
				69 LCLA &L(8)
				70 &L(1) SetA 128, 64, 32, 16, 8, 4, 2, 1 bit positions within byte
				71
				72 &FBBYTE SETA &BITNO/8
				73 &FBBIT SETA &L((&BITNO-(&FBBYTE*8))+1)
				74 . * MNOTE 0, 'checking Bit=&BITNO: FBBYTE=&FBBYTE, FBBIT=&FBBIT'
				75
				76 B X&SYSNDX
				77 * Fcheck data area
				78 * skip messgae
				79 SKT&SYSNDX DC C' Skipping tests: '
				80 DC C&NOTSETMSG
				81 DC C' (bit &BITNO) is not installed.'
				82 SKL&SYSNDX EQU *-SKT&SYSNDX
				83 * facility bits
				84 DS FD gap
				85 FB&SYSNDX DS 4FD
				86 DS FD gap
				87 *
				88 X&SYSNDX EQU *
				89 LA R0, ((X&SYSNDX- FB&SYSNDX)/8)-1
				90 STFLE FB&SYSNDX get facility bits
				91
				92 XGR R0, R0
				93 IC R0, FB&SYSNDX+&FBBYTE get fbit byte
				94 N R0, =F' &FBBIT' is bit set?
				95 BNZ XC&SYSNDX
				96 *
				97 * facility bit not set, issue message and exit
				98 *
				99 LA R0, SKL&SYSNDX message length
				100 LA R1, SKT&SYSNDX message address
				101 BAL R2, MSG
				102
				103 B EOJ
				104 XC&SYSNDX EQU *
				105 MEND

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				107	*****
				108	* Low core PSWs
				109	*****
00000000		00000000	0000438F	110	ZVE7TST START 0
		00000000		111	USING ZVE7TST, R0 Low core addressability
		00000140	00000000	112	
				113	SVOLDPSW EQU ZVE7TST+X' 140' z/Arch Supervisor call old PSW
00000000		00000000	000001A0	115	ORG ZVE7TST+X' 1A0' z/Architecture RESTART PSW
000001A0	00000001 80000000			116	DC X' 0000000180000000'
000001A8	00000000 00000200			117	DC AD(BEGIN)
000001B0		000001B0	000001D0	119	ORG ZVE7TST+X' 1D0' z/Architecture PROGRAM CHECK PSW
000001D0	00020001 80000000			120	DC X' 0002000180000000'
000001D8	00000000 0000DEAD			121	DC AD(X' DEAD')
000001E0		000001E0	00000200	123	ORG ZVE7TST+X' 200' Start of actual test program..
				125	*****
				126	* The actual "ZVE7TST" program itself...
				127	*****
				128	*
				129	* Architecture Mode: z/Arch
				130	* Register Usage:
				131	*
				132	* R0 (work)
				133	* R1- 4 (work)
				134	* R5 Testing control table - current test base
				135	* R6- R7 (work)
				136	* R8 First base register
				137	* R9 Second base register
				138	* R10 Third base register
				139	* R11 E7TEST call return
				140	* R12 E7TESTS register
				141	* R13 (work)
				142	* R14 Subroutine call
				143	* R15 Secondary Subroutine call or work
				144	*
				145	*****
00000200		00000200		147	USING BEGIN, R8 FIRST Base Register
00000200		00001200		148	USING BEGIN+4096, R9 SECOND Base Register
00000200		00002200		149	USING BEGIN+8192, R10 THIRD Base Register
00000200	0580			151	BEGIN BALR R8, 0 Initialize FIRST base register
00000202	0680			152	BCTR R8, 0 Initialize FIRST base register
00000204	0680			153	BCTR R8, 0 Initialize FIRST base register
00000206	4190 8800		00000800	155	LA R9, 2048(, R8) Initialize SECOND base register
0000020A	4190 9800		00000800	156	LA R9, 2048(, R9) Initialize SECOND base register
				157	

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						233 *****	
						234 * cc was not as expected	
				0000031C	00000001	235 *****	
						236 CCMMSG EQU *	
						237 *	
						238 * is CS set by test?	
						239 *	
0000031C	E310	5008	0076		00000008	240 LB R1, M5	Get M5
00000322	E310	8360	0080		00000560	241 NG R1, =D' 1'	issolate CS
00000328	4780	8100			00000300	242 BZ TESTREST	not set?
						243 *	
						244 * extract CC from extracted PSW	
						245 *	
0000032C	5810	500C			0000000C	246 L R1, CCPSW	
00000330	8810	000C			0000000C	247 SRL R1, 12	
00000334	5410	8370			00000570	248 N R1, =XL4' 3'	
00000338	4210	5014			00000014	249 STC R1, CCFOUND	save cc
						250 *	
						251 * FILL IN MESSAGE	
						252 *	
0000033C	4820	5004			00000004	253 LH R2, TNUM	get test number and convert
00000340	4E20	8ED6			000010D6	254 CVD R2, DECNUM	
00000344	D211	8EC0	8EAA	000010C0	000010AA	255 MVC PRT3, EDIT	
0000034A	DE11	8EC0	8ED6	000010C0	000010D6	256 ED PRT3, DECNUM	
00000350	D202	8E65	8ECD	00001065	000010CD	257 MVC CCPRTNUM(3), PRT3+13	fill in message with test #
						258	
00000356	D207	8E82	5015	00001082	00000015	259 MVC CCPRTNAME, OPNAME	fill in message with instruction
						260	
0000035C	B982	0022				261 XGR R2, R2	get CC as U8
00000360	4320	5009			00000009	262 IC R2, CC	
00000364	4E20	8ED6			000010D6	263 CVD R2, DECNUM	and convert
00000368	D211	8EC0	8EAA	000010C0	000010AA	264 MVC PRT3, EDIT	
0000036E	DE11	8EC0	8ED6	000010C0	000010D6	265 ED PRT3, DECNUM	
00000374	D200	8E98	8ECF	00001098	000010CF	266 MVC CCPRTEXP(1), PRT3+15	fill in message with CC field
						267	
0000037A	B982	0022				268 XGR R2, R2	get CCFOUND as U8
0000037E	4320	5014			00000014	269 IC R2, CCFOUND	
00000382	4E20	8ED6			000010D6	270 CVD R2, DECNUM	and convert
00000386	D211	8EC0	8EAA	000010C0	000010AA	271 MVC PRT3, EDIT	
0000038C	DE11	8EC0	8ED6	000010C0	000010D6	272 ED PRT3, DECNUM	
00000392	D200	8EA8	8ECF	000010A8	000010CF	273 MVC CCPRTGOT(1), PRT3+15	fill in message with ccfound
						274	
00000398	4100	0055			00000055	275 LA R0, CCPRTLNG	message length
0000039C	4110	8E55			00001055	276 LA R1, CCPRTLNE	messagfe address
000003A0	45F0	8236			00000436	277 BAL R15, RPTERROR	
						278	
000003A4	5800	8374			00000574	279 L R0, =F' 1'	set failed test indicator
000003A8	5000	8E00			00001000	280 ST R0, FAILED	
						281	
000003AC	47F0	8100			00000300	282 B TESTREST	
						283	

LOC	OBJECT CODE			ADDR1	ADDR2	STMT	
						285	*****
						286	* result not as expected:
						287	* issue message with test number, instruction under test
						288	* and instruction M3, M5
						289	*****
				000003B0	00000001	290	FAILMSG EQU *
000003B0	4820	5004			00000004	291	LH R2, TNUM get test number and convert
000003B4	4E20	8ED6			000010D6	292	CVD R2, DECNUM
000003B8	D211	8EC0 8EAA		000010C0	000010AA	293	MVC PRT3, EDIT
000003BE	DE11	8EC0 8ED6		000010C0	000010D6	294	ED PRT3, DECNUM
000003C4	D202	8E18 8ECD		00001018	000010CD	295	MVC PRTNUM(3), PRT3+13 fill in message with test #
						296	
000003CA	D207	8E33 5015		00001033	00000015	297	MVC PRTNAME, OPNAME fill in message with instruction
						298	
000003D0	B982	0022				299	XGR R2, R2 get M3 as U8
000003D4	4320	5007			00000007	300	IC R2, M3
000003D8	4E20	8ED6			000010D6	301	CVD R2, DECNUM and convert
000003DC	D211	8EC0 8EAA		000010C0	000010AA	302	MVC PRT3, EDIT
000003E2	DE11	8EC0 8ED6		000010C0	000010D6	303	ED PRT3, DECNUM
000003E8	D202	8E44 8ECD		00001044	000010CD	304	MVC PRTM3(3), PRT3+13 fill in message with M3 field
						305	
000003EE	B982	0022				306	XGR R2, R2 get M5 as U8
000003F2	4320	5008			00000008	307	IC R2, M5
000003F6	4E20	8ED6			000010D6	308	CVD R2, DECNUM and convert
000003FA	D211	8EC0 8EAA		000010C0	000010AA	309	MVC PRT3, EDIT
00000400	DE11	8EC0 8ED6		000010C0	000010D6	310	ED PRT3, DECNUM
00000406	D202	8E51 8ECD		00001051	000010CD	311	MVC PRTM5(3), PRT3+13 fill in message with M5 field
						312	
0000040C	4100	004D			0000004D	313	LA R0, PRTLNG message length
00000410	4110	8E08			00001008	314	LA R1, PRTLNE messagfe address
00000414	45F0	8236			00000436	315	BAL R15, RPTERROR
						317	*****
						318	* continue after a failed test
						319	*****
				00000418	00000001	320	FAILCONT EQU *
00000418	5800	8374			00000574	321	L R0, =F' 1' set failed test indicator
0000041C	5000	8E00			00001000	322	ST R0, FAILED
						323	
00000420	41C0	C004			00000004	324	LA R12, 4(0, R12) next test address
00000424	47F0	80D4			000002D4	325	B NEXTE7
						327	*****
						328	* end of testing; set ending psw
						329	*****
				00000428	00000001	330	ENDTEST EQU *
00000428	5810	8E00			00001000	331	L R1, FAILED did a test fail?
0000042C	1211					332	LTR R1, R1
0000042E	4780	8338			00000538	333	BZ EOJ No, exit
00000432	47F0	8350			00000550	334	B FAILTEST Yes, exit with BAD PSW

LOC	OBJECT CODE	ADDR1	ADDR2	STMT				
				336	*****			
				337	*	RPTERROR	Report instruction test in error	
				338	*		R0 = MESSGAE LENGTH	
				339	*		R1 = ADDRESS OF MESSAGE	
				340	*****			
00000436	50F0 8254		00000454	342	RPTERROR	ST	R15, RPTSAVE	Save return address
0000043A	5050 8258		00000458	343		ST	R5, RPTSVR5	Save R5
				344	*			
				345	*	Use Hercules Diagnose for Message to console		
				346	*			
0000043E	9002 8260		00000460	347		STM	R0, R2, RPTDWSAV	save regs used by MSG
00000442	4520 8270		00000470	348		BAL	R2, MSG	call Hercules console MSG display
00000446	9802 8260		00000460	349		LM	R0, R2, RPTDWSAV	restore regs
0000044A	5850 8258		00000458	351		L	R5, RPTSVR5	Restore R5
0000044E	58F0 8254		00000454	352		L	R15, RPTSAVE	Restore return address
00000452	07FF			353		BR	R15	Return to caller
00000454	00000000			355	RPTSAVE	DC	F' 0'	R15 save area
00000458	00000000			356	RPTSVR5	DC	F' 0'	R5 save area
00000460	00000000 00000000			358	RPTDWSAV	DC	2D' 0'	R0-R2 save area for MSG call
				360	*****			
				361	*	Issue HERCULES MESSAGE pointed to by R1, length in R0		
				362	*	R2 = return address		
				363	*****			
00000470	4900 8378		00000578	365	MSG	CH	R0, =H' 0'	Do we even HAVE a message?
00000474	07D2			366		BNHR	R2	No, ignore
00000476	9002 82AC		000004AC	368		STM	R0, R2, MSGSAVE	Save registers
0000047A	4900 837A		0000057A	370		CH	R0, =AL2(L' MSGMSG)	Message length within limits?
0000047E	47D0 8286		00000486	371		BNH	MSGOK	Yes, continue
00000482	4100 005F		0000005F	372		LA	R0, L' MSGMSG	No, set to maximum
00000486	1820			374	MSGOK	LR	R2, R0	Copy length to work register
00000488	0620			375		BCTR	R2, 0	Minus-1 for execute
0000048A	4420 82B8		000004B8	376		EX	R2, MSGMVC	Copy message to O/P buffer
0000048E	4120 200A		0000000A	378		LA	R2, 1+L' MSGCMD(, R2)	Calculate true command length
00000492	4110 82BE		000004BE	379		LA	R1, MSGCMD	Point to true command
00000496	83120008			381		DC	X' 83' , X' 12' , X' 0008'	Issue Hercules Diagnose X' 008'
0000049A	4780 82A6		000004A6	382		BZ	MSGRET	Return if successful
				383				
0000049E	1222			384		LTR	R2, R2	Is Diag8 Ry (R2) 0?
000004A0	4780 82A6		000004A6	385		BZ	MSGRET	an error occurred but coninue
				386				
000004A4	0000			387		DC	H' 0'	CRASH for debugging purposes
000004A6	9802 82AC		000004AC	389	MSGRET	LM	R0, R2, MSGSAVE	Restore registers

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				437 *=====
				438 *
				439 * NOTE: start data on an address that is easy to display
				440 * within Hercules
				441 *
				442 *=====
				443
0000057C		0000057C	00001000	444
00001000	00000000			445 FAILED DC F' 0' some test failed?
00001004	00000000			446 TESTING DC F' 0' current test number
				448 *****
				449 * TEST failed : result messgae
				450 *****
				451 *
				452 * failed message and associated editing
				453 *
00001008	40404040	40404040		454 PRTLNE DC C' Test # '
00001018	A7A7A7			455 PRTNUM DC C' xxx'
0000101B	40868189	93858440		456 DC C' failed for instruction '
00001033	A7A7A7A7	A7A7A7A7		457 PRTNAME DC CL8' xxxxxxxx'
0000103B	40A689A3	8840D4F3		458 DC C' with MB=
00001044	A7A7A7			459 PRTMB DC C' xxx'
00001047	6B			460 DC C' ,'
00001048	40A689A3	8840D4F5		461 DC C' with MB=
00001051	A7A7A7			462 PRTMB DC C' xxx'
00001054	4B			463 DC C' .'
		0000004D	00000001	464 PRTLNG EQU *- PRTLNE
				465
				466 *****
				467 * TEST failed : CC message
				468 *****
				469 *
				470 * failed message and associated editing
				471 *
00001055	40404040	40404040		472 CCPRTLNE DC C' Test # '
00001065	A7A7A7			473 CCPRTNUM DC C' xxx'
00001068	40A69996	95874083		474 DC c' wrong cc for instruction '
00001082	A7A7A7A7	A7A7A7A7		475 CCPRTNAME DC CL8' xxxxxxxx'
0000108A	4085A797	8583A385		476 DC C' expected: cc=
00001098	A7			477 CCPRTEXP DC C' x'
00001099	6B			478 DC C' ,'
0000109A	40998583	8589A585		479 DC C' received: cc=
000010A8	A7			480 CCPRTGOT DC C' x'
000010A9	4B			481 DC C' .'
		00000055	00000001	482 CCPRTLNG EQU *- CCPRTLNE

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				484 *****
				485 * TEST failed : message working storge
				486 *****
000010AA	40212020	20202020		487 EDIT DC XL18' 40212020202020202020202020202020'
				488
000010BC	7E7E7E6E			489 DC C' ==>'
000010C0	40404040	40404040		490 PRT3 DC CL18' '
000010D2	4C7E7E7E			491 DC C' <==='
000010D6	00000000	00000000		492 DECNUM DS CL16
				494 *****
				495 * Vector instruction results, pollution and input
				496 *****
000010E8				497 DS 0F
000010E8	00000000	00000000		498 DS XL16
000010F8	FFFFFFFF	FFFFFFFF		499 V1FUDGE DC XL16' FFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFFF' V1 FUDGE
00001108	00000000	00000000		500 DS XL16
				502 *****
				503 * E7TEST DSECT
				504 *****
				506 E7TEST DSECT ,
00000000	00000000			507 TSUB DC A(0) pointer to test
00000004	0000			508 TNUM DC H' 00' Test Number
00000006	00			509 DC X' 00'
00000007	00			510 M3 DC HL1' 00' M3 used
00000008	00			511 M5 DC HL1' 00' M5 used
00000009	00			512 CC DC HL1' 00' cc expected
0000000A	00			513 CCMASK DC HL1' 00' not expected CC mask
				514 *
				515 * CC extrtaction
				516 *
0000000C	00000000	00000000		517 CCPSW DS 2F extract PSW after test (has CC)
00000014	00			518 CCFOUND DS X extracted cc
				519
00000015	40404040	40404040		520 OPNAME DC CL8' ' E7 name
00000020	00000000			521 V1ADDR DC A(0) address of v1 result
00000024	00000000			522 V2ADDR DC A(0) address of v2 source
00000028	00000000			523 V3ADDR DC A(0) address of v3 source
0000002C	00000000			524 RELEN DC A(0) RESULT LENGTH
00000030	00000000			525 READDR DC A(0) result (expected) address
00000038	00000000	00000000		526 DS FD gap
00000040	00000000	00000000		527 V1OUTPUT DS XL16 V1 Output
00000050	00000000	00000000		528 DS FD gap
				529
				530 * test routine will be here (from VRR-a macro)
				531 *
				532 * followed by
				533 * EXPECTED RESULT

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
00001118		00000000	0000438F	535 ZVE7TST CSECT , 536 DS OF	
				538 *****	
				539 * Macros to help build test tables	
				540 *****	
				542 *	
				543 * macro to generate individual test	
				544 *	
				545 MACRO	
				546 VRR_A &INST, &MB, &M5, &CC	
				547 . *	&INST - VRR-a instruction under test
				548 . *	&MB - MB field - element size
				549 . *	&M5 - M5 field - CS
				550 . *	&CC - expected CC
				551	
				552 LCLA &XCC(4) &XCC has	mask values for FAILED condition codes
				553 &XCC(1) SETA 7	CC != 0
				554 &XCC(2) SETA 11	CC != 1
				555 &XCC(3) SETA 13	CC != 2
				556 &XCC(4) SETA 14	CC != 3
				557	
				558 GBLA &TNUM	
				559 &TNUM SETA &TNUM+1	
				560	
				561 DS OFD	
				562 USING *, R5	base for test data and test routine
				563	
				564 T&TNUM DC A(X&TNUM)	address of test routine
				565 DC H' &TNUM	test number
				566 DC X' 00'	
				567 DC HL1' &MB'	MB used
				568 DC HL1' &M5'	M5 used
				569 DC HL1' &CC'	CC
				570 DC HL1' &XCC(&CC+1)'	CC failed mask
				571	
				572 DS 2F	extracted PSW after test (has CC)
				573 DC X' FF'	extracted CC, if test failed
				574	
				575 DC CL8' &INST'	instruction name
				576 DC A(RE&TNUM)	address of v1 result
				577 DC A(RE&TNUM+16)	address of v2 source
				578 DC A(RE&TNUM+32)	address of v3 source
				579 DC A(16)	result length
				580 REA&TNUM DC A(RE&TNUM)	result address
				581 DS FD	gap
				582 V10&TNUM DS XL16	V1 output
				583 DS FD	gap
				584 . *	
				585 *	
				586 X&TNUM DS OF	
				587 LA R1, V1FUDGE	load v21 fudge
				588 VL v21, 0(R1)	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				630 *****	
				631 * E7 VRR-a tests	
				632 *****	
				633 PRINT DATA	
				634 *	
				635 *	
				636 * E75C VISTR - Vector Isolate String	
				637 *	
				638 * VRR-a instruction,	
				639 * M3,	element size
				640 * M5,	CS
				641 * CC	expected condition code
				642 *	
				643 * followed by	
				644 * 16 byte V1 result	
				645 * 16 byte V2 source	
				646	
				647 * -----	
				648 * VISTR - Vector Isolate String	
				649 * -----	
				650	
				651 * -----	
				652 * case 0 - simple debug	CS=1
				653 * -----	
				654 *byte	
				655 VRR_A VISTR, 0, 1, 0	
00001118				656+ DS OFD	
00001118		00001118		657+ USING *, R5	base for test data and test routine
00001118	00001170			658+T1 DC A(X1)	address of test routine
0000111C	0001			659+ DC H' 1'	test number
0000111E	00			660+ DC X' 00'	
0000111F	00			661+ DC HL1' 0'	M3 used
00001120	01			662+ DC HL1' 1'	M5 used
00001121	00			663+ DC HL1' 0'	CC
00001122	07			664+ DC HL1' 7'	CC failed mask
00001124	00000000 00000000			665+ DS 2F	extracted PSW after test (has CC)
0000112C	FF			666+ DC X' FF'	extracted CC, if test failed
0000112D	E5C9E2E3 D9404040			667+ DC CL8' VISTR'	instruction name
00001138	0000119C			668+ DC A(RE1)	address of v1 result
0000113C	000011AC			669+ DC A(RE1+16)	address of v2 source
00001140	000011BC			670+ DC A(RE1+32)	address of v3 source
00001144	00000010			671+ DC A(16)	result length
00001148	0000119C			672+REA1 DC A(RE1)	result address
00001150	00000000 00000000			673+ DS FD	gap
00001158	00000000 00000000			674+V101 DS XL16	V1 output
00001160	00000000 00000000				
00001168	00000000 00000000			675+ DS FD	gap
				676+ *	
00001170				677+X1 DS OF	
00001170	4110 8EF8		000010F8	678+ LA R1, V1FUDGE	load v21 fudge
00001174	E751 0000 0806		00000000	679+ VL v21, 0(R1)	
0000117A	E310 5024 0014		00000024	680+ LGF R1, V2ADDR	load v2 source
00001180	E761 0000 0806		00000000	681+ VL v22, 0(R1)	use v21 to test decoder
00001186	E756 0010 0C5C			682+ VISTR V21, V22, 0, 1	test instruction
0000118C	B98D 0020			683+ EPSW R2, R0	extract psw
00001190	5020 500C		0000000C	684+ ST R2, CCPSW	to save CC

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001194	E750 5040 080E		00001158	685+	VST	V21, V101	save v1 output		
0000119A	07FB			686+	BR	R11	return		
0000119C				687+RE1	DC	0F	V1 for this test		
0000119C				688+	DROP	R5			
0000119C	00000000 00000000			689	DC	XL16' 00000000 00000000 00000000 00000000'	V1		
000011A4	00000000 00000000								
000011AC	00000000 00000000			690	DC	XL16' 00000000 00000000 00000000 00000000'	v2		
000011B4	00000000 00000000								
				691					
				692	VRR_A	VISTR, 0, 1, 0			
000011C0				693+	DS	0FD			
000011C0		000011C0		694+	USING	*, R5	base for test data and test routine		
000011C0	00001218			695+T2	DC	A(X2)	address of test routine		
000011C4	0002			696+	DC	H' 2'	test number		
000011C6	00			697+	DC	X' 00'			
000011C7	00			698+	DC	HL1' 0'	MB used		
000011C8	01			699+	DC	HL1' 1'	M5 used		
000011C9	00			700+	DC	HL1' 0'	CC		
000011CA	07			701+	DC	HL1' 7'	CC failed mask		
000011CC	00000000 00000000			702+	DS	2F	extracted PSW after test (has CC)		
000011D4	FF			703+	DC	X' FF'	extracted CC, if test failed		
000011D5	E5C9E2E3 D9404040			704+	DC	CL8' VISTR'	instruction name		
000011E0	00001244			705+	DC	A(RE2)	address of v1 result		
000011E4	00001254			706+	DC	A(RE2+16)	address of v2 source		
000011E8	00001264			707+	DC	A(RE2+32)	address of v3 source		
000011EC	00000010			708+	DC	A(16)	result length		
000011F0	00001244			709+REA2	DC	A(RE2)	result address		
000011F8	00000000 00000000			710+	DS	FD	gap		
00001200	00000000 00000000			711+V102	DS	XL16	V1 output		
00001208	00000000 00000000								
00001210	00000000 00000000			712+	DS	FD	gap		
				713+*					
00001218				714+X2	DS	0F			
00001218	4110 8EF8		000010F8	715+	LA	R1, V1FUDGE	load v21 fudge		
0000121C	E751 0000 0806		00000000	716+	VL	v21, 0(R1)			
00001222	E310 5024 0014		00000024	717+	LGF	R1, V2ADDR	load v2 source		
00001228	E761 0000 0806		00000000	718+	VL	v22, 0(R1)	use v21 to test decoder		
0000122E	E756 0010 0C5C			719+	VISTR	V21, V22, 0, 1	test instruction		
00001234	B98D 0020			720+	EPSW	R2, R0	extract psw		
00001238	5020 500C		0000000C	721+	ST	R2, CCPSW	to save CC		
0000123C	E750 9000 080E		00001200	722+	VST	V21, V102	save v1 output		
00001242	07FB			723+	BR	R11	return		
00001244				724+RE2	DC	0F	V1 for this test		
00001244				725+	DROP	R5			
00001244	01020304 00000000			726	DC	XL16' 01020304 00000000 00000000 00000000'	V1		
0000124C	00000000 00000000								
00001254	01020304 00000000			727	DC	XL16' 01020304 00000000 0FFFFFFF FFFFFFFF'	v2		
0000125C	0FFFFFFF FFFFFFFF								
				728					
				729	VRR_A	VISTR, 0, 1, 3			
00001268				730+	DS	0FD			
00001268		00001268		731+	USING	*, R5	base for test data and test routine		
00001268	000012C0			732+T3	DC	A(X3)	address of test routine		
0000126C	0003			733+	DC	H' 3'	test number		
0000126E	00			734+	DC	X' 00'			
0000126F	00			735+	DC	HL1' 0'	MB used		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001270	01			736+	DC	HL1' 1'	M5 used		
00001271	03			737+	DC	HL1' 3'	CC		
00001272	0E			738+	DC	HL1' 14'	CC failed mask		
00001274	00000000	00000000		739+	DS	2F	extracted PSW after test (has CC)		
0000127C	FF			740+	DC	X' FF'	extracted CC, if test failed		
0000127D	E5C9E2E3	D9404040		741+	DC	CL8' VISTR'	instruction name		
00001288	000012EC			742+	DC	A(RE3)	address of v1 result		
0000128C	000012FC			743+	DC	A(RE3+16)	address of v2 source		
00001290	0000130C			744+	DC	A(RE3+32)	address of v3 source		
00001294	00000010			745+	DC	A(16)	result length		
00001298	000012EC			746+REA3	DC	A(RE3)	result address		
000012A0	00000000	00000000		747+	DS	FD	gap		
000012A8	00000000	00000000		748+V103	DS	XL16	V1 output		
000012B0	00000000	00000000							
000012B8	00000000	00000000		749+	DS	FD	gap		
				750+*					
000012C0				751+X3	DS	0F			
000012C0	4110 8EF8		000010F8	752+	LA	R1, V1FUDGE	load v21 fudge		
000012C4	E751 0000 0806		00000000	753+	VL	v21, 0(R1)			
000012CA	E310 5024 0014		00000024	754+	LGF	R1, V2ADDR	load v2 source		
000012D0	E761 0000 0806		00000000	755+	VL	v22, 0(R1)	use v21 to test decoder		
000012D6	E756 0010 0C5C			756+	VISTR	V21, V22, 0, 1	test instruction		
000012DC	B98D 0020			757+	EPSW	R2, R0	extract psw		
000012E0	5020 500C		0000000C	758+	ST	R2, CCPSW	to save CC		
000012E4	E750 5040 080E		000012A8	759+	VST	V21, V103	save v1 output		
000012EA	07FB			760+	BR	R11	return		
000012EC				761+RE3	DC	0F	V1 for this test		
000012EC				762+	DROP	R5			
000012EC	01020304	05060708		763	DC	XL16' 01020304 05060708 090A0B0C 0D0E0F10'	v1		
000012F4	090A0B0C	0D0E0F10							
000012FC	01020304	05060708		764	DC	XL16' 01020304 05060708 090A0B0C 0D0E0F10'	v2		
00001304	090A0B0C	0D0E0F10							

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				766 *halfword		
				767	VRR_A VISTR, 1, 1, 0	
00001310				768+	DS OFD	
00001310		00001310		769+	USING *, R5	base for test data and test routine
00001310	00001368			770+T4	DC A(X4)	address of test routine
00001314	0004			771+	DC H' 4'	test number
00001316	00			772+	DC X' 00'	
00001317	01			773+	DC HL1' 1'	M3 used
00001318	01			774+	DC HL1' 1'	M5 used
00001319	00			775+	DC HL1' 0'	CC
0000131A	07			776+	DC HL1' 7'	CC failed mask
0000131C	00000000 00000000			777+	DS 2F	extracted PSW after test (has CC)
00001324	FF			778+	DC X' FF'	extracted CC, if test failed
00001325	E5C9E2E3 D9404040			779+	DC CL8' VISTR'	instruction name
00001330	00001394			780+	DC A(RE4)	address of v1 result
00001334	000013A4			781+	DC A(RE4+16)	address of v2 source
00001338	000013B4			782+	DC A(RE4+32)	address of v3 source
0000133C	00000010			783+	DC A(16)	result length
00001340	00001394			784+REA4	DC A(RE4)	result address
00001348	00000000 00000000			785+	DS FD	gap
00001350	00000000 00000000			786+V104	DS XL16	V1 output
00001358	00000000 00000000					
00001360	00000000 00000000			787+	DS FD	gap
				788+*		
00001368				789+X4	DS OF	
00001368	4110 8EF8		000010F8	790+	LA R1, V1FUDGE	load v21 fudge
0000136C	E751 0000 0806		00000000	791+	VL v21, 0(R1)	
00001372	E310 5024 0014		00000024	792+	LGF R1, V2ADDR	load v2 source
00001378	E761 0000 0806		00000000	793+	VL v22, 0(R1)	use v21 to test decoder
0000137E	E756 0010 1C5C			794+	VISTR V21, V22, 1, 1	test instruction
00001384	B98D 0020			795+	EPSW R2, R0	extract psw
00001388	5020 500C		0000000C	796+	ST R2, CCPSW	to save CC
0000138C	E750 5040 080E		00001350	797+	VST V21, V104	save v1 output
00001392	07FB			798+	BR R11	return
00001394				799+RE4	DC OF	V1 for this test
00001394				800+	DROP R5	
00001394	00000000 00000000			801	DC XL16' 00000000 00000000 00000000 00000000'	V1
0000139C	00000000 00000000					
000013A4	00000000 00000000			802	DC XL16' 00000000 00000000 00000000 00000000'	v2
000013AC	00000000 00000000					
				803		
				804	VRR_A VISTR, 1, 1, 0	
000013B8				805+	DS OFD	
000013B8		000013B8		806+	USING *, R5	base for test data and test routine
000013B8	00001410			807+T5	DC A(X5)	address of test routine
000013BC	0005			808+	DC H' 5'	test number
000013BE	00			809+	DC X' 00'	
000013BF	01			810+	DC HL1' 1'	M3 used
000013C0	01			811+	DC HL1' 1'	M5 used
000013C1	00			812+	DC HL1' 0'	CC
000013C2	07			813+	DC HL1' 7'	CC failed mask
000013C4	00000000 00000000			814+	DS 2F	extracted PSW after test (has CC)
000013CC	FF			815+	DC X' FF'	extracted CC, if test failed
000013CD	E5C9E2E3 D9404040			816+	DC CL8' VISTR'	instruction name
000013D8	0000143C			817+	DC A(RE5)	address of v1 result
000013DC	0000144C			818+	DC A(RE5+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000013E0	0000145C			819+	DC	A(RE5+32)
000013E4	00000010			820+	DC	A(16)
000013E8	0000143C			821+REA5	DC	A(RE5)
000013F0	00000000 00000000			822+	DS	FD
000013F8	00000000 00000000			823+V105	DS	XL16
00001400	00000000 00000000					
00001408	00000000 00000000			824+	DS	FD
				825+*		gap
00001410				826+X5	DS	OF
00001410	4110 8EF8		000010F8	827+	LA	R1, V1FUDGE
00001414	E751 0000 0806		00000000	828+	VL	v21, 0(R1)
0000141A	E310 5024 0014		00000024	829+	LGF	R1, V2ADDR
00001420	E761 0000 0806		00000000	830+	VL	v22, 0(R1)
00001426	E756 0010 1C5C			831+	VISTR	V21, V22, 1, 1
0000142C	B98D 0020			832+	EPSW	R2, R0
00001430	5020 500C		0000000C	833+	ST	R2, CCPSW
00001434	E750 5040 080E		000013F8	834+	VST	V21, V105
0000143A	07FB			835+	BR	R11
0000143C				836+RE5	DC	OF
0000143C				837+	DROP	R5
0000143C	10203040 00000000			838	DC	XL16' 01020304 00000000 00000000 00000000' V1
00001444	00000000 00000000					
0000144C	10203040 00000000			839	DC	XL16' 01020304 00000000 0FFFFFFF FFFFFFFF' v2
00001454	FFFFFFFF FFFFFFFF					
				840		
				841	VRR_A	VISTR, 1, 1, 3
00001460				842+	DS	OFD
00001460		00001460		843+	USING	*, R5
00001460	000014B8			844+T6	DC	A(X6)
00001464	0006			845+	DC	H' 6'
00001466	00			846+	DC	X' 00'
00001467	01			847+	DC	HL1' 1'
00001468	01			848+	DC	HL1' 1'
00001469	03			849+	DC	HL1' 3'
0000146A	0E			850+	DC	HL1' 14'
0000146C	00000000 00000000			851+	DS	2F
00001474	FF			852+	DC	X' FF'
00001475	E5C9E2E3 D9404040			853+	DC	CL8' VISTR'
00001480	000014E4			854+	DC	A(RE6)
00001484	000014F4			855+	DC	A(RE6+16)
00001488	00001504			856+	DC	A(RE6+32)
0000148C	00000010			857+	DC	A(16)
00001490	000014E4			858+REA6	DC	A(RE6)
00001498	00000000 00000000			859+	DS	FD
000014A0	00000000 00000000			860+V106	DS	XL16
000014A8	00000000 00000000					
000014B0	00000000 00000000			861+	DS	FD
				862+*		gap
000014B8				863+X6	DS	OF
000014B8	4110 8EF8		000010F8	864+	LA	R1, V1FUDGE
000014BC	E751 0000 0806		00000000	865+	VL	v21, 0(R1)
000014C2	E310 5024 0014		00000024	866+	LGF	R1, V2ADDR
000014C8	E761 0000 0806		00000000	867+	VL	v22, 0(R1)
000014CE	E756 0010 1C5C			868+	VISTR	V21, V22, 1, 1
000014D4	B98D 0020			869+	EPSW	R2, R0
000014D8	5020 500C		0000000C	870+	ST	R2, CCPSW

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				878 *word		
				879	VRR_A VISTR, 2, 1, 0	
00001508				880+	DS OFD	
00001508		00001508		881+	USING *, R5	base for test data and test routine
00001508	00001560			882+T7	DC A(X7)	address of test routine
0000150C	0007			883+	DC H' 7'	test number
0000150E	00			884+	DC X' 00'	
0000150F	02			885+	DC HL1' 2'	M3 used
00001510	01			886+	DC HL1' 1'	M5 used
00001511	00			887+	DC HL1' 0'	CC
00001512	07			888+	DC HL1' 7'	CC failed mask
00001514	00000000 00000000			889+	DS 2F	extracted PSW after test (has CC)
0000151C	FF			890+	DC X' FF'	extracted CC, if test failed
0000151D	E5C9E2E3 D9404040			891+	DC CL8' VISTR'	instruction name
00001528	0000158C			892+	DC A(RE7)	address of v1 result
0000152C	0000159C			893+	DC A(RE7+16)	address of v2 source
00001530	000015AC			894+	DC A(RE7+32)	address of v3 source
00001534	00000010			895+	DC A(16)	result length
00001538	0000158C			896+REA7	DC A(RE7)	result address
00001540	00000000 00000000			897+	DS FD	gap
00001548	00000000 00000000			898+V107	DS XL16	V1 output
00001550	00000000 00000000					
00001558	00000000 00000000			899+	DS FD	gap
				900+*		
00001560				901+X7	DS OF	
00001560	4110 8EF8		000010F8	902+	LA R1, V1FUDGE	load v21 fudge
00001564	E751 0000 0806		00000000	903+	VL v21, 0(R1)	
0000156A	E310 5024 0014		00000024	904+	LGF R1, V2ADDR	load v2 source
00001570	E761 0000 0806		00000000	905+	VL v22, 0(R1)	use v21 to test decoder
00001576	E756 0010 2C5C			906+	VISTR V21, V22, 2, 1	test instruction
0000157C	B98D 0020			907+	EPSW R2, R0	extract psw
00001580	5020 500C		0000000C	908+	ST R2, CCPSW	to save CC
00001584	E750 5040 080E		00001548	909+	VST V21, V107	save v1 output
0000158A	07FB			910+	BR R11	return
0000158C				911+RE7	DC OF	V1 for this test
0000158C				912+	DROP R5	
0000158C	00000000 00000000			913	DC XL16' 00000000 00000000 00000000 00000000'	V1
00001594	00000000 00000000					
0000159C	00000000 00000000			914	DC XL16' 00000000 00000000 00000000 00000000'	v2
000015A4	00000000 00000000					
				915		
				916	VRR_A VISTR, 2, 1, 0	
000015B0				917+	DS OFD	
000015B0		000015B0		918+	USING *, R5	base for test data and test routine
000015B0	00001608			919+T8	DC A(X8)	address of test routine
000015B4	0008			920+	DC H' 8'	test number
000015B6	00			921+	DC X' 00'	
000015B7	02			922+	DC HL1' 2'	M3 used
000015B8	01			923+	DC HL1' 1'	M5 used
000015B9	00			924+	DC HL1' 0'	CC
000015BA	07			925+	DC HL1' 7'	CC failed mask
000015BC	00000000 00000000			926+	DS 2F	extracted PSW after test (has CC)
000015C4	FF			927+	DC X' FF'	extracted CC, if test failed
000015C5	E5C9E2E3 D9404040			928+	DC CL8' VISTR'	instruction name
000015D0	00001634			929+	DC A(RE8)	address of v1 result
000015D4	00001644			930+	DC A(RE8+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000015D8	00001654			931+	DC	A(RE8+32)
000015DC	00000010			932+	DC	A(16)
000015E0	00001634			933+REA8	DC	A(RE8)
000015E8	00000000 00000000			934+	DS	FD
000015F0	00000000 00000000			935+V108	DS	XL16
000015F8	00000000 00000000					
00001600	00000000 00000000			936+	DS	FD
				937+*		
00001608				938+X8	DS	OF
00001608	4110 8EF8		000010F8	939+	LA	R1, V1FUDGE
0000160C	E751 0000 0806		00000000	940+	VL	v21, 0(R1)
00001612	E310 5024 0014		00000024	941+	LGF	R1, V2ADDR
00001618	E761 0000 0806		00000000	942+	VL	v22, 0(R1)
0000161E	E756 0010 2C5C			943+	VISTR	V21, V22, 2, 1
00001624	B98D 0020			944+	EPSW	R2, R0
00001628	5020 500C		0000000C	945+	ST	R2, CCPSW
0000162C	E750 5040 080E		000015F0	946+	VST	V21, V108
00001632	07FB			947+	BR	R11
00001634				948+RE8	DC	OF
00001634				949+	DROP	R5
00001634	10203040 00000000			950	DC	XL16' 01020304 00000000 00000000 00000000' V1
0000163C	00000000 00000000					
00001644	10203040 00000000			951	DC	XL16' 01020304 00000000 0FFFFFFF FFFFFFFF' v2
0000164C	FFFFFFFF FFFFFFFF					
				952		
				953	VRR_A	VISTR, 2, 1, 3
00001658				954+	DS	OFD
00001658		00001658		955+	USING	*, R5
00001658	000016B0			956+T9	DC	A(X9)
0000165C	0009			957+	DC	H' 9'
0000165E	00			958+	DC	X' 00'
0000165F	02			959+	DC	HL1' 2'
00001660	01			960+	DC	HL1' 1'
00001661	03			961+	DC	HL1' 3'
00001662	0E			962+	DC	HL1' 14'
00001664	00000000 00000000			963+	DS	2F
0000166C	FF			964+	DC	X' FF'
0000166D	E5C9E2E3 D9404040			965+	DC	CL8' VISTR'
00001678	000016DC			966+	DC	A(RE9)
0000167C	000016EC			967+	DC	A(RE9+16)
00001680	000016FC			968+	DC	A(RE9+32)
00001684	00000010			969+	DC	A(16)
00001688	000016DC			970+REA9	DC	A(RE9)
00001690	00000000 00000000			971+	DS	FD
00001698	00000000 00000000			972+V109	DS	XL16
000016A0	00000000 00000000					
000016A8	00000000 00000000			973+	DS	FD
				974+*		
000016B0				975+X9	DS	OF
000016B0	4110 8EF8		000010F8	976+	LA	R1, V1FUDGE
000016B4	E751 0000 0806		00000000	977+	VL	v21, 0(R1)
000016BA	E310 5024 0014		00000024	978+	LGF	R1, V2ADDR
000016C0	E761 0000 0806		00000000	979+	VL	v22, 0(R1)
000016C6	E756 0010 2C5C			980+	VISTR	V21, V22, 2, 1
000016CC	B98D 0020			981+	EPSW	R2, R0
000016D0	5020 500C		0000000C	982+	ST	R2, CCPSW

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				990 *-----	
				991 * case 1 - one zero	CS=1
				992 *-----	
				993 *byte	
				994 VRR_A VISTR, 0, 1, 3	
00001700				995+ DS OFD	
00001700		00001700		996+ USING *, R5	base for test data and test routine
00001700	00001758			997+T10 DC A(X10)	address of test routine
00001704	000A			998+ DC H' 10'	test number
00001706	00			999+ DC X' 00'	
00001707	00			1000+ DC HL1' 0'	M3 used
00001708	01			1001+ DC HL1' 1'	M5 used
00001709	03			1002+ DC HL1' 3'	CC
0000170A	0E			1003+ DC HL1' 14'	CC failed mask
0000170C	00000000 00000000			1004+ DS 2F	extracted PSW after test (has CC)
00001714	FF			1005+ DC X' FF'	extracted CC, if test failed
00001715	E5C9E2E3 D9404040			1006+ DC CL8' VISTR'	instruction name
00001720	00001784			1007+ DC A(RE10)	address of v1 result
00001724	00001794			1008+ DC A(RE10+16)	address of v2 source
00001728	000017A4			1009+ DC A(RE10+32)	address of v3 source
0000172C	00000010			1010+ DC A(16)	result length
00001730	00001784			1011+REA10 DC A(RE10)	result address
00001738	00000000 00000000			1012+ DS FD	gap
00001740	00000000 00000000			1013+V1010 DS XL16	V1 output
00001748	00000000 00000000				
00001750	00000000 00000000			1014+ DS FD	gap
				1015+*	
00001758				1016+X10 DS OF	
00001758	4110 8EF8		000010F8	1017+ LA R1, V1FUDGE	load v21 fudge
0000175C	E751 0000 0806		00000000	1018+ VL v21, 0(R1)	
00001762	E310 5024 0014		00000024	1019+ LGF R1, V2ADDR	load v2 source
00001768	E761 0000 0806		00000000	1020+ VL v22, 0(R1)	use v21 to test decoder
0000176E	E756 0010 0C5C			1021+ VISTR V21, V22, 0, 1	test instruction
00001774	B98D 0020			1022+ EPSW R2, R0	extract psw
00001778	5020 500C		0000000C	1023+ ST R2, CCPSW	to save CC
0000177C	E750 5040 080E		00001740	1024+ VST V21, V1010	save v1 output
00001782	07FB			1025+ BR R11	return
00001784				1026+RE10 DC OF	V1 for this test
00001784				1027+ DROP R5	
00001784	01020304 05060708			1028 DC XL16' 01020304 05060708 090A0B0C 0D0E0F10'	v1
0000178C	090A0B0C 0D0E0F10				
00001794	01020304 05060708			1029 DC XL16' 01020304 05060708 090A0B0C 0D0E0F10'	v2
0000179C	090A0B0C 0D0E0F10				
				1030	
000017A8				1031 VRR_A VISTR, 0, 1, 0	
000017A8		000017A8		1032+ DS OFD	
000017A8	00001800			1033+ USING *, R5	base for test data and test routine
000017AC	000B			1034+T11 DC A(X11)	address of test routine
000017AE	00			1035+ DC H' 11'	test number
000017AF	00			1036+ DC X' 00'	
000017B0	01			1037+ DC HL1' 0'	M3 used
000017B1	00			1038+ DC HL1' 1'	M5 used
000017B2	07			1039+ DC HL1' 0'	CC
000017B4	00000000 00000000			1040+ DC HL1' 7'	CC failed mask
000017BC	FF			1041+ DS 2F	extracted PSW after test (has CC)
				1042+ DC X' FF'	extracted CC, if test failed

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000017BD	E5C9E2E3 D9404040			1043+	DC	CL8' VISTR'	instruction name
000017C8	0000182C			1044+	DC	A(RE11)	address of v1 result
000017CC	0000183C			1045+	DC	A(RE11+16)	address of v2 source
000017D0	0000184C			1046+	DC	A(RE11+32)	address of v3 source
000017D4	00000010			1047+	DC	A(16)	result length
000017D8	0000182C			1048+REA11	DC	A(RE11)	result address
000017E0	00000000 00000000			1049+	DS	FD	gap
000017E8	00000000 00000000			1050+V1011	DS	XL16	V1 output
000017F0	00000000 00000000						
000017F8	00000000 00000000			1051+	DS	FD	gap
				1052+*			
00001800				1053+X11	DS	OF	
00001800	4110 8EF8		000010F8	1054+	LA	R1, V1FUDGE	load v21 fudge
00001804	E751 0000 0806		00000000	1055+	VL	v21, 0(R1)	
0000180A	E310 5024 0014		00000024	1056+	LGF	R1, V2ADDR	load v2 source
00001810	E761 0000 0806		00000000	1057+	VL	v22, 0(R1)	use v21 to test decoder
00001816	E756 0010 0C5C			1058+	VISTR	V21, V22, 0, 1	test instruction
0000181C	B98D 0020			1059+	EPSW	R2, R0	extract psw
00001820	5020 500C		0000000C	1060+	ST	R2, CCPSW	to save CC
00001824	E750 5040 080E		000017E8	1061+	VST	V21, V1011	save v1 output
0000182A	07FB			1062+	BR	R11	return
0000182C				1063+RE11	DC	OF	V1 for this test
0000182C				1064+	DROP	R5	
0000182C	01020304 05060708			1065	DC	XL16' 01020304 05060708 090A0B0C 0D0E0F00'	v1
00001834	090A0B0C 0D0E0F00						
0000183C	01020304 05060708			1066	DC	XL16' 01020304 05060708 090A0B0C 0D0E0F00'	v2
00001844	090A0B0C 0D0E0F00						
				1067			
				1068	VRR_A	VISTR, 0, 1, 0	
00001850				1069+	DS	OFD	
00001850		00001850		1070+	USING	*, R5	base for test data and test routine
00001850	000018A8			1071+T12	DC	A(X12)	address of test routine
00001854	000C			1072+	DC	H' 12'	test number
00001856	00			1073+	DC	X' 00'	
00001857	00			1074+	DC	HL1' 0'	M3 used
00001858	01			1075+	DC	HL1' 1'	M5 used
00001859	00			1076+	DC	HL1' 0'	CC
0000185A	07			1077+	DC	HL1' 7'	CC failed mask
0000185C	00000000 00000000			1078+	DS	2F	extracted PSW after test (has CC)
00001864	FF			1079+	DC	X' FF'	extracted CC, if test failed
00001865	E5C9E2E3 D9404040			1080+	DC	CL8' VISTR'	instruction name
00001870	000018D4			1081+	DC	A(RE12)	address of v1 result
00001874	000018E4			1082+	DC	A(RE12+16)	address of v2 source
00001878	000018F4			1083+	DC	A(RE12+32)	address of v3 source
0000187C	00000010			1084+	DC	A(16)	result length
00001880	000018D4			1085+REA12	DC	A(RE12)	result address
00001888	00000000 00000000			1086+	DS	FD	gap
00001890	00000000 00000000			1087+V1012	DS	XL16	V1 output
00001898	00000000 00000000						
000018A0	00000000 00000000			1088+	DS	FD	gap
				1089+*			
000018A8				1090+X12	DS	OF	
000018A8	4110 8EF8		000010F8	1091+	LA	R1, V1FUDGE	load v21 fudge
000018AC	E751 0000 0806		00000000	1092+	VL	v21, 0(R1)	
000018B2	E310 5024 0014		00000024	1093+	LGF	R1, V2ADDR	load v2 source
000018B8	E761 0000 0806		00000000	1094+	VL	v22, 0(R1)	use v21 to test decoder

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000018BE	E756 0010 0C5C			1095+	VISTR	V21, V22, 0, 1		test instruction	
000018C4	B98D 0020			1096+	EPSW	R2, R0		extract psw	
000018C8	5020 500C		0000000C	1097+	ST	R2, CCPSW		to save CC	
000018CC	E750 5040 080E		00001890	1098+	VST	V21, V1012		save v1 output	
000018D2	07FB			1099+	BR	R11		return	
000018D4				1100+RE12	DC	0F		V1 for this test	
000018D4				1101+	DROP	R5			
000018D4	01020304 05060708			1102	DC	XL16' 01020304 05060708 090A0B0C 0D000000'		v1	
000018DC	090A0B0C 0D000000								
000018E4	01020304 05060708			1103	DC	XL16' 01020304 05060708 090A0B0C 0D000F10'		v2	
000018EC	090A0B0C 0D000F10								
				1104					
000018F8				1105	VRR_A	VISTR, 0, 1, 0			
000018F8		000018F8		1106+	DS	0FD			
000018F8	00001950			1107+	USING	*, R5		base for test data and test routine	
000018FC	000D			1108+T13	DC	A(X13)		address of test routine	
000018FE	00			1109+	DC	H' 13'		test number	
000018FF	00			1110+	DC	X' 00'			
00001900	01			1111+	DC	HL1' 0'		MB used	
00001901	00			1112+	DC	HL1' 1'		M5 used	
00001902	07			1113+	DC	HL1' 0'		CC	
00001904	00000000 00000000			1114+	DC	HL1' 7'		CC failed mask	
0000190C	FF			1115+	DS	2F		extracted PSW after test (has CC)	
0000190D	E5C9E2E3 D9404040			1116+	DC	X' FF'		extracted CC, if test failed	
00001918	0000197C			1117+	DC	CL8' VISTR'		instruction name	
0000191C	0000198C			1118+	DC	A(RE13)		address of v1 result	
00001920	0000199C			1119+	DC	A(RE13+16)		address of v2 source	
00001924	00000010			1120+	DC	A(RE13+32)		address of v3 source	
00001928	0000197C			1121+	DC	A(16)		result length	
00001930	00000000 00000000			1122+REA13	DC	A(RE13)		result address	
00001938	00000000 00000000			1123+	DS	FD		gap	
00001940	00000000 00000000			1124+V1013	DS	XL16		V1 output	
00001948	00000000 00000000			1125+	DS	FD		gap	
				1126+*					
00001950				1127+X13	DS	0F			
00001950	4110 8EF8		000010F8	1128+	LA	R1, V1FUDGE		load v21 fudge	
00001954	E751 0000 0806		00000000	1129+	VL	v21, 0(R1)			
0000195A	E310 5024 0014		00000024	1130+	LGF	R1, V2ADDR		load v2 source	
00001960	E761 0000 0806		00000000	1131+	VL	v22, 0(R1)		use v21 to test decoder	
00001966	E756 0010 0C5C			1132+	VISTR	V21, V22, 0, 1		test instruction	
0000196C	B98D 0020			1133+	EPSW	R2, R0		extract psw	
00001970	5020 500C		0000000C	1134+	ST	R2, CCPSW		to save CC	
00001974	E750 5040 080E		00001938	1135+	VST	V21, V1013		save v1 output	
0000197A	07FB			1136+	BR	R11		return	
0000197C				1137+RE13	DC	0F		V1 for this test	
0000197C				1138+	DROP	R5			
0000197C	01020304 05060708			1139	DC	XL16' 01020304 05060708 090A0B0C 00000000'		v1	
00001984	090A0B0C 00000000								
0000198C	01020304 05060708			1140	DC	XL16' 01020304 05060708 090A0B0C 000E0F10'		v2	
00001994	090A0B0C 000E0F10								
				1141					
000019A0				1142	VRR_A	VISTR, 0, 1, 0			
000019A0		000019A0		1143+	DS	0FD			
000019A0	000019F8			1144+	USING	*, R5		base for test data and test routine	
				1145+T14	DC	A(X14)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
000019A4	000E			1146+	DC	H' 14'
000019A6	00			1147+	DC	X' 00'
000019A7	00			1148+	DC	HL1' 0'
000019A8	01			1149+	DC	HL1' 1'
000019A9	00			1150+	DC	HL1' 0'
000019AA	07			1151+	DC	HL1' 7'
000019AC	00000000	00000000		1152+	DS	2F
000019B4	FF			1153+	DC	X' FF'
000019B5	E5C9E2E3	D9404040		1154+	DC	CL8' VISTR'
000019C0	00001A24			1155+	DC	A(RE14)
000019C4	00001A34			1156+	DC	A(RE14+16)
000019C8	00001A44			1157+	DC	A(RE14+32)
000019CC	00000010			1158+	DC	A(16)
000019D0	00001A24			1159+REA14	DC	A(RE14)
000019D8	00000000	00000000		1160+	DS	FD
000019E0	00000000	00000000		1161+V1014	DS	XL16
000019E8	00000000	00000000				
000019F0	00000000	00000000		1162+	DS	FD
				1163+*		
000019F8				1164+X14	DS	0F
000019F8	4110 8EF8		000010F8	1165+	LA	R1, V1FUDGE
000019FC	E751 0000 0806		00000000	1166+	VL	v21, 0(R1)
00001A02	E310 5024 0014		00000024	1167+	LGF	R1, V2ADDR
00001A08	E761 0000 0806		00000000	1168+	VL	v22, 0(R1)
00001A0E	E756 0010 0C5C			1169+	VISTR	V21, V22, 0, 1
00001A14	B98D 0020			1170+	EPSW	R2, R0
00001A18	5020 500C		0000000C	1171+	ST	R2, CCPSW
00001A1C	E750 5040 080E		000019E0	1172+	VST	V21, V1014
00001A22	07FB			1173+	BR	R11
00001A24				1174+RE14	DC	0F
00001A24				1175+	DROP	R5
00001A24	01020304 05060708			1176	DC	XL16' 01020304 05060708 090A0B00 00000000'
00001A2C	090A0B00 00000000					v1
00001A34	01020304 05060708			1177	DC	XL16' 01020304 05060708 090A0B00 0D0E0F10'
00001A3C	090A0B00 0D0E0F10					v2
				1178		
00001A48				1179	VRR_A	VISTR, 0, 1, 0
00001A48		00001A48		1180+	DS	0FD
00001A48	00001AA0			1181+	USING	*, R5
00001A4C	000F			1182+T15	DC	A(X15)
00001A4E	00			1183+	DC	H' 15'
00001A4F	00			1184+	DC	X' 00'
00001A50	01			1185+	DC	HL1' 0'
00001A51	00			1186+	DC	HL1' 1'
00001A52	07			1187+	DC	HL1' 0'
00001A54	00000000	00000000		1188+	DC	HL1' 7'
00001A5C	FF			1189+	DS	2F
00001A5D	E5C9E2E3	D9404040		1190+	DC	X' FF'
00001A68	00001ACC			1191+	DC	CL8' VISTR'
00001A6C	00001ADC			1192+	DC	A(RE15)
00001A70	00001AEC			1193+	DC	A(RE15+16)
00001A74	00000010			1194+	DC	A(RE15+32)
00001A78	00001ACC			1195+	DC	A(16)
00001A80	00000000	00000000		1196+REA15	DC	A(RE15)
00001A88	00000000	00000000		1197+	DS	FD
				1198+V1015	DS	XL16

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001A90	00000000 00000000								
00001A98	00000000 00000000			1199+	DS	FD	gap		
				1200+*					
00001AA0				1201+X15	DS	OF			
00001AA0	4110 8EF8		000010F8	1202+	LA	R1, V1FUDGE	load v21 fudge		
00001AA4	E751 0000 0806		00000000	1203+	VL	v21, 0(R1)			
00001AAA	E310 5024 0014		00000024	1204+	LGF	R1, V2ADDR	load v2 source		
00001AB0	E761 0000 0806		00000000	1205+	VL	v22, 0(R1)	use v21 to test decoder		
00001AB6	E756 0010 0C5C			1206+	VISTR	V21, V22, 0, 1	test instruction		
00001ABC	B98D 0020			1207+	EPSW	R2, R0	extract psw		
00001AC0	5020 500C		0000000C	1208+	ST	R2, CCPSW	to save CC		
00001AC4	E750 5040 080E		00001A88	1209+	VST	V21, V1015	save v1 output		
00001ACA	07FB			1210+	BR	R11	return		
00001ACC				1211+RE15	DC	OF	V1 for this test		
00001ACC				1212+	DROP	R5			
00001ACC	01020304 05060708			1213	DC	XL16' 01020304 05060708 090A0000 00000000'	v1		
00001AD4	090A0000 00000000								
00001ADC	01020304 05060708			1214	DC	XL16' 01020304 05060708 090A000C 0D0E0F10'	v2		
00001AE4	090A000C 0D0E0F10								
				1215					
				1216	VRR_A	VISTR, 0, 1, 0			
00001AF0				1217+	DS	OFD			
00001AF0		00001AF0		1218+	USING	*, R5	base for test data and test routine		
00001AF0	00001B48			1219+T16	DC	A(X16)	address of test routine		
00001AF4	0010			1220+	DC	H' 16'	test number		
00001AF6	00			1221+	DC	X' 00'			
00001AF7	00			1222+	DC	HL1' 0'	MB used		
00001AF8	01			1223+	DC	HL1' 1'	M5 used		
00001AF9	00			1224+	DC	HL1' 0'	CC		
00001AFA	07			1225+	DC	HL1' 7'	CC failed mask		
00001AFC	00000000 00000000			1226+	DS	2F	extracted PSW after test (has CC)		
00001B04	FF			1227+	DC	X' FF'	extracted CC, if test failed		
00001B05	E5C9E2E3 D9404040			1228+	DC	CL8' VISTR'	instruction name		
00001B10	00001B74			1229+	DC	A(RE16)	address of v1 result		
00001B14	00001B84			1230+	DC	A(RE16+16)	address of v2 source		
00001B18	00001B94			1231+	DC	A(RE16+32)	address of v3 source		
00001B1C	00000010			1232+	DC	A(16)	result length		
00001B20	00001B74			1233+REA16	DC	A(RE16)	result address		
00001B28	00000000 00000000			1234+	DS	FD	gap		
00001B30	00000000 00000000			1235+V1016	DS	XL16	V1 output		
00001B38	00000000 00000000								
00001B40	00000000 00000000			1236+	DS	FD	gap		
				1237+*					
00001B48				1238+X16	DS	OF			
00001B48	4110 8EF8		000010F8	1239+	LA	R1, V1FUDGE	load v21 fudge		
00001B4C	E751 0000 0806		00000000	1240+	VL	v21, 0(R1)			
00001B52	E310 5024 0014		00000024	1241+	LGF	R1, V2ADDR	load v2 source		
00001B58	E761 0000 0806		00000000	1242+	VL	v22, 0(R1)	use v21 to test decoder		
00001B5E	E756 0010 0C5C			1243+	VISTR	V21, V22, 0, 1	test instruction		
00001B64	B98D 0020			1244+	EPSW	R2, R0	extract psw		
00001B68	5020 500C		0000000C	1245+	ST	R2, CCPSW	to save CC		
00001B6C	E750 5040 080E		00001B30	1246+	VST	V21, V1016	save v1 output		
00001B72	07FB			1247+	BR	R11	return		
00001B74				1248+RE16	DC	OF	V1 for this test		
00001B74				1249+	DROP	R5			
00001B74	01020304 05060708			1250	DC	XL16' 01020304 05060708 09000000 00000000'	v1		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001B7C	09000000	00000000							
00001B84	01020304	05060708		1251	DC	XL16'	01020304 05060708 09000B0C 0D0E0F10'	v2	
00001B8C	09000B0C	0D0E0F10							
				1252					
				1253	VRR_A	VISTR, 0, 1, 0			
00001B98				1254+	DS	0FD			
00001B98		00001B98		1255+	USING	*, R5	base for test data and test routine		
00001B98	00001BF0			1256+T17	DC	A(X17)	address of test routine		
00001B9C	0011			1257+	DC	H' 17'	test number		
00001B9E	00			1258+	DC	X' 00'			
00001B9F	00			1259+	DC	HL1' 0'	MB used		
00001BA0	01			1260+	DC	HL1' 1'	M5 used		
00001BA1	00			1261+	DC	HL1' 0'	CC		
00001BA2	07			1262+	DC	HL1' 7'	CC failed mask		
00001BA4	00000000	00000000		1263+	DS	2F	extracted PSW after test (has CC)		
00001BAC	FF			1264+	DC	X' FF'	extracted CC, if test failed		
00001BAD	E5C9E2E3	D9404040		1265+	DC	CL8' VISTR'	instruction name		
00001BB8	00001C1C			1266+	DC	A(RE17)	address of v1 result		
00001BBC	00001C2C			1267+	DC	A(RE17+16)	address of v2 source		
00001BC0	00001C3C			1268+	DC	A(RE17+32)	address of v3 source		
00001BC4	00000010			1269+	DC	A(16)	result length		
00001BC8	00001C1C			1270+REA17	DC	A(RE17)	result address		
00001BD0	00000000	00000000		1271+	DS	FD	gap		
00001BD8	00000000	00000000		1272+V1017	DS	XL16	V1 output		
00001BE0	00000000	00000000							
00001BE8	00000000	00000000		1273+	DS	FD	gap		
				1274+*					
00001BF0				1275+X17	DS	0F			
00001BF0	4110 8EF8		000010F8	1276+	LA	R1, V1FUDGE	load v21 fudge		
00001BF4	E751 0000 0806		00000000	1277+	VL	v21, 0(R1)			
00001BFA	E310 5024 0014		00000024	1278+	LGF	R1, V2ADDR	load v2 source		
00001C00	E761 0000 0806		00000000	1279+	VL	v22, 0(R1)	use v21 to test decoder		
00001C06	E756 0010 0C5C			1280+	VISTR	V21, V22, 0, 1	test instruction		
00001C0C	B98D 0020			1281+	EPSW	R2, R0	extract psw		
00001C10	5020 500C		0000000C	1282+	ST	R2, CCPSW	to save CC		
00001C14	E750 5040 080E		00001BD8	1283+	VST	V21, V1017	save v1 output		
00001C1A	07FB			1284+	BR	R11	return		
00001C1C				1285+RE17	DC	0F	V1 for this test		
00001C1C				1286+	DROP	R5			
00001C1C	01020304 05060708			1287	DC	XL16' 01020304 05060708 00000000 00000000'	v1		
00001C24	00000000	00000000							
00001C2C	01020304 05060708			1288	DC	XL16' 01020304 05060708 000A0B0C 0D0E0F10'	v2		
00001C34	000A0B0C 0D0E0F10								
				1289					
				1290	VRR_A	VISTR, 0, 1, 0			
00001C40				1291+	DS	0FD			
00001C40		00001C40		1292+	USING	*, R5	base for test data and test routine		
00001C40	00001C98			1293+T18	DC	A(X18)	address of test routine		
00001C44	0012			1294+	DC	H' 18'	test number		
00001C46	00			1295+	DC	X' 00'			
00001C47	00			1296+	DC	HL1' 0'	MB used		
00001C48	01			1297+	DC	HL1' 1'	M5 used		
00001C49	00			1298+	DC	HL1' 0'	CC		
00001C4A	07			1299+	DC	HL1' 7'	CC failed mask		
00001C4C	00000000	00000000		1300+	DS	2F	extracted PSW after test (has CC)		
00001C54	FF			1301+	DC	X' FF'	extracted CC, if test failed		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00001C55	E5C9E2E3 D9404040			1302+	DC	CL8' VISTR'	instruction name
00001C60	00001CC4			1303+	DC	A(RE18)	address of v1 result
00001C64	00001CD4			1304+	DC	A(RE18+16)	address of v2 source
00001C68	00001CE4			1305+	DC	A(RE18+32)	address of v3 source
00001C6C	00000010			1306+	DC	A(16)	result length
00001C70	00001CC4			1307+REA18	DC	A(RE18)	result address
00001C78	00000000 00000000			1308+	DS	FD	gap
00001C80	00000000 00000000			1309+V1018	DS	XL16	V1 output
00001C88	00000000 00000000						
00001C90	00000000 00000000			1310+	DS	FD	gap
				1311+*			
00001C98				1312+X18	DS	OF	
00001C98	4110 8EF8		000010F8	1313+	LA	R1, V1FUDGE	load v21 fudge
00001C9C	E751 0000 0806		00000000	1314+	VL	v21, 0(R1)	
00001CA2	E310 5024 0014		00000024	1315+	LGF	R1, V2ADDR	load v2 source
00001CA8	E761 0000 0806		00000000	1316+	VL	v22, 0(R1)	use v21 to test decoder
00001CAE	E756 0010 0C5C			1317+	VISTR	V21, V22, 0, 1	test instruction
00001CB4	B98D 0020			1318+	EPSW	R2, R0	extract psw
00001CB8	5020 500C		0000000C	1319+	ST	R2, CCPSW	to save CC
00001CBC	E750 5040 080E		00001C80	1320+	VST	V21, V1018	save v1 output
00001CC2	07FB			1321+	BR	R11	return
00001CC4				1322+RE18	DC	OF	V1 for this test
00001CC4				1323+	DROP	R5	
00001CC4	01020304 05060700			1324	DC	XL16' 01020304 05060700 00000000 00000000'	v1
00001CCC	00000000 00000000						
00001CD4	01020304 05060700			1325	DC	XL16' 01020304 05060700 090A0B0C 0D0E0F10'	v2
00001CDC	090A0B0C 0D0E0F10						
				1326			
				1327	VRR_A	VISTR, 0, 1, 0	
00001CE8				1328+	DS	OFD	
00001CE8		00001CE8		1329+	USING	*, R5	base for test data and test routine
00001CE8	00001D40			1330+T19	DC	A(X19)	address of test routine
00001CEC	0013			1331+	DC	H' 19'	test number
00001CEE	00			1332+	DC	X' 00'	
00001CEF	00			1333+	DC	HL1' 0'	M3 used
00001CF0	01			1334+	DC	HL1' 1'	M5 used
00001CF1	00			1335+	DC	HL1' 0'	CC
00001CF2	07			1336+	DC	HL1' 7'	CC failed mask
00001CF4	00000000 00000000			1337+	DS	2F	extracted PSW after test (has CC)
00001CFC	FF			1338+	DC	X' FF'	extracted CC, if test failed
00001CFD	E5C9E2E3 D9404040			1339+	DC	CL8' VISTR'	instruction name
00001D08	00001D6C			1340+	DC	A(RE19)	address of v1 result
00001D0C	00001D7C			1341+	DC	A(RE19+16)	address of v2 source
00001D10	00001D8C			1342+	DC	A(RE19+32)	address of v3 source
00001D14	00000010			1343+	DC	A(16)	result length
00001D18	00001D6C			1344+REA19	DC	A(RE19)	result address
00001D20	00000000 00000000			1345+	DS	FD	gap
00001D28	00000000 00000000			1346+V1019	DS	XL16	V1 output
00001D30	00000000 00000000						
00001D38	00000000 00000000			1347+	DS	FD	gap
				1348+*			
00001D40				1349+X19	DS	OF	
00001D40	4110 8EF8		000010F8	1350+	LA	R1, V1FUDGE	load v21 fudge
00001D44	E751 0000 0806		00000000	1351+	VL	v21, 0(R1)	
00001D4A	E310 5024 0014		00000024	1352+	LGF	R1, V2ADDR	load v2 source
00001D50	E761 0000 0806		00000000	1353+	VL	v22, 0(R1)	use v21 to test decoder

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001D56	E756 0010 0C5C			1354+	VISTR	V21, V22, 0, 1		test instruction	
00001D5C	B98D 0020			1355+	EPSW	R2, R0		extract psw	
00001D60	5020 500C		0000000C	1356+	ST	R2, CCPSW		to save CC	
00001D64	E750 5040 080E		00001D28	1357+	VST	V21, V1019		save v1 output	
00001D6A	07FB			1358+	BR	R11		return	
00001D6C				1359+RE19	DC	0F		V1 for this test	
00001D6C				1360+	DROP	R5			
00001D6C	01020304 05060000			1361	DC	XL16' 01020304 05060000 00000000 00000000'		v1	
00001D74	00000000 00000000								
00001D7C	01020304 05060008			1362	DC	XL16' 01020304 05060008 090A0B0C 0D0E0F10'		v2	
00001D84	090A0B0C 0D0E0F10								
00001D90				1363					
00001D90		00001D90		1364	VRR_A	VISTR, 0, 1, 0			
00001D90	00001DE8			1365+	DS	0FD			
00001D94	0014			1366+	USING	*, R5		base for test data and test routine	
00001D96	00			1367+T20	DC	A(X20)		address of test routine	
00001D97	00			1368+	DC	H' 20'		test number	
00001D98	01			1369+	DC	X' 00'			
00001D99	00			1370+	DC	HL1' 0'		MB used	
00001D9A	07			1371+	DC	HL1' 1'		M5 used	
00001D9C	00000000 00000000			1372+	DC	HL1' 0'		CC	
00001DA4	FF			1373+	DC	HL1' 7'		CC failed mask	
00001DA5	E5C9E2E3 D9404040			1374+	DS	2F		extracted PSW after test (has CC)	
00001DB0	00001E14			1375+	DC	X' FF'		extracted CC, if test failed	
00001DB4	00001E24			1376+	DC	CL8' VISTR'		instruction name	
00001DB8	00001E34			1377+	DC	A(RE20)		address of v1 result	
00001DBC	00000010			1378+	DC	A(RE20+16)		address of v2 source	
00001DC0	00001E14			1379+	DC	A(RE20+32)		address of v3 source	
00001DC8	00000000 00000000			1380+	DC	A(16)		result length	
00001DD0	00000000 00000000			1381+REA20	DC	A(RE20)		result address	
00001DD8	00000000 00000000			1382+	DS	FD		gap	
00001DE0	00000000 00000000			1383+V1020	DS	XL16		V1 output	
00001DE8				1384+	DS	FD		gap	
00001DE8	4110 8EF8			1385+*					
00001DEC	E751 0000 0806		000010F8	1386+X20	DS	0F			
00001DF2	E310 5024 0014		00000000	1387+	LA	R1, V1FUDGE		load v21 fudge	
00001DF8	E761 0000 0806		00000024	1388+	VL	v21, 0(R1)			
00001DFE	E756 0010 0C5C		00000000	1389+	LGF	R1, V2ADDR		load v2 source	
00001E04	B98D 0020			1390+	VL	v22, 0(R1)		use v21 to test decoder	
00001E08	5020 500C		0000000C	1391+	VISTR	V21, V22, 0, 1		test instruction	
00001E0C	E750 5040 080E		00001DD0	1392+	EPSW	R2, R0		extract psw	
00001E12	07FB			1393+	ST	R2, CCPSW		to save CC	
00001E14				1394+	VST	V21, V1020		save v1 output	
00001E14				1395+	BR	R11		return	
00001E14				1396+RE20	DC	0F		V1 for this test	
00001E14	01020304 05000000			1397+	DROP	R5			
00001E1C	00000000 00000000			1398	DC	XL16' 01020304 05000000 00000000 00000000'		v1	
00001E24	01020304 05000708								
00001E2C	090A0B0C 0D0E0F10			1399	DC	XL16' 01020304 05000708 090A0B0C 0D0E0F10'		v2	
00001E38				1400					
00001E38		00001E38		1401	VRR_A	VISTR, 0, 1, 0			
00001E38	00001E90			1402+	DS	0FD			
				1403+	USING	*, R5		base for test data and test routine	
				1404+T21	DC	A(X21)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001E3C	0015			1405+	DC	H' 21'		test number	
00001E3E	00			1406+	DC	X' 00'			
00001E3F	00			1407+	DC	HL1' 0'		MB used	
00001E40	01			1408+	DC	HL1' 1'		M5 used	
00001E41	00			1409+	DC	HL1' 0'		CC	
00001E42	07			1410+	DC	HL1' 7'		CC failed mask	
00001E44	00000000	00000000		1411+	DS	2F		extracted PSW after test (has CC)	
00001E4C	FF			1412+	DC	X' FF'		extracted CC, if test failed	
00001E4D	E5C9E2E3	D9404040		1413+	DC	CL8' VISTR'		instruction name	
00001E58	00001EBC			1414+	DC	A(RE21)		address of v1 result	
00001E5C	00001ECC			1415+	DC	A(RE21+16)		address of v2 source	
00001E60	00001EDC			1416+	DC	A(RE21+32)		address of v3 source	
00001E64	00000010			1417+	DC	A(16)		result length	
00001E68	00001EBC			1418+REA21	DC	A(RE21)		result address	
00001E70	00000000	00000000		1419+	DS	FD		gap	
00001E78	00000000	00000000		1420+V1021	DS	XL16		V1 output	
00001E80	00000000	00000000							
00001E88	00000000	00000000		1421+	DS	FD		gap	
				1422+*					
00001E90				1423+X21	DS	0F			
00001E90	4110 8EF8		000010F8	1424+	LA	R1, V1FUDGE		load v21 fudge	
00001E94	E751 0000 0806		00000000	1425+	VL	v21, 0(R1)			
00001E9A	E310 5024 0014		00000024	1426+	LGF	R1, V2ADDR		load v2 source	
00001EA0	E761 0000 0806		00000000	1427+	VL	v22, 0(R1)		use v21 to test decoder	
00001EA6	E756 0010 0C5C			1428+	VISTR	V21, V22, 0, 1		test instruction	
00001EAC	B98D 0020			1429+	EPSW	R2, R0		extract psw	
00001EB0	5020 500C		0000000C	1430+	ST	R2, CCPSW		to save CC	
00001EB4	E750 5040 080E		00001E78	1431+	VST	V21, V1021		save v1 output	
00001EBA	07FB			1432+	BR	R11		return	
00001EBC				1433+RE21	DC	0F		V1 for this test	
00001EBC				1434+	DROP	R5			
00001EBC	01020304	00000000		1435	DC	XL16' 01020304	00000000 00000000 00000000'	v1	
00001EC4	00000000	00000000							
00001ECC	01020304	00060708		1436	DC	XL16' 01020304	00060708 090A0B0C 0D0E0F10'	v2	
00001ED4	090A0B0C	0D0E0F10							
				1437					
00001EE0				1438	VRR_A	VISTR, 0, 1, 0			
00001EE0		00001EE0		1439+	DS	0FD			
00001EE0	00001F38			1440+	USING	*, R5		base for test data and test routine	
00001EE4	0016			1441+T22	DC	A(X22)		address of test routine	
00001EE6	00			1442+	DC	H' 22'		test number	
00001EE6	00			1443+	DC	X' 00'			
00001EE7	00			1444+	DC	HL1' 0'		MB used	
00001EE8	01			1445+	DC	HL1' 1'		M5 used	
00001EE9	00			1446+	DC	HL1' 0'		CC	
00001EEA	07			1447+	DC	HL1' 7'		CC failed mask	
00001EEC	00000000	00000000		1448+	DS	2F		extracted PSW after test (has CC)	
00001EF4	FF			1449+	DC	X' FF'		extracted CC, if test failed	
00001EF5	E5C9E2E3	D9404040		1450+	DC	CL8' VISTR'		instruction name	
00001F00	00001F64			1451+	DC	A(RE22)		address of v1 result	
00001F04	00001F74			1452+	DC	A(RE22+16)		address of v2 source	
00001F08	00001F84			1453+	DC	A(RE22+32)		address of v3 source	
00001F0C	00000010			1454+	DC	A(16)		result length	
00001F10	00001F64			1455+REA22	DC	A(RE22)		result address	
00001F18	00000000	00000000		1456+	DS	FD		gap	
00001F20	00000000	00000000		1457+V1022	DS	XL16		V1 output	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00001F28	00000000 00000000								
00001F30	00000000 00000000			1458+	DS	FD	gap		
				1459+*					
00001F38				1460+X22	DS	0F			
00001F38	4110 8EF8		000010F8	1461+	LA	R1, V1FUDGE	load v21 fudge		
00001F3C	E751 0000 0806		00000000	1462+	VL	v21, 0(R1)			
00001F42	E310 5024 0014		00000024	1463+	LGF	R1, V2ADDR	load v2 source		
00001F48	E761 0000 0806		00000000	1464+	VL	v22, 0(R1)	use v21 to test decoder		
00001F4E	E756 0010 0C5C			1465+	VISTR	V21, V22, 0, 1	test instruction		
00001F54	B98D 0020			1466+	EPSW	R2, R0	extract psw		
00001F58	5020 500C		0000000C	1467+	ST	R2, CCPSW	to save CC		
00001F5C	E750 5040 080E		00001F20	1468+	VST	V21, V1022	save v1 output		
00001F62	07FB			1469+	BR	R11	return		
00001F64				1470+RE22	DC	0F	V1 for this test		
00001F64				1471+	DROP	R5			
00001F64	01020300 00000000			1472	DC	XL16' 01020300 00000000 00000000 00000000'	v1		
00001F6C	00000000 00000000								
00001F74	01020300 05060708			1473	DC	XL16' 01020300 05060708 090A0B0C 0D0E0F10'	v2		
00001F7C	090A0B0C 0D0E0F10								
				1474					
				1475	VRR_A	VISTR, 0, 1, 0			
00001F88				1476+	DS	0FD			
00001F88		00001F88		1477+	USING	*, R5	base for test data and test routine		
00001F88	00001FE0			1478+T23	DC	A(X23)	address of test routine		
00001F8C	0017			1479+	DC	H' 23'	test number		
00001F8E	00			1480+	DC	X' 00'			
00001F8F	00			1481+	DC	HL1' 0'	M3 used		
00001F90	01			1482+	DC	HL1' 1'	M5 used		
00001F91	00			1483+	DC	HL1' 0'	CC		
00001F92	07			1484+	DC	HL1' 7'	CC failed mask		
00001F94	00000000 00000000			1485+	DS	2F	extracted PSW after test (has CC)		
00001F9C	FF			1486+	DC	X' FF'	extracted CC, if test failed		
00001F9D	E5C9E2E3 D9404040			1487+	DC	CL8' VISTR'	instruction name		
00001FA8	0000200C			1488+	DC	A(RE23)	address of v1 result		
00001FAC	0000201C			1489+	DC	A(RE23+16)	address of v2 source		
00001FB0	0000202C			1490+	DC	A(RE23+32)	address of v3 source		
00001FB4	00000010			1491+	DC	A(16)	result length		
00001FB8	0000200C			1492+REA23	DC	A(RE23)	result address		
00001FC0	00000000 00000000			1493+	DS	FD	gap		
00001FC8	00000000 00000000			1494+V1023	DS	XL16	V1 output		
00001FD0	00000000 00000000								
00001FD8	00000000 00000000			1495+	DS	FD	gap		
				1496+*					
00001FE0				1497+X23	DS	0F			
00001FE0	4110 8EF8		000010F8	1498+	LA	R1, V1FUDGE	load v21 fudge		
00001FE4	E751 0000 0806		00000000	1499+	VL	v21, 0(R1)			
00001FEA	E310 5024 0014		00000024	1500+	LGF	R1, V2ADDR	load v2 source		
00001FF0	E761 0000 0806		00000000	1501+	VL	v22, 0(R1)	use v21 to test decoder		
00001FF6	E756 0010 0C5C			1502+	VISTR	V21, V22, 0, 1	test instruction		
00001FFC	B98D 0020			1503+	EPSW	R2, R0	extract psw		
00002000	5020 500C		0000000C	1504+	ST	R2, CCPSW	to save CC		
00002004	E750 5040 080E		00001FC8	1505+	VST	V21, V1023	save v1 output		
0000200A	07FB			1506+	BR	R11	return		
0000200C				1507+RE23	DC	0F	V1 for this test		
0000200C				1508+	DROP	R5			
0000200C	01020000 00000000			1509	DC	XL16' 01020000 00000000 00000000 00000000'	v1		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002014	00000000	00000000							
0000201C	01020004	05060708		1510	DC	XL16'	01020004 05060708 090A0B0C 0D0E0F10'	v2	
00002024	090A0B0C	0D0E0F10							
				1511					
				1512	VRR_A	VISTR, 0, 1, 0			
00002030				1513+	DS	0FD			
00002030		00002030		1514+	USING	*, R5	base for test data and test routine		
00002030	00002088			1515+T24	DC	A(X24)	address of test routine		
00002034	0018			1516+	DC	H' 24'	test number		
00002036	00			1517+	DC	X' 00'			
00002037	00			1518+	DC	HL1' 0'	MB used		
00002038	01			1519+	DC	HL1' 1'	M5 used		
00002039	00			1520+	DC	HL1' 0'	CC		
0000203A	07			1521+	DC	HL1' 7'	CC failed mask		
0000203C	00000000	00000000		1522+	DS	2F	extracted PSW after test (has CC)		
00002044	FF			1523+	DC	X' FF'	extracted CC, if test failed		
00002045	E5C9E2E3	D9404040		1524+	DC	CL8' VISTR'	instruction name		
00002050	000020B4			1525+	DC	A(RE24)	address of v1 result		
00002054	000020C4			1526+	DC	A(RE24+16)	address of v2 source		
00002058	000020D4			1527+	DC	A(RE24+32)	address of v3 source		
0000205C	00000010			1528+	DC	A(16)	result length		
00002060	000020B4			1529+REA24	DC	A(RE24)	result address		
00002068	00000000	00000000		1530+	DS	FD	gap		
00002070	00000000	00000000		1531+V1024	DS	XL16	V1 output		
00002078	00000000	00000000							
00002080	00000000	00000000		1532+	DS	FD	gap		
				1533+*					
00002088				1534+X24	DS	0F			
00002088	4110 8EF8		000010F8	1535+	LA	R1, V1FUDGE	load v21 fudge		
0000208C	E751 0000 0806		00000000	1536+	VL	v21, 0(R1)			
00002092	E310 5024 0014		00000024	1537+	LGF	R1, V2ADDR	load v2 source		
00002098	E761 0000 0806		00000000	1538+	VL	v22, 0(R1)	use v21 to test decoder		
0000209E	E756 0010 0C5C			1539+	VISTR	V21, V22, 0, 1	test instruction		
000020A4	B98D 0020			1540+	EPSW	R2, R0	extract psw		
000020A8	5020 500C		0000000C	1541+	ST	R2, CCPSW	to save CC		
000020AC	E750 5040 080E		00002070	1542+	VST	V21, V1024	save v1 output		
000020B2	07FB			1543+	BR	R11	return		
000020B4				1544+RE24	DC	0F	V1 for this test		
000020B4				1545+	DROP	R5			
000020B4	01000000	00000000		1546	DC	XL16' 01000000 00000000 00000000 00000000'	v1		
000020BC	00000000	00000000							
000020C4	01000304	05060708		1547	DC	XL16' 01000304 05060708 090A0B0C 0D0E0F10'	v2		
000020CC	090A0B0C	0D0E0F10							
				1548					
				1549	VRR_A	VISTR, 0, 1, 0			
000020D8				1550+	DS	0FD			
000020D8		000020D8		1551+	USING	*, R5	base for test data and test routine		
000020D8	00002130			1552+T25	DC	A(X25)	address of test routine		
000020DC	0019			1553+	DC	H' 25'	test number		
000020DE	00			1554+	DC	X' 00'			
000020DF	00			1555+	DC	HL1' 0'	MB used		
000020E0	01			1556+	DC	HL1' 1'	M5 used		
000020E1	00			1557+	DC	HL1' 0'	CC		
000020E2	07			1558+	DC	HL1' 7'	CC failed mask		
000020E4	00000000	00000000		1559+	DS	2F	extracted PSW after test (has CC)		
000020EC	FF			1560+	DC	X' FF'	extracted CC, if test failed		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
000020ED	E5C9E2E3 D9404040			1561+	DC	CL8' VISTR'	instruction name
000020F8	0000215C			1562+	DC	A(RE25)	address of v1 result
000020FC	0000216C			1563+	DC	A(RE25+16)	address of v2 source
00002100	0000217C			1564+	DC	A(RE25+32)	address of v3 source
00002104	00000010			1565+	DC	A(16)	result length
00002108	0000215C			1566+REA25	DC	A(RE25)	result address
00002110	00000000 00000000			1567+	DS	FD	gap
00002118	00000000 00000000			1568+V1025	DS	XL16	V1 output
00002120	00000000 00000000						
00002128	00000000 00000000			1569+	DS	FD	gap
				1570+*			
00002130				1571+X25	DS	OF	
00002130	4110 8EF8		000010F8	1572+	LA	R1, V1FUDGE	load v21 fudge
00002134	E751 0000 0806		00000000	1573+	VL	v21, 0(R1)	
0000213A	E310 5024 0014		00000024	1574+	LGF	R1, V2ADDR	load v2 source
00002140	E761 0000 0806		00000000	1575+	VL	v22, 0(R1)	use v21 to test decoder
00002146	E756 0010 0C5C			1576+	VISTR	V21, V22, 0, 1	test instruction
0000214C	B98D 0020			1577+	EPSW	R2, R0	extract psw
00002150	5020 500C		0000000C	1578+	ST	R2, CCPSW	to save CC
00002154	E750 5040 080E		00002118	1579+	VST	V21, V1025	save v1 output
0000215A	07FB			1580+	BR	R11	return
0000215C				1581+RE25	DC	OF	V1 for this test
0000215C				1582+	DROP	R5	
0000215C	00000000 00000000			1583	DC	XL16' 00000000 00000000 00000000 00000000'	v1
00002164	00000000 00000000						
0000216C	00020304 05060708			1584	DC	XL16' 00020304 05060708 090A0B0C 0D0E0F10'	v2
00002174	090A0B0C 0D0E0F10						

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				1586 *halfword		
				1587	VRR_A VISTR, 1, 1, 3	
00002180				1588+	DS OFD	
00002180		00002180		1589+	USING *, R5	base for test data and test routine
00002180	000021D8			1590+T26	DC A(X26)	address of test routine
00002184	001A			1591+	DC H' 26'	test number
00002186	00			1592+	DC X' 00'	
00002187	01			1593+	DC HL1' 1'	M3 used
00002188	01			1594+	DC HL1' 1'	M5 used
00002189	03			1595+	DC HL1' 3'	CC
0000218A	0E			1596+	DC HL1' 14'	CC failed mask
0000218C	00000000 00000000			1597+	DS 2F	extracted PSW after test (has CC)
00002194	FF			1598+	DC X' FF'	extracted CC, if test failed
00002195	E5C9E2E3 D9404040			1599+	DC CL8' VISTR'	instruction name
000021A0	00002204			1600+	DC A(RE26)	address of v1 result
000021A4	00002214			1601+	DC A(RE26+16)	address of v2 source
000021A8	00002224			1602+	DC A(RE26+32)	address of v3 source
000021AC	00000010			1603+	DC A(16)	result length
000021B0	00002204			1604+REA26	DC A(RE26)	result address
000021B8	00000000 00000000			1605+	DS FD	gap
000021C0	00000000 00000000			1606+V1026	DS XL16	V1 output
000021C8	00000000 00000000					
000021D0	00000000 00000000			1607+	DS FD	gap
				1608+*		
000021D8				1609+X26	DS OF	
000021D8	4110 8EF8		000010F8	1610+	LA R1, V1FUDGE	load v21 fudge
000021DC	E751 0000 0806		00000000	1611+	VL v21, 0(R1)	
000021E2	E310 5024 0014		00000024	1612+	LGF R1, V2ADDR	load v2 source
000021E8	E761 0000 0806		00000000	1613+	VL v22, 0(R1)	use v21 to test decoder
000021EE	E756 0010 1C5C			1614+	VISTR V21, V22, 1, 1	test instruction
000021F4	B98D 0020			1615+	EPSW R2, R0	extract psw
000021F8	5020 500C		0000000C	1616+	ST R2, CCPSW	to save CC
000021FC	E750 5040 080E		000021C0	1617+	VST V21, V1026	save v1 output
00002202	07FB			1618+	BR R11	return
00002204				1619+RE26	DC OF	V1 for this test
00002204				1620+	DROP R5	
00002204	88888888 77777777			1621	DC XL16' 88888888 77777777 66666666 55555555'	v1
0000220C	66666666 55555555					
00002214	88888888 77777777			1622	DC XL16' 88888888 77777777 66666666 55555555'	v2
0000221C	66666666 55555555					
				1623		
				1624	VRR_A VISTR, 1, 1, 0	
00002228				1625+	DS OFD	
00002228		00002228		1626+	USING *, R5	base for test data and test routine
00002228	00002280			1627+T27	DC A(X27)	address of test routine
0000222C	001B			1628+	DC H' 27'	test number
0000222E	00			1629+	DC X' 00'	
0000222F	01			1630+	DC HL1' 1'	M3 used
00002230	01			1631+	DC HL1' 1'	M5 used
00002231	00			1632+	DC HL1' 0'	CC
00002232	07			1633+	DC HL1' 7'	CC failed mask
00002234	00000000 00000000			1634+	DS 2F	extracted PSW after test (has CC)
0000223C	FF			1635+	DC X' FF'	extracted CC, if test failed
0000223D	E5C9E2E3 D9404040			1636+	DC CL8' VISTR'	instruction name
00002248	000022AC			1637+	DC A(RE27)	address of v1 result
0000224C	000022BC			1638+	DC A(RE27+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002250	000022CC			1639+	DC	A(RE27+32)	address of v3 source		
00002254	00000010			1640+	DC	A(16)	result length		
00002258	000022AC			1641+REA27	DC	A(RE27)	result address		
00002260	00000000 00000000			1642+	DS	FD	gap		
00002268	00000000 00000000			1643+V1027	DS	XL16	V1 output		
00002270	00000000 00000000								
00002278	00000000 00000000			1644+	DS	FD	gap		
				1645+*					
00002280				1646+X27	DS	OF			
00002280	4110 8EF8		000010F8	1647+	LA	R1, V1FUDGE	load v21 fudge		
00002284	E751 0000 0806		00000000	1648+	VL	v21, 0(R1)			
0000228A	E310 5024 0014		00000024	1649+	LGF	R1, V2ADDR	load v2 source		
00002290	E761 0000 0806		00000000	1650+	VL	v22, 0(R1)	use v21 to test decoder		
00002296	E756 0010 1C5C			1651+	VISTR	V21, V22, 1, 1	test instruction		
0000229C	B98D 0020			1652+	EPSW	R2, R0	extract psw		
000022A0	5020 500C		0000000C	1653+	ST	R2, CCPSW	to save CC		
000022A4	E750 5040 080E		00002268	1654+	VST	V21, V1027	save v1 output		
000022AA	07FB			1655+	BR	R11	return		
000022AC				1656+RE27	DC	OF	V1 for this test		
000022AC				1657+	DROP	R5			
000022AC	88888888 77777777			1658	DC	XL16' 88888888 77777777 66666666 55550000'	v1		
000022B4	66666666 55550000								
000022BC	88888888 77777777			1659	DC	XL16' 88888888 77777777 66666666 55550000'	v2		
000022C4	66666666 55550000								
				1660					
				1661	VRR_A	VISTR, 1, 1, 0			
000022D0				1662+	DS	OFD			
000022D0		000022D0		1663+	USING	*, R5	base for test data and test routine		
000022D0	00002328			1664+T28	DC	A(X28)	address of test routine		
000022D4	001C			1665+	DC	H' 28'	test number		
000022D6	00			1666+	DC	X' 00'			
000022D7	01			1667+	DC	HL1' 1'	M3 used		
000022D8	01			1668+	DC	HL1' 1'	M5 used		
000022D9	00			1669+	DC	HL1' 0'	CC		
000022DA	07			1670+	DC	HL1' 7'	CC failed mask		
000022DC	00000000 00000000			1671+	DS	2F	extracted PSW after test (has CC)		
000022E4	FF			1672+	DC	X' FF'	extracted CC, if test failed		
000022E5	E5C9E2E3 D9404040			1673+	DC	CL8' VISTR'	instruction name		
000022F0	00002354			1674+	DC	A(RE28)	address of v1 result		
000022F4	00002364			1675+	DC	A(RE28+16)	address of v2 source		
000022F8	00002374			1676+	DC	A(RE28+32)	address of v3 source		
000022FC	00000010			1677+	DC	A(16)	result length		
00002300	00002354			1678+REA28	DC	A(RE28)	result address		
00002308	00000000 00000000			1679+	DS	FD	gap		
00002310	00000000 00000000			1680+V1028	DS	XL16	V1 output		
00002318	00000000 00000000								
00002320	00000000 00000000			1681+	DS	FD	gap		
				1682+*					
00002328				1683+X28	DS	OF			
00002328	4110 8EF8		000010F8	1684+	LA	R1, V1FUDGE	load v21 fudge		
0000232C	E751 0000 0806		00000000	1685+	VL	v21, 0(R1)			
00002332	E310 5024 0014		00000024	1686+	LGF	R1, V2ADDR	load v2 source		
00002338	E761 0000 0806		00000000	1687+	VL	v22, 0(R1)	use v21 to test decoder		
0000233E	E756 0010 1C5C			1688+	VISTR	V21, V22, 1, 1	test instruction		
00002344	B98D 0020			1689+	EPSW	R2, R0	extract psw		
00002348	5020 500C		0000000C	1690+	ST	R2, CCPSW	to save CC		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
0000234C	E750 5040 080E		00002310	1691+	VST	V21, V1028	save v1 output		
00002352	07FB			1692+	BR	R11	return		
00002354				1693+RE28	DC	0F	V1 for this test		
00002354				1694+	DROP	R5			
00002354	88888888 77777777			1695	DC	XL16' 88888888 77777777 66666666 00000000'	v1		
0000235C	66666666 00000000								
00002364	88888888 77777777			1696	DC	XL16' 88888888 77777777 66666666 00005555'	v2		
0000236C	66666666 00005555								
				1697					
				1698	VRR_A	VISTR, 1, 1, 0			
00002378				1699+	DS	0FD			
00002378		00002378		1700+	USING	*, R5	base for test data and test routine		
00002378	000023D0			1701+T29	DC	A(X29)	address of test routine		
0000237C	001D			1702+	DC	H' 29'	test number		
0000237E	00			1703+	DC	X' 00'			
0000237F	01			1704+	DC	HL1' 1'	MB used		
00002380	01			1705+	DC	HL1' 1'	M5 used		
00002381	00			1706+	DC	HL1' 0'	CC		
00002382	07			1707+	DC	HL1' 7'	CC failed mask		
00002384	00000000 00000000			1708+	DS	2F	extracted PSW after test (has CC)		
0000238C	FF			1709+	DC	X' FF'	extracted CC, if test failed		
0000238D	E5C9E2E3 D9404040			1710+	DC	CL8' VISTR'	instruction name		
00002398	000023FC			1711+	DC	A(RE29)	address of v1 result		
0000239C	0000240C			1712+	DC	A(RE29+16)	address of v2 source		
000023A0	0000241C			1713+	DC	A(RE29+32)	address of v3 source		
000023A4	00000010			1714+	DC	A(16)	result length		
000023A8	000023FC			1715+REA29	DC	A(RE29)	result address		
000023B0	00000000 00000000			1716+	DS	FD	gap		
000023B8	00000000 00000000			1717+V1029	DS	XL16	V1 output		
000023C0	00000000 00000000								
000023C8	00000000 00000000			1718+	DS	FD	gap		
				1719+*					
000023D0				1720+X29	DS	0F			
000023D0	4110 8EF8		000010F8	1721+	LA	R1, V1FUDGE	load v21 fudge		
000023D4	E751 0000 0806		00000000	1722+	VL	v21, 0(R1)			
000023DA	E310 5024 0014		00000024	1723+	LGF	R1, V2ADDR	load v2 source		
000023E0	E761 0000 0806		00000000	1724+	VL	v22, 0(R1)	use v21 to test decoder		
000023E6	E756 0010 1C5C			1725+	VISTR	V21, V22, 1, 1	test instruction		
000023EC	B98D 0020			1726+	EPSW	R2, R0	extract psw		
000023F0	5020 500C		0000000C	1727+	ST	R2, CCPSW	to save CC		
000023F4	E750 5040 080E		000023B8	1728+	VST	V21, V1029	save v1 output		
000023FA	07FB			1729+	BR	R11	return		
000023FC				1730+RE29	DC	0F	V1 for this test		
000023FC				1731+	DROP	R5			
000023FC	88888888 77777777			1732	DC	XL16' 88888888 77777777 66660000 00000000'	v1		
00002404	66660000 00000000								
0000240C	88888888 77777777			1733	DC	XL16' 88888888 77777777 66660000 55555555'	v2		
00002414	66660000 55555555								
				1734					
				1735	VRR_A	VISTR, 1, 1, 0			
00002420				1736+	DS	0FD			
00002420		00002420		1737+	USING	*, R5	base for test data and test routine		
00002420	00002478			1738+T30	DC	A(X30)	address of test routine		
00002424	001E			1739+	DC	H' 30'	test number		
00002426	00			1740+	DC	X' 00'			
00002427	01			1741+	DC	HL1' 1'	MB used		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00002428	01			1742+	DC	HL1' 1' M5 used
00002429	00			1743+	DC	HL1' 0' CC
0000242A	07			1744+	DC	HL1' 7' CC failed mask
0000242C	00000000 00000000			1745+	DS	2F extracted PSW after test (has CC)
00002434	FF			1746+	DC	X' FF' extracted CC, if test failed
00002435	E5C9E2E3 D9404040			1747+	DC	CL8' VISTR' instruction name
00002440	000024A4			1748+	DC	A(RE30) address of v1 result
00002444	000024B4			1749+	DC	A(RE30+16) address of v2 source
00002448	000024C4			1750+	DC	A(RE30+32) address of v3 source
0000244C	00000010			1751+	DC	A(16) result length
00002450	000024A4			1752+REA30	DC	A(RE30) result address
00002458	00000000 00000000			1753+	DS	FD gap
00002460	00000000 00000000			1754+V1030	DS	XL16 V1 output
00002468	00000000 00000000					
00002470	00000000 00000000			1755+	DS	FD gap
				1756+*		
00002478				1757+X30	DS	0F
00002478	4110 8EF8		000010F8	1758+	LA	R1, V1FUDGE load v21 fudge
0000247C	E751 0000 0806		00000000	1759+	VL	v21, 0(R1)
00002482	E310 5024 0014		00000024	1760+	LGF	R1, V2ADDR load v2 source
00002488	E761 0000 0806		00000000	1761+	VL	v22, 0(R1) use v21 to test decoder
0000248E	E756 0010 1C5C			1762+	VISTR	V21, V22, 1, 1 test instruction
00002494	B98D 0020			1763+	EPSW	R2, R0 extract psw
00002498	5020 500C		0000000C	1764+	ST	R2, CCPSW to save CC
0000249C	E750 5040 080E		00002460	1765+	VST	V21, V1030 save v1 output
000024A2	07FB			1766+	BR	R11 return
000024A4				1767+RE30	DC	0F V1 for this test
000024A4				1768+	DROP	R5
000024A4	88888888 77777777			1769	DC	XL16' 88888888 77777777 00000000 00000000' v1
000024AC	00000000 00000000					
000024B4	88888888 77777777			1770	DC	XL16' 88888888 77777777 00006666 55555555' v2
000024BC	00006666 55555555					
				1771		
				1772	VRR_A	VISTR, 1, 1, 0
000024C8				1773+	DS	0FD
000024C8		000024C8		1774+	USING	*, R5 base for test data and test routine
000024C8	00002520			1775+T31	DC	A(X31) address of test routine
000024CC	001F			1776+	DC	H' 31' test number
000024CE	00			1777+	DC	X' 00'
000024CF	01			1778+	DC	HL1' 1' M3 used
000024D0	01			1779+	DC	HL1' 1' M5 used
000024D1	00			1780+	DC	HL1' 0' CC
000024D2	07			1781+	DC	HL1' 7' CC failed mask
000024D4	00000000 00000000			1782+	DS	2F extracted PSW after test (has CC)
000024DC	FF			1783+	DC	X' FF' extracted CC, if test failed
000024DD	E5C9E2E3 D9404040			1784+	DC	CL8' VISTR' instruction name
000024E8	0000254C			1785+	DC	A(RE31) address of v1 result
000024EC	0000255C			1786+	DC	A(RE31+16) address of v2 source
000024F0	0000256C			1787+	DC	A(RE31+32) address of v3 source
000024F4	00000010			1788+	DC	A(16) result length
000024F8	0000254C			1789+REA31	DC	A(RE31) result address
00002500	00000000 00000000			1790+	DS	FD gap
00002508	00000000 00000000			1791+V1031	DS	XL16 V1 output
00002510	00000000 00000000					
00002518	00000000 00000000			1792+	DS	FD gap
				1793+*		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002520				1794+X31	DS	OF			
00002520	4110 8EF8		000010F8	1795+	LA	R1, V1FUDGE	load v21 fudge		
00002524	E751 0000 0806		00000000	1796+	VL	v21, 0(R1)			
0000252A	E310 5024 0014		00000024	1797+	LGF	R1, V2ADDR	load v2 source		
00002530	E761 0000 0806		00000000	1798+	VL	v22, 0(R1)	use v21 to test decoder		
00002536	E756 0010 1C5C			1799+	VISTR	V21, V22, 1, 1	test instruction		
0000253C	B98D 0020			1800+	EPSW	R2, R0	extract psw		
00002540	5020 500C		0000000C	1801+	ST	R2, CCPSW	to save CC		
00002544	E750 5040 080E		00002508	1802+	VST	V21, V1031	save v1 output		
0000254A	07FB			1803+	BR	R11	return		
0000254C				1804+RE31	DC	OF	V1 for this test		
0000254C				1805+	DROP	R5			
0000254C	88888888 77770000			1806	DC	XL16' 88888888 77770000 00000000 00000000'	v1		
00002554	00000000 00000000								
0000255C	88888888 77770000			1807	DC	XL16' 88888888 77770000 66666666 55555555'	v2		
00002564	66666666 55555555								
				1808					
00002570				1809	VRR_A	VISTR, 1, 1, 0			
00002570		00002570		1810+	DS	OFD			
00002570	000025C8			1811+	USING	*, R5	base for test data and test routine		
00002574	0020			1812+T32	DC	A(X32)	address of test routine		
00002576	00			1813+	DC	H' 32'	test number		
00002576	00			1814+	DC	X' 00'			
00002577	01			1815+	DC	HL1' 1'	M3 used		
00002578	01			1816+	DC	HL1' 1'	M5 used		
00002579	00			1817+	DC	HL1' 0'	CC		
0000257A	07			1818+	DC	HL1' 7'	CC failed mask		
0000257C	00000000 00000000			1819+	DS	2F	extracted PSW after test (has CC)		
00002584	FF			1820+	DC	X' FF'	extracted CC, if test failed		
00002585	E5C9E2E3 D9404040			1821+	DC	CL8' VISTR'	instruction name		
00002590	000025F4			1822+	DC	A(RE32)	address of v1 result		
00002594	00002604			1823+	DC	A(RE32+16)	address of v2 source		
00002598	00002614			1824+	DC	A(RE32+32)	address of v3 source		
0000259C	00000010			1825+	DC	A(16)	result length		
000025A0	000025F4			1826+REA32	DC	A(RE32)	result address		
000025A8	00000000 00000000			1827+	DS	FD	gap		
000025B0	00000000 00000000			1828+V1032	DS	XL16	V1 output		
000025B8	00000000 00000000								
000025C0	00000000 00000000			1829+	DS	FD	gap		
				1830+*					
000025C8				1831+X32	DS	OF			
000025C8	4110 8EF8		000010F8	1832+	LA	R1, V1FUDGE	load v21 fudge		
000025CC	E751 0000 0806		00000000	1833+	VL	v21, 0(R1)			
000025D2	E310 5024 0014		00000024	1834+	LGF	R1, V2ADDR	load v2 source		
000025D8	E761 0000 0806		00000000	1835+	VL	v22, 0(R1)	use v21 to test decoder		
000025DE	E756 0010 1C5C			1836+	VISTR	V21, V22, 1, 1	test instruction		
000025E4	B98D 0020			1837+	EPSW	R2, R0	extract psw		
000025E8	5020 500C		0000000C	1838+	ST	R2, CCPSW	to save CC		
000025EC	E750 5040 080E		000025B0	1839+	VST	V21, V1032	save v1 output		
000025F2	07FB			1840+	BR	R11	return		
000025F4				1841+RE32	DC	OF	V1 for this test		
000025F4				1842+	DROP	R5			
000025F4	88888888 00000000			1843	DC	XL16' 88888888 00000000 00000000 00000000'	v1		
000025FC	00000000 00000000								
00002604	88888888 00007777			1844	DC	XL16' 88888888 00007777 66666666 55555555'	v2		
0000260C	66666666 55555555								

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				1845		
				1846	VRR_A VISTR, 1, 1, 0	
00002618				1847+	DS OFD	
00002618		00002618		1848+	USING *, R5	base for test data and test routine
00002618	00002670			1849+T33	DC A(X33)	address of test routine
0000261C	0021			1850+	DC H' 33'	test number
0000261E	00			1851+	DC X' 00'	
0000261F	01			1852+	DC HL1' 1'	M3 used
00002620	01			1853+	DC HL1' 1'	M5 used
00002621	00			1854+	DC HL1' 0'	CC
00002622	07			1855+	DC HL1' 7'	CC failed mask
00002624	00000000 00000000			1856+	DS 2F	extracted PSW after test (has CC)
0000262C	FF			1857+	DC X' FF'	extracted CC, if test failed
0000262D	E5C9E2E3 D9404040			1858+	DC CL8' VISTR'	instruction name
00002638	0000269C			1859+	DC A(RE33)	address of v1 result
0000263C	000026AC			1860+	DC A(RE33+16)	address of v2 source
00002640	000026BC			1861+	DC A(RE33+32)	address of v3 source
00002644	00000010			1862+	DC A(16)	result length
00002648	0000269C			1863+REA33	DC A(RE33)	result address
00002650	00000000 00000000			1864+	DS FD	gap
00002658	00000000 00000000			1865+V1033	DS XL16	V1 output
00002660	00000000 00000000					
00002668	00000000 00000000			1866+	DS FD	gap
				1867+*		
00002670				1868+X33	DS OF	
00002670	4110 8EF8		000010F8	1869+	LA R1, V1FUDGE	load v21 fudge
00002674	E751 0000 0806		00000000	1870+	VL v21, 0(R1)	
0000267A	E310 5024 0014		00000024	1871+	LGF R1, V2ADDR	load v2 source
00002680	E761 0000 0806		00000000	1872+	VL v22, 0(R1)	use v21 to test decoder
00002686	E756 0010 1C5C			1873+	VISTR V21, V22, 1, 1	test instruction
0000268C	B98D 0020			1874+	EPSW R2, R0	extract psw
00002690	5020 500C		0000000C	1875+	ST R2, CCPSW	to save CC
00002694	E750 5040 080E		00002658	1876+	VST V21, V1033	save v1 output
0000269A	07FB			1877+	BR R11	return
0000269C				1878+RE33	DC OF	V1 for this test
0000269C				1879+	DROP R5	
0000269C	88880000 00000000			1880	DC XL16' 88880000 00000000 00000000 00000000'	v1
000026A4	00000000 00000000					
000026AC	88880000 77777777			1881	DC XL16' 88880000 77777777 66666666 55555555'	v2
000026B4	66666666 55555555					
				1882		
				1883	VRR_A VISTR, 1, 1, 0	
000026C0				1884+	DS OFD	
000026C0		000026C0		1885+	USING *, R5	base for test data and test routine
000026C0	00002718			1886+T34	DC A(X34)	address of test routine
000026C4	0022			1887+	DC H' 34'	test number
000026C6	00			1888+	DC X' 00'	
000026C7	01			1889+	DC HL1' 1'	M3 used
000026C8	01			1890+	DC HL1' 1'	M5 used
000026C9	00			1891+	DC HL1' 0'	CC
000026CA	07			1892+	DC HL1' 7'	CC failed mask
000026CC	00000000 00000000			1893+	DS 2F	extracted PSW after test (has CC)
000026D4	FF			1894+	DC X' FF'	extracted CC, if test failed
000026D5	E5C9E2E3 D9404040			1895+	DC CL8' VISTR'	instruction name
000026E0	00002744			1896+	DC A(RE34)	address of v1 result
000026E4	00002754			1897+	DC A(RE34+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000026E8	00002764			1898+	DC	A(RE34+32)	address of v3 source		
000026EC	00000010			1899+	DC	A(16)	result length		
000026F0	00002744			1900+REA34	DC	A(RE34)	result address		
000026F8	00000000 00000000			1901+	DS	FD	gap		
00002700	00000000 00000000			1902+V1034	DS	XL16	V1 output		
00002708	00000000 00000000								
00002710	00000000 00000000			1903+	DS	FD	gap		
				1904+*					
00002718				1905+X34	DS	OF			
00002718	4110 8EF8		000010F8	1906+	LA	R1, V1FUDGE	load v21 fudge		
0000271C	E751 0000 0806		00000000	1907+	VL	v21, 0(R1)			
00002722	E310 5024 0014		00000024	1908+	LGF	R1, V2ADDR	load v2 source		
00002728	E761 0000 0806		00000000	1909+	VL	v22, 0(R1)	use v21 to test decoder		
0000272E	E756 0010 1C5C			1910+	VISTR	V21, V22, 1, 1	test instruction		
00002734	B98D 0020			1911+	EPSW	R2, R0	extract psw		
00002738	5020 500C		0000000C	1912+	ST	R2, CCPSW	to save CC		
0000273C	E750 5040 080E		00002700	1913+	VST	V21, V1034	save v1 output		
00002742	07FB			1914+	BR	R11	return		
00002744				1915+RE34	DC	OF	V1 for this test		
00002744				1916+	DROP	R5			
00002744	00000000 00000000			1917	DC	XL16' 00000000 00000000 00000000 00000000'	v1		
0000274C	00000000 00000000								
00002754	00008888 77777777			1918	DC	XL16' 00008888 77777777 66666666 55555555'	v2		
0000275C	66666666 55555555								

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				1920 *word		
				1921	VRR_A VISTR, 2, 1, 3	
00002768				1922+	DS OFD	
00002768		00002768		1923+	USING *, R5	base for test data and test routine
00002768	000027C0			1924+T35	DC A(X35)	address of test routine
0000276C	0023			1925+	DC H' 35'	test number
0000276E	00			1926+	DC X' 00'	
0000276F	02			1927+	DC HL1' 2'	M3 used
00002770	01			1928+	DC HL1' 1'	M5 used
00002771	03			1929+	DC HL1' 3'	CC
00002772	0E			1930+	DC HL1' 14'	CC failed mask
00002774	00000000 00000000			1931+	DS 2F	extracted PSW after test (has CC)
0000277C	FF			1932+	DC X' FF'	extracted CC, if test failed
0000277D	E5C9E2E3 D9404040			1933+	DC CL8' VISTR'	instruction name
00002788	000027EC			1934+	DC A(RE35)	address of v1 result
0000278C	000027FC			1935+	DC A(RE35+16)	address of v2 source
00002790	0000280C			1936+	DC A(RE35+32)	address of v3 source
00002794	00000010			1937+	DC A(16)	result length
00002798	000027EC			1938+REA35	DC A(RE35)	result address
000027A0	00000000 00000000			1939+	DS FD	gap
000027A8	00000000 00000000			1940+V1035	DS XL16	V1 output
000027B0	00000000 00000000					
000027B8	00000000 00000000			1941+	DS FD	gap
				1942+*		
000027C0				1943+X35	DS OF	
000027C0	4110 8EF8		000010F8	1944+	LA R1, V1FUDGE	load v21 fudge
000027C4	E751 0000 0806		00000000	1945+	VL v21, 0(R1)	
000027CA	E310 5024 0014		00000024	1946+	LGF R1, V2ADDR	load v2 source
000027D0	E761 0000 0806		00000000	1947+	VL v22, 0(R1)	use v21 to test decoder
000027D6	E756 0010 2C5C			1948+	VISTR V21, V22, 2, 1	test instruction
000027DC	B98D 0020			1949+	EPSW R2, R0	extract psw
000027E0	5020 500C		0000000C	1950+	ST R2, CCPSW	to save CC
000027E4	E750 5040 080E		000027A8	1951+	VST V21, V1035	save v1 output
000027EA	07FB			1952+	BR R11	return
000027EC				1953+RE35	DC OF	V1 for this test
000027EC				1954+	DROP R5	
000027EC	AAAAAAAA BBBB BBBB			1955	DC XL16' AAAAAAAAA BBBB BBBB CCCCCCCC DDDDDDDD'	v1
000027F4	CCCCCCCC DDDDDDDD					
000027FC	AAAAAAAA BBBB BBBB			1956	DC XL16' AAAAAAAAA BBBB BBBB CCCCCCCC DDDDDDDD'	v2
00002804	CCCCCCCC DDDDDDDD					
				1957		
00002810				1958	VRR_A VISTR, 2, 1, 0	
00002810		00002810		1959+	DS OFD	
00002810	00002868			1960+	USING *, R5	base for test data and test routine
00002814	0024			1961+T36	DC A(X36)	address of test routine
00002816	00			1962+	DC H' 36'	test number
00002817	02			1963+	DC X' 00'	
00002818	01			1964+	DC HL1' 2'	M3 used
00002819	00			1965+	DC HL1' 1'	M5 used
0000281A	07			1966+	DC HL1' 0'	CC
0000281C	00000000 00000000			1967+	DC HL1' 7'	CC failed mask
00002824	FF			1968+	DS 2F	extracted PSW after test (has CC)
00002825	E5C9E2E3 D9404040			1969+	DC X' FF'	extracted CC, if test failed
00002830	00002894			1970+	DC CL8' VISTR'	instruction name
00002834	000028A4			1971+	DC A(RE36)	address of v1 result
				1972+	DC A(RE36+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002838	000028B4			1973+	DC	A(RE36+32)	address of v3 source
0000283C	00000010			1974+	DC	A(16)	result length
00002840	00002894			1975+REA36	DC	A(RE36)	result address
00002848	00000000 00000000			1976+	DS	FD	gap
00002850	00000000 00000000			1977+V1036	DS	XL16	V1 output
00002858	00000000 00000000						
00002860	00000000 00000000			1978+	DS	FD	gap
				1979+*			
00002868				1980+X36	DS	OF	
00002868	4110 8EF8		000010F8	1981+	LA	R1, V1FUDGE	load v21 fudge
0000286C	E751 0000 0806		00000000	1982+	VL	v21, 0(R1)	
00002872	E310 5024 0014		00000024	1983+	LGF	R1, V2ADDR	load v2 source
00002878	E761 0000 0806		00000000	1984+	VL	v22, 0(R1)	use v21 to test decoder
0000287E	E756 0010 2C5C			1985+	VISTR	V21, V22, 2, 1	test instruction
00002884	B98D 0020			1986+	EPSW	R2, R0	extract psw
00002888	5020 500C		0000000C	1987+	ST	R2, CCPSW	to save CC
0000288C	E750 5040 080E		00002850	1988+	VST	V21, V1036	save v1 output
00002892	07FB			1989+	BR	R11	return
00002894				1990+RE36	DC	OF	V1 for this test
00002894				1991+	DROP	R5	
00002894	AAAAAAAA BBBB BBBB			1992	DC	XL16' AAAAAAAAA BBBB BBBB CCCCCC 00000000'	v1
0000289C	CCCCCCCC 00000000						
000028A4	AAAAAAAA BBBB BBBB			1993	DC	XL16' AAAAAAAAA BBBB BBBB CCCCCC 00000000'	v2
000028AC	CCCCCCCC 00000000						
				1994			
				1995		VRR_A VISTR, 2, 1, 0	
000028B8				1996+	DS	OFD	
000028B8		000028B8		1997+	USING	*, R5	base for test data and test routine
000028B8	00002910			1998+T37	DC	A(X37)	address of test routine
000028BC	0025			1999+	DC	H' 37'	test number
000028BE	00			2000+	DC	X' 00'	
000028BF	02			2001+	DC	HL1' 2'	M3 used
000028C0	01			2002+	DC	HL1' 1'	M5 used
000028C1	00			2003+	DC	HL1' 0'	CC
000028C2	07			2004+	DC	HL1' 7'	CC failed mask
000028C4	00000000 00000000			2005+	DS	2F	extracted PSW after test (has CC)
000028CC	FF			2006+	DC	X' FF'	extracted CC, if test failed
000028CD	E5C9E2E3 D9404040			2007+	DC	CL8' VISTR'	instruction name
000028D8	0000293C			2008+	DC	A(RE37)	address of v1 result
000028DC	0000294C			2009+	DC	A(RE37+16)	address of v2 source
000028E0	0000295C			2010+	DC	A(RE37+32)	address of v3 source
000028E4	00000010			2011+	DC	A(16)	result length
000028E8	0000293C			2012+REA37	DC	A(RE37)	result address
000028F0	00000000 00000000			2013+	DS	FD	gap
000028F8	00000000 00000000			2014+V1037	DS	XL16	V1 output
00002900	00000000 00000000						
00002908	00000000 00000000			2015+	DS	FD	gap
				2016+*			
00002910				2017+X37	DS	OF	
00002910	4110 8EF8		000010F8	2018+	LA	R1, V1FUDGE	load v21 fudge
00002914	E751 0000 0806		00000000	2019+	VL	v21, 0(R1)	
0000291A	E310 5024 0014		00000024	2020+	LGF	R1, V2ADDR	load v2 source
00002920	E761 0000 0806		00000000	2021+	VL	v22, 0(R1)	use v21 to test decoder
00002926	E756 0010 2C5C			2022+	VISTR	V21, V22, 2, 1	test instruction
0000292C	B98D 0020			2023+	EPSW	R2, R0	extract psw
00002930	5020 500C		0000000C	2024+	ST	R2, CCPSW	to save CC

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002934	E750 5040 080E		000028F8	2025+	VST	V21, V1037	save v1 output
0000293A	07FB			2026+	BR	R11	return
0000293C				2027+RE37	DC	0F	V1 for this test
0000293C				2028+	DROP	R5	
0000293C	AAAAAAAA BBBB BBBB			2029	DC	XL16' AAAAAAAAA BBBB BBBB 00000000 00000000'	v1
00002944	00000000 00000000						
0000294C	AAAAAAAA BBBB BBBB		2030		DC	XL16' AAAAAAAAA BBBB BBBB 00000000 DDDDDDDD'	v2
00002954	00000000 DDDDDDDD						
				2031			
				2032	VRR_A	VISTR, 2, 1, 0	
00002960				2033+	DS	0FD	
00002960		00002960		2034+	USING	*, R5	base for test data and test routine
00002960	000029B8			2035+T38	DC	A(X38)	address of test routine
00002964	0026			2036+	DC	H' 38'	test number
00002966	00			2037+	DC	X' 00'	
00002967	02			2038+	DC	HL1' 2'	MB used
00002968	01			2039+	DC	HL1' 1'	M5 used
00002969	00			2040+	DC	HL1' 0'	CC
0000296A	07			2041+	DC	HL1' 7'	CC failed mask
0000296C	00000000 00000000			2042+	DS	2F	extracted PSW after test (has CC)
00002974	FF			2043+	DC	X' FF'	extracted CC, if test failed
00002975	E5C9E2E3 D9404040			2044+	DC	CL8' VISTR'	instruction name
00002980	000029E4			2045+	DC	A(RE38)	address of v1 result
00002984	000029F4			2046+	DC	A(RE38+16)	address of v2 source
00002988	00002A04			2047+	DC	A(RE38+32)	address of v3 source
0000298C	00000010			2048+	DC	A(16)	result length
00002990	000029E4			2049+REA38	DC	A(RE38)	result address
00002998	00000000 00000000			2050+	DS	FD	gap
000029A0	00000000 00000000			2051+V1038	DS	XL16	V1 output
000029A8	00000000 00000000						
000029B0	00000000 00000000			2052+	DS	FD	gap
				2053+*			
000029B8				2054+X38	DS	0F	
000029B8	4110 8EF8		000010F8	2055+	LA	R1, V1FUDGE	load v21 fudge
000029BC	E751 0000 0806		00000000	2056+	VL	v21, 0(R1)	
000029C2	E310 5024 0014		00000024	2057+	LGF	R1, V2ADDR	load v2 source
000029C8	E761 0000 0806		00000000	2058+	VL	v22, 0(R1)	use v21 to test decoder
000029CE	E756 0010 2C5C			2059+	VISTR	V21, V22, 2, 1	test instruction
000029D4	B98D 0020			2060+	EPSW	R2, R0	extract psw
000029D8	5020 500C		0000000C	2061+	ST	R2, CCPSW	to save CC
000029DC	E750 5040 080E		000029A0	2062+	VST	V21, V1038	save v1 output
000029E2	07FB			2063+	BR	R11	return
000029E4				2064+RE38	DC	0F	V1 for this test
000029E4				2065+	DROP	R5	
000029E4	AAAAAAAA 00000000			2066	DC	XL16' AAAAAAAAA 00000000 00000000 00000000'	v1
000029EC	00000000 00000000						
000029F4	AAAAAAAA 00000000		2067		DC	XL16' AAAAAAAAA 00000000 CCCCCCCC DDDDDDDD'	v2
000029FC	CCCCCCCC DDDDDDDD						
				2068			
				2069	VRR_A	VISTR, 2, 1, 0	
00002A08				2070+	DS	0FD	
00002A08		00002A08		2071+	USING	*, R5	base for test data and test routine
00002A08	00002A60			2072+T39	DC	A(X39)	address of test routine
00002A0C	0027			2073+	DC	H' 39'	test number
00002A0E	00			2074+	DC	X' 00'	
00002A0F	02			2075+	DC	HL1' 2'	MB used

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				2107 *	-----
				2108 * case 2 - two zeros	CS=1
				2109 *	-----
				2110 *byte	
				2111	VRR_A VISTR, 0, 1, 0
00002AB0				2112+	DS OFD
00002AB0		00002AB0		2113+	USING *, R5
00002AB0	00002B08			2114+T40	DC A(X40)
00002AB4	0028			2115+	DC H' 40'
00002AB6	00			2116+	DC X' 00'
00002AB7	00			2117+	DC HL1' 0'
00002AB8	01			2118+	DC HL1' 1'
00002AB9	00			2119+	DC HL1' 0'
00002ABA	07			2120+	DC HL1' 7'
00002ABC	00000000 00000000			2121+	DS 2F
00002AC4	FF			2122+	DC X' FF'
00002AC5	E5C9E2E3 D9404040			2123+	DC CL8' VISTR'
00002AD0	00002B34			2124+	DC A(RE40)
00002AD4	00002B44			2125+	DC A(RE40+16)
00002AD8	00002B54			2126+	DC A(RE40+32)
00002ADC	00000010			2127+	DC A(16)
00002AE0	00002B34			2128+REA40	DC A(RE40)
00002AE8	00000000 00000000			2129+	DS FD
00002AF0	00000000 00000000			2130+V1040	DS XL16
00002AF8	00000000 00000000				
00002B00	00000000 00000000			2131+	DS FD
				2132+*	
00002B08				2133+X40	DS OF
00002B08	4110 8EF8		000010F8	2134+	LA R1, V1FUDGE
00002B0C	E751 0000 0806		00000000	2135+	VL v21, 0(R1)
00002B12	E310 5024 0014		00000024	2136+	LGF R1, V2ADDR
00002B18	E761 0000 0806		00000000	2137+	VL v22, 0(R1)
00002B1E	E756 0010 0C5C			2138+	VISTR V21, V22, 0, 1
00002B24	B98D 0020			2139+	EPSW R2, R0
00002B28	5020 500C		0000000C	2140+	ST R2, CCPSW
00002B2C	E750 5040 080E		00002AF0	2141+	VST V21, V1040
00002B32	07FB			2142+	BR R11
00002B34				2143+RE40	DC OF
00002B34				2144+	DROP R5
00002B34	01020304 05060708			2145	DC XL16' 01020304 05060708 090A0B0C 00000000' v1
00002B3C	090A0B0C 00000000				
00002B44	01020304 05060708			2146	DC XL16' 01020304 05060708 090A0B0C 000E0F00' v2
00002B4C	090A0B0C 000E0F00				
				2147	
				2148	VRR_A VISTR, 0, 1, 0
00002B58				2149+	DS OFD
00002B58		00002B58		2150+	USING *, R5
00002B58	00002BB0			2151+T41	DC A(X41)
00002B5C	0029			2152+	DC H' 41'
00002B5E	00			2153+	DC X' 00'
00002B5F	00			2154+	DC HL1' 0'
00002B60	01			2155+	DC HL1' 1'
00002B61	00			2156+	DC HL1' 0'
00002B62	07			2157+	DC HL1' 7'
00002B64	00000000 00000000			2158+	DS 2F
00002B6C	FF			2159+	DC X' FF'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00002B6D	E5C9E2E3 D9404040			2160+	DC	CL8' VISTR'	instruction name
00002B78	00002BDC			2161+	DC	A(RE41)	address of v1 result
00002B7C	00002BEC			2162+	DC	A(RE41+16)	address of v2 source
00002B80	00002BFC			2163+	DC	A(RE41+32)	address of v3 source
00002B84	00000010			2164+	DC	A(16)	result length
00002B88	00002BDC			2165+REA41	DC	A(RE41)	result address
00002B90	00000000 00000000			2166+	DS	FD	gap
00002B98	00000000 00000000			2167+V1041	DS	XL16	V1 output
00002BA0	00000000 00000000						
00002BA8	00000000 00000000			2168+	DS	FD	gap
				2169+*			
00002BB0				2170+X41	DS	OF	
00002BB0	4110 8EF8		000010F8	2171+	LA	R1, V1FUDGE	load v21 fudge
00002BB4	E751 0000 0806		00000000	2172+	VL	v21, 0(R1)	
00002BBA	E310 5024 0014		00000024	2173+	LGF	R1, V2ADDR	load v2 source
00002BC0	E761 0000 0806		00000000	2174+	VL	v22, 0(R1)	use v21 to test decoder
00002BC6	E756 0010 0C5C			2175+	VISTR	V21, V22, 0, 1	test instruction
00002BCC	B98D 0020			2176+	EPSW	R2, R0	extract psw
00002BD0	5020 500C		0000000C	2177+	ST	R2, CCPSW	to save CC
00002BD4	E750 5040 080E		00002B98	2178+	VST	V21, V1041	save v1 output
00002BDA	07FB			2179+	BR	R11	return
00002BDC				2180+RE41	DC	OF	V1 for this test
00002BDC				2181+	DROP	R5	
00002BDC	01020304 05060708			2182	DC	XL16' 01020304 05060708 090A0B00 00000000'	v1
00002BE4	090A0B00 00000000						
00002BEC	01020304 05060708			2183	DC	XL16' 01020304 05060708 090A0B00 0D000F10'	v2
00002BF4	090A0B00 0D000F10						
				2184			
				2185	VRR_A	VISTR, 0, 1, 0	
00002C00				2186+	DS	OFD	
00002C00		00002C00		2187+	USING	*, R5	base for test data and test routine
00002C00	00002C58			2188+T42	DC	A(X42)	address of test routine
00002C04	002A			2189+	DC	H' 42'	test number
00002C06	00			2190+	DC	X' 00'	
00002C07	00			2191+	DC	HL1' 0'	M3 used
00002C08	01			2192+	DC	HL1' 1'	M5 used
00002C09	00			2193+	DC	HL1' 0'	CC
00002C0A	07			2194+	DC	HL1' 7'	CC failed mask
00002C0C	00000000 00000000			2195+	DS	2F	extracted PSW after test (has CC)
00002C14	FF			2196+	DC	X' FF'	extracted CC, if test failed
00002C15	E5C9E2E3 D9404040			2197+	DC	CL8' VISTR'	instruction name
00002C20	00002C84			2198+	DC	A(RE42)	address of v1 result
00002C24	00002C94			2199+	DC	A(RE42+16)	address of v2 source
00002C28	00002CA4			2200+	DC	A(RE42+32)	address of v3 source
00002C2C	00000010			2201+	DC	A(16)	result length
00002C30	00002C84			2202+REA42	DC	A(RE42)	result address
00002C38	00000000 00000000			2203+	DS	FD	gap
00002C40	00000000 00000000			2204+V1042	DS	XL16	V1 output
00002C48	00000000 00000000						
00002C50	00000000 00000000			2205+	DS	FD	gap
				2206+*			
00002C58				2207+X42	DS	OF	
00002C58	4110 8EF8		000010F8	2208+	LA	R1, V1FUDGE	load v21 fudge
00002C5C	E751 0000 0806		00000000	2209+	VL	v21, 0(R1)	
00002C62	E310 5024 0014		00000024	2210+	LGF	R1, V2ADDR	load v2 source
00002C68	E761 0000 0806		00000000	2211+	VL	v22, 0(R1)	use v21 to test decoder

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002C6E	E756 0010 0C5C			2212+	VISTR	V21, V22, 0, 1		test instruction	
00002C74	B98D 0020			2213+	EPSW	R2, R0		extract psw	
00002C78	5020 500C		0000000C	2214+	ST	R2, CCPSW		to save CC	
00002C7C	E750 5040 080E		00002C40	2215+	VST	V21, V1042		save v1 output	
00002C82	07FB			2216+	BR	R11		return	
00002C84				2217+RE42	DC	0F		V1 for this test	
00002C84				2218+	DROP	R5			
00002C84	01020304 05060708			2219	DC	XL16' 01020304 05060708 090A0000 00000000'		v1	
00002C8C	090A0000 00000000								
00002C94	01020304 05060708			2220	DC	XL16' 01020304 05060708 090A000C 000E0F10'		v2	
00002C9C	090A000C 000E0F10								
00002CA8				2221					
00002CA8		00002CA8		2222	VRR_A	VISTR, 0, 1, 0			
00002CA8	00002D00			2223+	DS	0FD			
00002CAC	002B			2224+	USING	*, R5		base for test data and test routine	
00002CAE	00			2225+T43	DC	A(X43)		address of test routine	
00002CAF	00			2226+	DC	H' 43'		test number	
00002CB0	01			2227+	DC	X' 00'			
00002CB1	00			2228+	DC	HL1' 0'		M3 used	
00002CB2	07			2229+	DC	HL1' 1'		M5 used	
00002CB4	00000000 00000000			2230+	DC	HL1' 0'		CC	
00002CBC	FF			2231+	DC	HL1' 7'		CC failed mask	
00002CBD	E5C9E2E3 D9404040			2232+	DS	2F		extracted PSW after test (has CC)	
00002CC8	00002D2C			2233+	DC	X' FF'		extracted CC, if test failed	
00002CCC	00002D3C			2234+	DC	CL8' VISTR'		instruction name	
00002CD0	00002D4C			2235+	DC	A(RE43)		address of v1 result	
00002CD4	00000010			2236+	DC	A(RE43+16)		address of v2 source	
00002CD8	00002D2C			2237+	DC	A(RE43+32)		address of v3 source	
00002CE0	00000000 00000000			2238+	DC	A(16)		result length	
00002CE8	00000000 00000000			2239+REA43	DC	A(RE43)		result address	
00002CF0	00000000 00000000			2240+	DS	FD		gap	
00002CF8	00000000 00000000			2241+V1043	DS	XL16		V1 output	
00002D00				2242+	DS	FD		gap	
00002D00	4110 8EF8			2243+*					
00002D04	E751 0000 0806		000010F8	2244+X43	DS	0F			
00002D0A	E310 5024 0014		00000000	2245+	LA	R1, V1FUDGE		load v21 fudge	
00002D10	E761 0000 0806		00000024	2246+	VL	v21, 0(R1)			
00002D16	E756 0010 0C5C		00000000	2247+	LGF	R1, V2ADDR		load v2 source	
00002D1C	B98D 0020			2248+	VL	v22, 0(R1)		use v21 to test decoder	
00002D20	5020 500C		0000000C	2249+	VISTR	V21, V22, 0, 1		test instruction	
00002D24	E750 5040 080E		00002CE8	2250+	EPSW	R2, R0		extract psw	
00002D2A	07FB			2251+	ST	R2, CCPSW		to save CC	
00002D2C				2252+	VST	V21, V1043		save v1 output	
00002D2C				2253+	BR	R11		return	
00002D2C				2254+RE43	DC	0F		V1 for this test	
00002D2C	01020304 05060708			2255+	DROP	R5			
00002D34	00000000 00000000			2256	DC	XL16' 01020304 05060708 00000000 00000000'		v1	
00002D3C	01020304 05060708			2257	DC	XL16' 01020304 05060708 00A0B000 0D0E0F10'		v2	
00002D44	00A0B000 0D0E0F10								
00002D50				2258					
00002D50		00002D50		2259	VRR_A	VISTR, 0, 1, 0			
00002D50	00002DA8			2260+	DS	0FD			
				2261+	USING	*, R5		base for test data and test routine	
				2262+T44	DC	A(X44)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002D54	002C			2263+	DC	H' 44'		test number	
00002D56	00			2264+	DC	X' 00'			
00002D57	00			2265+	DC	HL1' 0'		M3 used	
00002D58	01			2266+	DC	HL1' 1'		M5 used	
00002D59	00			2267+	DC	HL1' 0'		CC	
00002D5A	07			2268+	DC	HL1' 7'		CC failed mask	
00002D5C	00000000	00000000		2269+	DS	2F		extracted PSW after test (has CC)	
00002D64	FF			2270+	DC	X' FF'		extracted CC, if test failed	
00002D65	E5C9E2E3	D9404040		2271+	DC	CL8' VISTR'		instruction name	
00002D70	00002DD4			2272+	DC	A(RE44)		address of v1 result	
00002D74	00002DE4			2273+	DC	A(RE44+16)		address of v2 source	
00002D78	00002DF4			2274+	DC	A(RE44+32)		address of v3 source	
00002D7C	00000010			2275+	DC	A(16)		result length	
00002D80	00002DD4			2276+REA44	DC	A(RE44)		result address	
00002D88	00000000	00000000		2277+	DS	FD		gap	
00002D90	00000000	00000000		2278+V1044	DS	XL16		V1 output	
00002D98	00000000	00000000							
00002DA0	00000000	00000000		2279+	DS	FD		gap	
				2280+*					
00002DA8				2281+X44	DS	0F			
00002DA8	4110 8EF8		000010F8	2282+	LA	R1, V1FUDGE		load v21 fudge	
00002DAC	E751 0000 0806		00000000	2283+	VL	v21, 0(R1)			
00002DB2	E310 5024 0014		00000024	2284+	LGF	R1, V2ADDR		load v2 source	
00002DB8	E761 0000 0806		00000000	2285+	VL	v22, 0(R1)		use v21 to test decoder	
00002DBE	E756 0010 0C5C			2286+	VISTR	V21, V22, 0, 1		test instruction	
00002DC4	B98D 0020			2287+	EPSW	R2, R0		extract psw	
00002DC8	5020 500C		0000000C	2288+	ST	R2, CCPSW		to save CC	
00002DCC	E750 5040 080E		00002D90	2289+	VST	V21, V1044		save v1 output	
00002DD2	07FB			2290+	BR	R11		return	
00002DD4				2291+RE44	DC	0F		V1 for this test	
00002DD4				2292+	DROP	R5			
00002DD4	01020304 05060708			2293	DC	XL16' 01020304 05060708 00000000 00000000'		v1	
00002DDC	00000000 00000000								
00002DE4	01020304 05060708			2294	DC	XL16' 01020304 05060708 000A000C 0D0E0F10'		v2	
00002DEC	000A000C 0D0E0F10								
				2295					
00002DF8				2296	VRR_A	VISTR, 0, 1, 0			
00002DF8		00002DF8		2297+	DS	0FD			
00002DF8	00002E50			2298+	USING	*, R5		base for test data and test routine	
00002DFC	002D			2299+T45	DC	A(X45)		address of test routine	
00002DFE	00			2300+	DC	H' 45'		test number	
00002DFE	00			2301+	DC	X' 00'			
00002DFE	00			2302+	DC	HL1' 0'		M3 used	
00002E00	01			2303+	DC	HL1' 1'		M5 used	
00002E01	00			2304+	DC	HL1' 0'		CC	
00002E02	07			2305+	DC	HL1' 7'		CC failed mask	
00002E04	00000000 00000000			2306+	DS	2F		extracted PSW after test (has CC)	
00002E0C	FF			2307+	DC	X' FF'		extracted CC, if test failed	
00002E0D	E5C9E2E3	D9404040		2308+	DC	CL8' VISTR'		instruction name	
00002E18	00002E7C			2309+	DC	A(RE45)		address of v1 result	
00002E1C	00002E8C			2310+	DC	A(RE45+16)		address of v2 source	
00002E20	00002E9C			2311+	DC	A(RE45+32)		address of v3 source	
00002E24	00000010			2312+	DC	A(16)		result length	
00002E28	00002E7C			2313+REA45	DC	A(RE45)		result address	
00002E30	00000000 00000000			2314+	DS	FD		gap	
00002E38	00000000 00000000			2315+V1045	DS	XL16		V1 output	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00002F2C	00000000	00000000							
00002F34	01020304	00060708		2368	DC	XL16'	01020304 00060708 000A0B0C 0D0E0F10'	v2	
00002F3C	000A0B0C	0D0E0F10							
				2369					
				2370	VRR_A	VISTR, 0, 1, 0			
00002F48				2371+	DS	0FD			
00002F48		00002F48		2372+	USING	*, R5	base for test data and test routine		
00002F48	00002FA0			2373+T47	DC	A(X47)	address of test routine		
00002F4C	002F			2374+	DC	H' 47'	test number		
00002F4E	00			2375+	DC	X' 00'			
00002F4F	00			2376+	DC	HL1' 0'	MB used		
00002F50	01			2377+	DC	HL1' 1'	M5 used		
00002F51	00			2378+	DC	HL1' 0'	CC		
00002F52	07			2379+	DC	HL1' 7'	CC failed mask		
00002F54	00000000	00000000		2380+	DS	2F	extracted PSW after test (has CC)		
00002F5C	FF			2381+	DC	X' FF'	extracted CC, if test failed		
00002F5D	E5C9E2E3	D9404040		2382+	DC	CL8' VISTR'	instruction name		
00002F68	00002FCC			2383+	DC	A(RE47)	address of v1 result		
00002F6C	00002FDC			2384+	DC	A(RE47+16)	address of v2 source		
00002F70	00002FEC			2385+	DC	A(RE47+32)	address of v3 source		
00002F74	00000010			2386+	DC	A(16)	result length		
00002F78	00002FCC			2387+REA47	DC	A(RE47)	result address		
00002F80	00000000	00000000		2388+	DS	FD	gap		
00002F88	00000000	00000000		2389+V1047	DS	XL16	V1 output		
00002F90	00000000	00000000							
00002F98	00000000	00000000		2390+	DS	FD	gap		
				2391+*					
00002FA0				2392+X47	DS	0F			
00002FA0	4110 8EF8		000010F8	2393+	LA	R1, V1FUDGE	load v21 fudge		
00002FA4	E751 0000 0806		00000000	2394+	VL	v21, 0(R1)			
00002FAA	E310 5024 0014		00000024	2395+	LGF	R1, V2ADDR	load v2 source		
00002FB0	E761 0000 0806		00000000	2396+	VL	v22, 0(R1)	use v21 to test decoder		
00002FB6	E756 0010 0C5C			2397+	VISTR	V21, V22, 0, 1	test instruction		
00002FBC	B98D 0020			2398+	EPSW	R2, R0	extract psw		
00002FC0	5020 500C		0000000C	2399+	ST	R2, CCPSW	to save CC		
00002FC4	E750 5040 080E		00002F88	2400+	VST	V21, V1047	save v1 output		
00002FCA	07FB			2401+	BR	R11	return		
00002FCC				2402+RE47	DC	0F	V1 for this test		
00002FCC				2403+	DROP	R5			
00002FCC	01020304	00000000		2404	DC	XL16' 01020304 00000000 00000000 00000000'	v1		
00002FD4	00000000	00000000							
00002FDC	01020304	00060700		2405	DC	XL16' 01020304 00060700 090A0B0C 0D0E0F10'	v2		
00002FE4	090A0B0C	0D0E0F10							
				2406					
				2407	VRR_A	VISTR, 0, 1, 0			
00002FF0				2408+	DS	0FD			
00002FF0		00002FF0		2409+	USING	*, R5	base for test data and test routine		
00002FF0	00003048			2410+T48	DC	A(X48)	address of test routine		
00002FF4	0030			2411+	DC	H' 48'	test number		
00002FF6	00			2412+	DC	X' 00'			
00002FF7	00			2413+	DC	HL1' 0'	MB used		
00002FF8	01			2414+	DC	HL1' 1'	M5 used		
00002FF9	00			2415+	DC	HL1' 0'	CC		
00002FFA	07			2416+	DC	HL1' 7'	CC failed mask		
00002FFC	00000000	00000000		2417+	DS	2F	extracted PSW after test (has CC)		
00003004	FF			2418+	DC	X' FF'	extracted CC, if test failed		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003005	E5C9E2E3 D9404040			2419+	DC	CL8' VISTR'	instruction name
00003010	00003074			2420+	DC	A(RE48)	address of v1 result
00003014	00003084			2421+	DC	A(RE48+16)	address of v2 source
00003018	00003094			2422+	DC	A(RE48+32)	address of v3 source
0000301C	00000010			2423+	DC	A(16)	result length
00003020	00003074			2424+REA48	DC	A(RE48)	result address
00003028	00000000 00000000			2425+	DS	FD	gap
00003030	00000000 00000000			2426+V1048	DS	XL16	V1 output
00003038	00000000 00000000						
00003040	00000000 00000000			2427+	DS	FD	gap
				2428+*			
00003048				2429+X48	DS	OF	
00003048	4110 8EF8		000010F8	2430+	LA	R1, V1FUDGE	load v21 fudge
0000304C	E751 0000 0806		00000000	2431+	VL	v21, 0(R1)	
00003052	E310 5024 0014		00000024	2432+	LGF	R1, V2ADDR	load v2 source
00003058	E761 0000 0806		00000000	2433+	VL	v22, 0(R1)	use v21 to test decoder
0000305E	E756 0010 0C5C			2434+	VISTR	V21, V22, 0, 1	test instruction
00003064	B98D 0020			2435+	EPSW	R2, R0	extract psw
00003068	5020 500C		0000000C	2436+	ST	R2, CCPSW	to save CC
0000306C	E750 5040 080E		00003030	2437+	VST	V21, V1048	save v1 output
00003072	07FB			2438+	BR	R11	return
00003074				2439+RE48	DC	OF	V1 for this test
00003074				2440+	DROP	R5	
00003074	01020304 00000000			2441	DC	XL16' 01020304 00000000 00000000 00000000'	v1
0000307C	00000000 00000000						
00003084	01020304 00060008			2442	DC	XL16' 01020304 00060008 090A0B0C 0D0E0F10'	v2
0000308C	090A0B0C 0D0E0F10						
				2443			
				2444	VRR_A	VISTR, 0, 1, 0	
00003098				2445+	DS	OFD	
00003098		00003098		2446+	USING	*, R5	base for test data and test routine
00003098	000030F0			2447+T49	DC	A(X49)	address of test routine
0000309C	0031			2448+	DC	H' 49'	test number
0000309E	00			2449+	DC	X' 00'	
0000309F	00			2450+	DC	HL1' 0'	M3 used
000030A0	01			2451+	DC	HL1' 1'	M5 used
000030A1	00			2452+	DC	HL1' 0'	CC
000030A2	07			2453+	DC	HL1' 7'	CC failed mask
000030A4	00000000 00000000			2454+	DS	2F	extracted PSW after test (has CC)
000030AC	FF			2455+	DC	X' FF'	extracted CC, if test failed
000030AD	E5C9E2E3 D9404040			2456+	DC	CL8' VISTR'	instruction name
000030B8	0000311C			2457+	DC	A(RE49)	address of v1 result
000030BC	0000312C			2458+	DC	A(RE49+16)	address of v2 source
000030C0	0000313C			2459+	DC	A(RE49+32)	address of v3 source
000030C4	00000010			2460+	DC	A(16)	result length
000030C8	0000311C			2461+REA49	DC	A(RE49)	result address
000030D0	00000000 00000000			2462+	DS	FD	gap
000030D8	00000000 00000000			2463+V1049	DS	XL16	V1 output
000030E0	00000000 00000000						
000030E8	00000000 00000000			2464+	DS	FD	gap
				2465+*			
000030F0				2466+X49	DS	OF	
000030F0	4110 8EF8		000010F8	2467+	LA	R1, V1FUDGE	load v21 fudge
000030F4	E751 0000 0806		00000000	2468+	VL	v21, 0(R1)	
000030FA	E310 5024 0014		00000024	2469+	LGF	R1, V2ADDR	load v2 source
00003100	E761 0000 0806		00000000	2470+	VL	v22, 0(R1)	use v21 to test decoder

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003106	E756 0010 0C5C			2471+	VISTR	V21, V22, 0, 1		test instruction	
0000310C	B98D 0020			2472+	EPSW	R2, R0		extract psw	
00003110	5020 500C		0000000C	2473+	ST	R2, CCPSW		to save CC	
00003114	E750 5040 080E		000030D8	2474+	VST	V21, V1049		save v1 output	
0000311A	07FB			2475+	BR	R11		return	
0000311C				2476+RE49	DC	0F		V1 for this test	
0000311C				2477+	DROP	R5			
0000311C	01020304 00000000			2478	DC	XL16' 01020304 00000000 00000000 00000000'		v1	
00003124	00000000 00000000								
0000312C	01020304 00000708			2479	DC	XL16' 01020304 00000708 090A0B0C 0D0E0F10'		v2	
00003134	090A0B0C 0D0E0F10								
00003140				2480					
00003140				2481	VRR_A	VISTR, 0, 1, 0			
00003140		00003140		2482+	DS	0FD			
00003140	00003198			2483+	USING	*, R5		base for test data and test routine	
00003144	0032			2484+T50	DC	A(X50)		address of test routine	
00003146	00			2485+	DC	H' 50'		test number	
00003147	00			2486+	DC	X' 00'			
00003148	01			2487+	DC	HL1' 0'		MB used	
00003148	01			2488+	DC	HL1' 1'		M5 used	
00003149	00			2489+	DC	HL1' 0'		CC	
0000314A	07			2490+	DC	HL1' 7'		CC failed mask	
0000314C	00000000 00000000			2491+	DS	2F		extracted PSW after test (has CC)	
00003154	FF			2492+	DC	X' FF'		extracted CC, if test failed	
00003155	E5C9E2E3 D9404040			2493+	DC	CL8' VISTR'		instruction name	
00003160	000031C4			2494+	DC	A(RE50)		address of v1 result	
00003164	000031D4			2495+	DC	A(RE50+16)		address of v2 source	
00003168	000031E4			2496+	DC	A(RE50+32)		address of v3 source	
0000316C	00000010			2497+	DC	A(16)		result length	
00003170	000031C4			2498+REA50	DC	A(RE50)		result address	
00003178	00000000 00000000			2499+	DS	FD		gap	
00003180	00000000 00000000			2500+V1050	DS	XL16		V1 output	
00003188	00000000 00000000								
00003190	00000000 00000000			2501+	DS	FD		gap	
00003198				2502+*					
00003198	4110 8EF8		000010F8	2503+X50	DS	0F			
0000319C	E751 0000 0806		00000000	2504+	LA	R1, V1FUDGE		load v21 fudge	
000031A2	E310 5024 0014		00000024	2505+	VL	v21, 0(R1)			
000031A8	E761 0000 0806		00000000	2506+	LGF	R1, V2ADDR		load v2 source	
000031AE	E756 0010 0C5C			2507+	VL	v22, 0(R1)		use v21 to test decoder	
000031B4	B98D 0020			2508+	VISTR	V21, V22, 0, 1		test instruction	
000031B8	5020 500C		0000000C	2509+	EPSW	R2, R0		extract psw	
000031BC	E750 5040 080E		00003180	2510+	ST	R2, CCPSW		to save CC	
000031C2	07FB			2511+	VST	V21, V1050		save v1 output	
000031C4				2512+	BR	R11		return	
000031C4				2513+RE50	DC	0F		V1 for this test	
000031C4				2514+	DROP	R5			
000031C4	01000000 00000000			2515	DC	XL16' 01000000 00000000 00000000 00000000'		v1	
000031CC	00000000 00000000								
000031D4	01000304 00060708			2516	DC	XL16' 01000304 00060708 090A0B0C 0D0E0F10'		v2	
000031DC	090A0B0C 0D0E0F10								
000031E8				2517					
000031E8				2518	VRR_A	VISTR, 0, 1, 0			
000031E8		000031E8		2519+	DS	0FD			
000031E8	00003240			2520+	USING	*, R5		base for test data and test routine	
				2521+T51	DC	A(X51)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000031EC	0033			2522+	DC	H' 51'	test number		
000031EE	00			2523+	DC	X' 00'			
000031EF	00			2524+	DC	HL1' 0'	MB used		
000031F0	01			2525+	DC	HL1' 1'	M5 used		
000031F1	00			2526+	DC	HL1' 0'	CC		
000031F2	07			2527+	DC	HL1' 7'	CC failed mask		
000031F4	00000000 00000000			2528+	DS	2F	extracted PSW after test (has CC)		
000031FC	FF			2529+	DC	X' FF'	extracted CC, if test failed		
000031FD	E5C9E2E3 D9404040			2530+	DC	CL8' VISTR'	instruction name		
00003208	0000326C			2531+	DC	A(RE51)	address of v1 result		
0000320C	0000327C			2532+	DC	A(RE51+16)	address of v2 source		
00003210	0000328C			2533+	DC	A(RE51+32)	address of v3 source		
00003214	00000010			2534+	DC	A(16)	result length		
00003218	0000326C			2535+REA51	DC	A(RE51)	result address		
00003220	00000000 00000000			2536+	DS	FD	gap		
00003228	00000000 00000000			2537+V1051	DS	XL16	V1 output		
00003230	00000000 00000000								
00003238	00000000 00000000			2538+	DS	FD	gap		
				2539+*					
00003240				2540+X51	DS	0F			
00003240	4110 8EF8		000010F8	2541+	LA	R1, V1FUDGE	load v21 fudge		
00003244	E751 0000 0806		00000000	2542+	VL	v21, 0(R1)			
0000324A	E310 5024 0014		00000024	2543+	LGF	R1, V2ADDR	load v2 source		
00003250	E761 0000 0806		00000000	2544+	VL	v22, 0(R1)	use v21 to test decoder		
00003256	E756 0010 0C5C			2545+	VISTR	V21, V22, 0, 1	test instruction		
0000325C	B98D 0020			2546+	EPSW	R2, R0	extract psw		
00003260	5020 500C		0000000C	2547+	ST	R2, CCPSW	to save CC		
00003264	E750 5040 080E		00003228	2548+	VST	V21, V1051	save v1 output		
0000326A	07FB			2549+	BR	R11	return		
0000326C				2550+RE51	DC	0F	V1 for this test		
0000326C				2551+	DROP	R5			
0000326C	01000000 00000000			2552	DC	XL16' 01000000 00000000 00000000 00000000'	v1		
00003274	00000000 00000000								
0000327C	01000300 05060708			2553	DC	XL16' 01000300 05060708 090A0B0C 0D0E0F10'	v2		
00003284	090A0B0C 0D0E0F10								
				2554					
00003290				2555	VRR_A	VISTR, 0, 1, 0			
00003290		00003290		2556+	DS	0FD			
00003290	000032E8			2557+	USING	*, R5	base for test data and test routine		
00003294	0034			2558+T52	DC	A(X52)	address of test routine		
00003296	00			2559+	DC	H' 52'	test number		
00003296	00			2560+	DC	X' 00'			
00003297	00			2561+	DC	HL1' 0'	MB used		
00003298	01			2562+	DC	HL1' 1'	M5 used		
00003299	00			2563+	DC	HL1' 0'	CC		
0000329A	07			2564+	DC	HL1' 7'	CC failed mask		
0000329C	00000000 00000000			2565+	DS	2F	extracted PSW after test (has CC)		
000032A4	FF			2566+	DC	X' FF'	extracted CC, if test failed		
000032A5	E5C9E2E3 D9404040			2567+	DC	CL8' VISTR'	instruction name		
000032B0	00003314			2568+	DC	A(RE52)	address of v1 result		
000032B4	00003324			2569+	DC	A(RE52+16)	address of v2 source		
000032B8	00003334			2570+	DC	A(RE52+32)	address of v3 source		
000032BC	00000010			2571+	DC	A(16)	result length		
000032C0	00003314			2572+REA52	DC	A(RE52)	result address		
000032C8	00000000 00000000			2573+	DS	FD	gap		
000032D0	00000000 00000000			2574+V1052	DS	XL16	V1 output		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000032D8	00000000 00000000								
000032E0	00000000 00000000			2575+	DS	FD	gap		
				2576+*					
000032E8				2577+X52	DS	OF			
000032E8	4110 8EF8		000010F8	2578+	LA	R1, V1FUDGE	load v21 fudge		
000032EC	E751 0000 0806		00000000	2579+	VL	v21, 0(R1)			
000032F2	E310 5024 0014		00000024	2580+	LGF	R1, V2ADDR	load v2 source		
000032F8	E761 0000 0806		00000000	2581+	VL	v22, 0(R1)	use v21 to test decoder		
000032FE	E756 0010 0C5C			2582+	VISTR	V21, V22, 0, 1	test instruction		
00003304	B98D 0020			2583+	EPSW	R2, R0	extract psw		
00003308	5020 500C		0000000C	2584+	ST	R2, CCPSW	to save CC		
0000330C	E750 5040 080E		000032D0	2585+	VST	V21, V1052	save v1 output		
00003312	07FB			2586+	BR	R11	return		
00003314				2587+RE52	DC	OF	V1 for this test		
00003314				2588+	DROP	R5			
00003314	01000000 00000000			2589	DC	XL16' 01000000 00000000 00000000 00000000'	v1		
0000331C	00000000 00000000								
00003324	01000004 05060708			2590	DC	XL16' 01000004 05060708 090A0B0C 0D0E0F10'	v2		
0000332C	090A0B0C 0D0E0F10								
				2591					
				2592	VRR_A	VISTR, 0, 1, 0			
00003338				2593+	DS	OFD			
00003338		00003338		2594+	USING	*, R5	base for test data and test routine		
00003338	00003390			2595+T53	DC	A(X53)	address of test routine		
0000333C	0035			2596+	DC	H' 53'	test number		
0000333E	00			2597+	DC	X' 00'			
0000333F	00			2598+	DC	HL1' 0'	M3 used		
00003340	01			2599+	DC	HL1' 1'	M5 used		
00003341	00			2600+	DC	HL1' 0'	CC		
00003342	07			2601+	DC	HL1' 7'	CC failed mask		
00003344	00000000 00000000			2602+	DS	2F	extracted PSW after test (has CC)		
0000334C	FF			2603+	DC	X' FF'	extracted CC, if test failed		
0000334D	E5C9E2E3 D9404040			2604+	DC	CL8' VISTR'	instruction name		
00003358	000033BC			2605+	DC	A(RE53)	address of v1 result		
0000335C	000033CC			2606+	DC	A(RE53+16)	address of v2 source		
00003360	000033DC			2607+	DC	A(RE53+32)	address of v3 source		
00003364	00000010			2608+	DC	A(16)	result length		
00003368	000033BC			2609+REA53	DC	A(RE53)	result address		
00003370	00000000 00000000			2610+	DS	FD	gap		
00003378	00000000 00000000			2611+V1053	DS	XL16	V1 output		
00003380	00000000 00000000								
00003388	00000000 00000000			2612+	DS	FD	gap		
				2613+*					
00003390				2614+X53	DS	OF			
00003390	4110 8EF8		000010F8	2615+	LA	R1, V1FUDGE	load v21 fudge		
00003394	E751 0000 0806		00000000	2616+	VL	v21, 0(R1)			
0000339A	E310 5024 0014		00000024	2617+	LGF	R1, V2ADDR	load v2 source		
000033A0	E761 0000 0806		00000000	2618+	VL	v22, 0(R1)	use v21 to test decoder		
000033A6	E756 0010 0C5C			2619+	VISTR	V21, V22, 0, 1	test instruction		
000033AC	B98D 0020			2620+	EPSW	R2, R0	extract psw		
000033B0	5020 500C		0000000C	2621+	ST	R2, CCPSW	to save CC		
000033B4	E750 5040 080E		00003378	2622+	VST	V21, V1053	save v1 output		
000033BA	07FB			2623+	BR	R11	return		
000033BC				2624+RE53	DC	OF	V1 for this test		
000033BC				2625+	DROP	R5			
000033BC	00000000 00000000			2626	DC	XL16' 00000000 00000000 00000000 00000000'	v1		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				2630 *halfword	
				2631	VRR_A VISTR, 1, 1, 0
000033E0				2632+	DS OFD
000033E0		000033E0		2633+	USING *, R5
000033E0	00003438			2634+T54	DC A(X54)
000033E4	0036			2635+	DC H' 54'
000033E6	00			2636+	DC X' 00'
000033E7	01			2637+	DC HL1' 1'
000033E8	01			2638+	DC HL1' 1'
000033E9	00			2639+	DC HL1' 0'
000033EA	07			2640+	DC HL1' 7'
000033EC	00000000 00000000			2641+	DS 2F
000033F4	FF			2642+	DC X' FF'
000033F5	E5C9E2E3 D9404040			2643+	DC CL8' VISTR'
00003400	00003464			2644+	DC A(RE54)
00003404	00003474			2645+	DC A(RE54+16)
00003408	00003484			2646+	DC A(RE54+32)
0000340C	00000010			2647+	DC A(16)
00003410	00003464			2648+REA54	DC A(RE54)
00003418	00000000 00000000			2649+	DS FD
00003420	00000000 00000000			2650+V1054	DS XL16
00003428	00000000 00000000				
00003430	00000000 00000000			2651+	DS FD
				2652+*	
00003438				2653+X54	DS OF
00003438	4110 8EF8		000010F8	2654+	LA R1, V1FUDGE
0000343C	E751 0000 0806		00000000	2655+	VL v21, 0(R1)
00003442	E310 5024 0014		00000024	2656+	LGF R1, V2ADDR
00003448	E761 0000 0806		00000000	2657+	VL v22, 0(R1)
0000344E	E756 0010 1C5C			2658+	VISTR V21, V22, 1, 1
00003454	B98D 0020			2659+	EPSW R2, R0
00003458	5020 500C		0000000C	2660+	ST R2, CCPSW
0000345C	E750 5040 080E		00003420	2661+	VST V21, V1054
00003462	07FB			2662+	BR R11
00003464				2663+RE54	DC OF
00003464				2664+	DROP R5
00003464	88888888 77777777			2665	DC XL16' 88888888 77777777 00000000 00000000'
0000346C	00000000 00000000				
00003474	88888888 77777777			2666	DC XL16' 88888888 77777777 00006666 55550000'
0000347C	00006666 55550000				
				2667	
				2668	VRR_A VISTR, 1, 1, 0
00003488				2669+	DS OFD
00003488		00003488		2670+	USING *, R5
00003488	000034E0			2671+T55	DC A(X55)
0000348C	0037			2672+	DC H' 55'
0000348E	00			2673+	DC X' 00'
0000348F	01			2674+	DC HL1' 1'
00003490	01			2675+	DC HL1' 1'
00003491	00			2676+	DC HL1' 0'
00003492	07			2677+	DC HL1' 7'
00003494	00000000 00000000			2678+	DS 2F
0000349C	FF			2679+	DC X' FF'
0000349D	E5C9E2E3 D9404040			2680+	DC CL8' VISTR'
000034A8	0000350C			2681+	DC A(RE55)
000034AC	0000351C			2682+	DC A(RE55+16)

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000034B0	0000352C			2683+	DC	A(RE55+32)	address of v3 source		
000034B4	00000010			2684+	DC	A(16)	result length		
000034B8	0000350C			2685+REA55	DC	A(RE55)	result address		
000034C0	00000000 00000000			2686+	DS	FD	gap		
000034C8	00000000 00000000			2687+V1055	DS	XL16	V1 output		
000034D0	00000000 00000000								
000034D8	00000000 00000000			2688+	DS	FD	gap		
				2689+*					
000034E0				2690+X55	DS	OF			
000034E0	4110 8EF8		000010F8	2691+	LA	R1, V1FUDGE	load v21 fudge		
000034E4	E751 0000 0806		00000000	2692+	VL	v21, 0(R1)			
000034EA	E310 5024 0014		00000024	2693+	LGF	R1, V2ADDR	load v2 source		
000034F0	E761 0000 0806		00000000	2694+	VL	v22, 0(R1)	use v21 to test decoder		
000034F6	E756 0010 1C5C			2695+	VISTR	V21, V22, 1, 1	test instruction		
000034FC	B98D 0020			2696+	EPSW	R2, R0	extract psw		
00003500	5020 500C		0000000C	2697+	ST	R2, CCPSW	to save CC		
00003504	E750 5040 080E		000034C8	2698+	VST	V21, V1055	save v1 output		
0000350A	07FB			2699+	BR	R11	return		
0000350C				2700+RE55	DC	OF	V1 for this test		
0000350C				2701+	DROP	R5			
0000350C	88888888 77777777			2702	DC	XL16' 88888888 77777777 00000000 00000000'	v1		
00003514	00000000 00000000								
0000351C	88888888 77777777			2703	DC	XL16' 88888888 77777777 00006666 00005555'	v2		
00003524	00006666 00005555								
				2704					
				2705	VRR_A	VISTR, 1, 1, 0			
00003530				2706+	DS	OFD			
00003530		00003530		2707+	USING	*, R5	base for test data and test routine		
00003530	00003588			2708+T56	DC	A(X56)	address of test routine		
00003534	0038			2709+	DC	H' 56'	test number		
00003536	00			2710+	DC	X' 00'			
00003537	01			2711+	DC	HL1' 1'	M3 used		
00003538	01			2712+	DC	HL1' 1'	M5 used		
00003539	00			2713+	DC	HL1' 0'	CC		
0000353A	07			2714+	DC	HL1' 7'	CC failed mask		
0000353C	00000000 00000000			2715+	DS	2F	extracted PSW after test (has CC)		
00003544	FF			2716+	DC	X' FF'	extracted CC, if test failed		
00003545	E5C9E2E3 D9404040			2717+	DC	CL8' VISTR'	instruction name		
00003550	000035B4			2718+	DC	A(RE56)	address of v1 result		
00003554	000035C4			2719+	DC	A(RE56+16)	address of v2 source		
00003558	000035D4			2720+	DC	A(RE56+32)	address of v3 source		
0000355C	00000010			2721+	DC	A(16)	result length		
00003560	000035B4			2722+REA56	DC	A(RE56)	result address		
00003568	00000000 00000000			2723+	DS	FD	gap		
00003570	00000000 00000000			2724+V1056	DS	XL16	V1 output		
00003578	00000000 00000000								
00003580	00000000 00000000			2725+	DS	FD	gap		
				2726+*					
00003588				2727+X56	DS	OF			
00003588	4110 8EF8		000010F8	2728+	LA	R1, V1FUDGE	load v21 fudge		
0000358C	E751 0000 0806		00000000	2729+	VL	v21, 0(R1)			
00003592	E310 5024 0014		00000024	2730+	LGF	R1, V2ADDR	load v2 source		
00003598	E761 0000 0806		00000000	2731+	VL	v22, 0(R1)	use v21 to test decoder		
0000359E	E756 0010 1C5C			2732+	VISTR	V21, V22, 1, 1	test instruction		
000035A4	B98D 0020			2733+	EPSW	R2, R0	extract psw		
000035A8	5020 500C		0000000C	2734+	ST	R2, CCPSW	to save CC		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
000035AC	E750 5040 080E		00003570	2735+	VST	V21, V1056	save v1 output		
000035B2	07FB			2736+	BR	R11	return		
000035B4				2737+RE56	DC	0F	V1 for this test		
000035B4				2738+	DROP	R5			
000035B4	88888888 77777777			2739	DC	XL16' 88888888 77777777 00000000 00000000'	v1		
000035BC	00000000 00000000								
000035C4	88888888 77777777			2740	DC	XL16' 88888888 77777777 00000000 55555555'	v2		
000035CC	00000000 55555555								
				2741					
				2742	VRR_A	VISTR, 1, 1, 0			
000035D8				2743+	DS	0FD			
000035D8		000035D8		2744+	USING	*, R5	base for test data and test routine		
000035D8	00003630			2745+T57	DC	A(X57)	address of test routine		
000035DC	0039			2746+	DC	H' 57'	test number		
000035DE	00			2747+	DC	X' 00'			
000035DF	01			2748+	DC	HL1' 1'	MB used		
000035E0	01			2749+	DC	HL1' 1'	M5 used		
000035E1	00			2750+	DC	HL1' 0'	CC		
000035E2	07			2751+	DC	HL1' 7'	CC failed mask		
000035E4	00000000 00000000			2752+	DS	2F	extracted PSW after test (has CC)		
000035EC	FF			2753+	DC	X' FF'	extracted CC, if test failed		
000035ED	E5C9E2E3 D9404040			2754+	DC	CL8' VISTR'	instruction name		
000035F8	0000365C			2755+	DC	A(RE57)	address of v1 result		
000035FC	0000366C			2756+	DC	A(RE57+16)	address of v2 source		
00003600	0000367C			2757+	DC	A(RE57+32)	address of v3 source		
00003604	00000010			2758+	DC	A(16)	result length		
00003608	0000365C			2759+REA57	DC	A(RE57)	result address		
00003610	00000000 00000000			2760+	DS	FD	gap		
00003618	00000000 00000000			2761+V1057	DS	XL16	V1 output		
00003620	00000000 00000000								
00003628	00000000 00000000			2762+	DS	FD	gap		
				2763+*					
00003630				2764+X57	DS	0F			
00003630	4110 8EF8		000010F8	2765+	LA	R1, V1FUDGE	load v21 fudge		
00003634	E751 0000 0806		00000000	2766+	VL	v21, 0(R1)			
0000363A	E310 5024 0014		00000024	2767+	LGF	R1, V2ADDR	load v2 source		
00003640	E761 0000 0806		00000000	2768+	VL	v22, 0(R1)	use v21 to test decoder		
00003646	E756 0010 1C5C			2769+	VISTR	V21, V22, 1, 1	test instruction		
0000364C	B98D 0020			2770+	EPSW	R2, R0	extract psw		
00003650	5020 500C		0000000C	2771+	ST	R2, CCPSW	to save CC		
00003654	E750 5040 080E		00003618	2772+	VST	V21, V1057	save v1 output		
0000365A	07FB			2773+	BR	R11	return		
0000365C				2774+RE57	DC	0F	V1 for this test		
0000365C				2775+	DROP	R5			
0000365C	88888888 00000000			2776	DC	XL16' 88888888 00000000 00000000 00000000'	v1		
00003664	00000000 00000000								
0000366C	88888888 00007777			2777	DC	XL16' 88888888 00007777 00006666 55555555'	v2		
00003674	00006666 55555555								
				2778					
				2779	VRR_A	VISTR, 1, 1, 0			
00003680				2780+	DS	0FD			
00003680		00003680		2781+	USING	*, R5	base for test data and test routine		
00003680	000036D8			2782+T58	DC	A(X58)	address of test routine		
00003684	003A			2783+	DC	H' 58'	test number		
00003686	00			2784+	DC	X' 00'			
00003687	01			2785+	DC	HL1' 1'	MB used		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
00003688	01			2786+	DC	HL1' 1' M5 used
00003689	00			2787+	DC	HL1' 0' CC
0000368A	07			2788+	DC	HL1' 7' CC failed mask
0000368C	00000000 00000000			2789+	DS	2F extracted PSW after test (has CC)
00003694	FF			2790+	DC	X' FF' extracted CC, if test failed
00003695	E5C9E2E3 D9404040			2791+	DC	CL8' VISTR' instruction name
000036A0	00003704			2792+	DC	A(RE58) address of v1 result
000036A4	00003714			2793+	DC	A(RE58+16) address of v2 source
000036A8	00003724			2794+	DC	A(RE58+32) address of v3 source
000036AC	00000010			2795+	DC	A(16) result length
000036B0	00003704			2796+REA58	DC	A(RE58) result address
000036B8	00000000 00000000			2797+	DS	FD gap
000036C0	00000000 00000000			2798+V1058	DS	XL16 V1 output
000036C8	00000000 00000000					
000036D0	00000000 00000000			2799+	DS	FD gap
				2800+*		
000036D8				2801+X58	DS	0F
000036D8	4110 8EF8		000010F8	2802+	LA	R1, V1FUDGE load v21 fudge
000036DC	E751 0000 0806		00000000	2803+	VL	v21, 0(R1)
000036E2	E310 5024 0014		00000024	2804+	LGF	R1, V2ADDR load v2 source
000036E8	E761 0000 0806		00000000	2805+	VL	v22, 0(R1) use v21 to test decoder
000036EE	E756 0010 1C5C			2806+	VISTR	V21, V22, 1, 1 test instruction
000036F4	B98D 0020			2807+	EPSW	R2, R0 extract psw
000036F8	5020 500C		0000000C	2808+	ST	R2, CCPSW to save CC
000036FC	E750 5040 080E		000036C0	2809+	VST	V21, V1058 save v1 output
00003702	07FB			2810+	BR	R11 return
00003704				2811+RE58	DC	0F V1 for this test
00003704				2812+	DROP	R5
00003704	88888888 00000000			2813	DC	XL16' 88888888 00000000 00000000 00000000' v1
0000370C	00000000 00000000					
00003714	88888888 00000000			2814	DC	XL16' 88888888 00000000 66666666 55555555' v2
0000371C	66666666 55555555					
				2815		
00003728				2816	VRR_A	VISTR, 1, 1, 0
00003728		00003728		2817+	DS	0FD
00003728	00003780			2818+	USING	*, R5 base for test data and test routine
0000372C	003B			2819+T59	DC	A(X59) address of test routine
0000372E	00			2820+	DC	H' 59' test number
0000372F	01			2821+	DC	X' 00'
00003730	01			2822+	DC	HL1' 1' M3 used
00003731	00			2823+	DC	HL1' 1' M5 used
00003732	07			2824+	DC	HL1' 0' CC
00003734	00000000 00000000			2825+	DC	HL1' 7' CC failed mask
0000373C	FF			2826+	DS	2F extracted PSW after test (has CC)
0000373D	E5C9E2E3 D9404040			2827+	DC	X' FF' extracted CC, if test failed
00003748	000037AC			2828+	DC	CL8' VISTR' instruction name
0000374C	000037BC			2829+	DC	A(RE59) address of v1 result
00003750	000037CC			2830+	DC	A(RE59+16) address of v2 source
00003754	00000010			2831+	DC	A(RE59+32) address of v3 source
00003758	000037AC			2832+	DC	A(16) result length
00003760	00000000 00000000			2833+REA59	DC	A(RE59) result address
00003768	00000000 00000000			2834+	DS	FD gap
00003770	00000000 00000000			2835+V1059	DS	XL16 V1 output
00003778	00000000 00000000			2836+	DS	FD gap
				2837+*		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003780				2838+X59	DS	OF			
00003780	4110 8EF8		000010F8	2839+	LA	R1, V1FUDGE	load v21 fudge		
00003784	E751 0000 0806		00000000	2840+	VL	v21, 0(R1)			
0000378A	E310 5024 0014		00000024	2841+	LGF	R1, V2ADDR	load v2 source		
00003790	E761 0000 0806		00000000	2842+	VL	v22, 0(R1)	use v21 to test decoder		
00003796	E756 0010 1C5C			2843+	VISTR	V21, V22, 1, 1	test instruction		
0000379C	B98D 0020			2844+	EPSW	R2, R0	extract psw		
000037A0	5020 500C		0000000C	2845+	ST	R2, CCPSW	to save CC		
000037A4	E750 5040 080E		00003768	2846+	VST	V21, V1059	save v1 output		
000037AA	07FB			2847+	BR	R11	return		
000037AC				2848+RE59	DC	OF	V1 for this test		
000037AC				2849+	DROP	R5			
000037AC	88880000 00000000			2850	DC	XL16' 88880000 00000000 00000000 00000000'	v1		
000037B4	00000000 00000000								
000037BC	88880000 00007777			2851	DC	XL16' 88880000 00007777 66666666 55555555'	v2		
000037C4	66666666 55555555								
				2852					
000037D0				2853	VRR_A	VISTR, 1, 1, 0			
000037D0		000037D0		2854+	DS	OFD			
000037D0	00003828			2855+	USING	*, R5	base for test data and test routine		
000037D4	003C			2856+T60	DC	A(X60)	address of test routine		
000037D6	00			2857+	DC	H' 60'	test number		
000037D6	00			2858+	DC	X' 00'			
000037D7	01			2859+	DC	HL1' 1'	M3 used		
000037D8	01			2860+	DC	HL1' 1'	M5 used		
000037D9	00			2861+	DC	HL1' 0'	CC		
000037DA	07			2862+	DC	HL1' 7'	CC failed mask		
000037DC	00000000 00000000			2863+	DS	2F	extracted PSW after test (has CC)		
000037E4	FF			2864+	DC	X' FF'	extracted CC, if test failed		
000037E5	E5C9E2E3 D9404040			2865+	DC	CL8' VISTR'	instruction name		
000037F0	00003854			2866+	DC	A(RE60)	address of v1 result		
000037F4	00003864			2867+	DC	A(RE60+16)	address of v2 source		
000037F8	00003874			2868+	DC	A(RE60+32)	address of v3 source		
000037FC	00000010			2869+	DC	A(16)	result length		
00003800	00003854			2870+REA60	DC	A(RE60)	result address		
00003808	00000000 00000000			2871+	DS	FD	gap		
00003810	00000000 00000000			2872+V1060	DS	XL16	V1 output		
00003818	00000000 00000000								
00003820	00000000 00000000			2873+	DS	FD	gap		
				2874+*					
00003828				2875+X60	DS	OF			
00003828	4110 8EF8		000010F8	2876+	LA	R1, V1FUDGE	load v21 fudge		
0000382C	E751 0000 0806		00000000	2877+	VL	v21, 0(R1)			
00003832	E310 5024 0014		00000024	2878+	LGF	R1, V2ADDR	load v2 source		
00003838	E761 0000 0806		00000000	2879+	VL	v22, 0(R1)	use v21 to test decoder		
0000383E	E756 0010 1C5C			2880+	VISTR	V21, V22, 1, 1	test instruction		
00003844	B98D 0020			2881+	EPSW	R2, R0	extract psw		
00003848	5020 500C		0000000C	2882+	ST	R2, CCPSW	to save CC		
0000384C	E750 5040 080E		00003810	2883+	VST	V21, V1060	save v1 output		
00003852	07FB			2884+	BR	R11	return		
00003854				2885+RE60	DC	OF	V1 for this test		
00003854				2886+	DROP	R5			
00003854	00000000 00000000			2887	DC	XL16' 00000000 00000000 00000000 00000000'	v1		
0000385C	00000000 00000000								
00003864	00000000 77777777			2888	DC	XL16' 00000000 77777777 66666666 55555555'	v2		
0000386C	66666666 55555555								

LOC	OBJECT CODE	ADDR1	ADDR2	STMT		
				2890 *word		
				2891	VRR_A VISTR, 2, 1, 0	
00003878				2892+	DS OFD	
00003878		00003878		2893+	USING *, R5	base for test data and test routine
00003878	000038D0			2894+T61	DC A(X61)	address of test routine
0000387C	003D			2895+	DC H' 61'	test number
0000387E	00			2896+	DC X' 00'	
0000387F	02			2897+	DC HL1' 2'	M3 used
00003880	01			2898+	DC HL1' 1'	M5 used
00003881	00			2899+	DC HL1' 0'	CC
00003882	07			2900+	DC HL1' 7'	CC failed mask
00003884	00000000 00000000			2901+	DS 2F	extracted PSW after test (has CC)
0000388C	FF			2902+	DC X' FF'	extracted CC, if test failed
0000388D	E5C9E2E3 D9404040			2903+	DC CL8' VISTR'	instruction name
00003898	000038FC			2904+	DC A(RE61)	address of v1 result
0000389C	0000390C			2905+	DC A(RE61+16)	address of v2 source
000038A0	0000391C			2906+	DC A(RE61+32)	address of v3 source
000038A4	00000010			2907+	DC A(16)	result length
000038A8	000038FC			2908+REA61	DC A(RE61)	result address
000038B0	00000000 00000000			2909+	DS FD	gap
000038B8	00000000 00000000			2910+V1061	DS XL16	V1 output
000038C0	00000000 00000000					
000038C8	00000000 00000000			2911+	DS FD	gap
				2912+*		
000038D0				2913+X61	DS OF	
000038D0	4110 8EF8		000010F8	2914+	LA R1, V1FUDGE	load v21 fudge
000038D4	E751 0000 0806		00000000	2915+	VL v21, 0(R1)	
000038DA	E310 5024 0014		00000024	2916+	LGF R1, V2ADDR	load v2 source
000038E0	E761 0000 0806		00000000	2917+	VL v22, 0(R1)	use v21 to test decoder
000038E6	E756 0010 2C5C			2918+	VISTR V21, V22, 2, 1	test instruction
000038EC	B98D 0020			2919+	EPSW R2, R0	extract psw
000038F0	5020 500C		0000000C	2920+	ST R2, CCPSW	to save CC
000038F4	E750 5040 080E		000038B8	2921+	VST V21, V1061	save v1 output
000038FA	07FB			2922+	BR R11	return
000038FC				2923+RE61	DC OF	V1 for this test
000038FC				2924+	DROP R5	
000038FC	AAAAAAAA 00000000			2925	DC XL16' AAAAAAAAAA 00000000 00000000 00000000'	v1
00003904	00000000 00000000					
0000390C	AAAAAAAA 00000000			2926	DC XL16' AAAAAAAAAA 00000000 CCCCCCCC 00000000'	v2
00003914	CCCCCCCC 00000000					
				2927		
				2928	VRR_A VISTR, 2, 1, 0	
00003920				2929+	DS OFD	
00003920		00003920		2930+	USING *, R5	base for test data and test routine
00003920	00003978			2931+T62	DC A(X62)	address of test routine
00003924	003E			2932+	DC H' 62'	test number
00003926	00			2933+	DC X' 00'	
00003927	02			2934+	DC HL1' 2'	M3 used
00003928	01			2935+	DC HL1' 1'	M5 used
00003929	00			2936+	DC HL1' 0'	CC
0000392A	07			2937+	DC HL1' 7'	CC failed mask
0000392C	00000000 00000000			2938+	DS 2F	extracted PSW after test (has CC)
00003934	FF			2939+	DC X' FF'	extracted CC, if test failed
00003935	E5C9E2E3 D9404040			2940+	DC CL8' VISTR'	instruction name
00003940	000039A4			2941+	DC A(RE62)	address of v1 result
00003944	000039B4			2942+	DC A(RE62+16)	address of v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003948	000039C4			2943+	DC	A(RE62+32)	address of v3 source
0000394C	00000010			2944+	DC	A(16)	result length
00003950	000039A4			2945+REA62	DC	A(RE62)	result address
00003958	00000000 00000000			2946+	DS	FD	gap
00003960	00000000 00000000			2947+V1062	DS	XL16	V1 output
00003968	00000000 00000000						
00003970	00000000 00000000			2948+	DS	FD	gap
				2949+*			
00003978				2950+X62	DS	OF	
00003978	4110 8EF8		000010F8	2951+	LA	R1, V1FUDGE	load v21 fudge
0000397C	E751 0000 0806		00000000	2952+	VL	v21, 0(R1)	
00003982	E310 5024 0014		00000024	2953+	LGF	R1, V2ADDR	load v2 source
00003988	E761 0000 0806		00000000	2954+	VL	v22, 0(R1)	use v21 to test decoder
0000398E	E756 0010 2C5C			2955+	VISTR	V21, V22, 2, 1	test instruction
00003994	B98D 0020			2956+	EPSW	R2, R0	extract psw
00003998	5020 500C		0000000C	2957+	ST	R2, CCPSW	to save CC
0000399C	E750 5040 080E		00003960	2958+	VST	V21, V1062	save v1 output
000039A2	07FB			2959+	BR	R11	return
000039A4				2960+RE62	DC	OF	V1 for this test
000039A4				2961+	DROP	R5	
000039A4	AAAAAAAA 00000000			2962	DC	XL16' AAAAAAAAA 00000000 00000000 00000000'	v1
000039AC	00000000 00000000						
000039B4	AAAAAAAA 00000000			2963	DC	XL16' AAAAAAAAA 00000000 00000000 DDDDDDDD'	v2
000039BC	00000000 DDDDDDDD						
				2964			
				2965	VRR_A	VISTR, 2, 1, 0	
000039C8				2966+	DS	OFD	
000039C8		000039C8		2967+	USING	*, R5	base for test data and test routine
000039C8	00003A20			2968+T63	DC	A(X63)	address of test routine
000039CC	003F			2969+	DC	H' 63'	test number
000039CE	00			2970+	DC	X' 00'	
000039CF	02			2971+	DC	HL1' 2'	MB used
000039D0	01			2972+	DC	HL1' 1'	M5 used
000039D1	00			2973+	DC	HL1' 0'	CC
000039D2	07			2974+	DC	HL1' 7'	CC failed mask
000039D4	00000000 00000000			2975+	DS	2F	extracted PSW after test (has CC)
000039DC	FF			2976+	DC	X' FF'	extracted CC, if test failed
000039DD	E5C9E2E3 D9404040			2977+	DC	CL8' VISTR'	instruction name
000039E8	00003A4C			2978+	DC	A(RE63)	address of v1 result
000039EC	00003A5C			2979+	DC	A(RE63+16)	address of v2 source
000039F0	00003A6C			2980+	DC	A(RE63+32)	address of v3 source
000039F4	00000010			2981+	DC	A(16)	result length
000039F8	00003A4C			2982+REA63	DC	A(RE63)	result address
00003A00	00000000 00000000			2983+	DS	FD	gap
00003A08	00000000 00000000			2984+V1063	DS	XL16	V1 output
00003A10	00000000 00000000						
00003A18	00000000 00000000			2985+	DS	FD	gap
				2986+*			
00003A20				2987+X63	DS	OF	
00003A20	4110 8EF8		000010F8	2988+	LA	R1, V1FUDGE	load v21 fudge
00003A24	E751 0000 0806		00000000	2989+	VL	v21, 0(R1)	
00003A2A	E310 5024 0014		00000024	2990+	LGF	R1, V2ADDR	load v2 source
00003A30	E761 0000 0806		00000000	2991+	VL	v22, 0(R1)	use v21 to test decoder
00003A36	E756 0010 2C5C			2992+	VISTR	V21, V22, 2, 1	test instruction
00003A3C	B98D 0020			2993+	EPSW	R2, R0	extract psw
00003A40	5020 500C		0000000C	2994+	ST	R2, CCPSW	to save CC

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003A44	E750 5040 080E		00003A08	2995+	VST	V21, V1063	save v1 output		
00003A4A	07FB			2996+	BR	R11	return		
00003A4C				2997+RE63	DC	0F	V1 for this test		
00003A4C				2998+	DROP	R5			
00003A4C	00000000 00000000			2999	DC	XL16' 00000000 00000000 00000000 00000000'	v1		
00003A54	00000000 00000000								
00003A5C	00000000 00000000		3000		DC	XL16' 00000000 00000000 CCCCCCCC DDDDDDDD'	v2		
00003A64	CCCCCCCC DDDDDDDD								
				3001					
				3002	VRR_A	VISTR, 2, 1, 0			
00003A70				3003+	DS	0FD			
00003A70		00003A70		3004+	USING	*, R5	base for test data and test routine		
00003A70	00003AC8			3005+T64	DC	A(X64)	address of test routine		
00003A74	0040			3006+	DC	H' 64'	test number		
00003A76	00			3007+	DC	X' 00'			
00003A77	02			3008+	DC	HL1' 2'	MB used		
00003A78	01			3009+	DC	HL1' 1'	M5 used		
00003A79	00			3010+	DC	HL1' 0'	CC		
00003A7A	07			3011+	DC	HL1' 7'	CC failed mask		
00003A7C	00000000 00000000			3012+	DS	2F	extracted PSW after test (has CC)		
00003A84	FF			3013+	DC	X' FF'	extracted CC, if test failed		
00003A85	E5C9E2E3 D9404040			3014+	DC	CL8' VISTR'	instruction name		
00003A90	00003AF4			3015+	DC	A(RE64)	address of v1 result		
00003A94	00003B04			3016+	DC	A(RE64+16)	address of v2 source		
00003A98	00003B14			3017+	DC	A(RE64+32)	address of v3 source		
00003A9C	00000010			3018+	DC	A(16)	result length		
00003AA0	00003AF4			3019+REA64	DC	A(RE64)	result address		
00003AA8	00000000 00000000			3020+	DS	FD	gap		
00003AB0	00000000 00000000			3021+V1064	DS	XL16	V1 output		
00003AB8	00000000 00000000								
00003AC0	00000000 00000000			3022+	DS	FD	gap		
				3023+*					
00003AC8				3024+X64	DS	0F			
00003AC8	4110 8EF8		000010F8	3025+	LA	R1, V1FUDGE	load v21 fudge		
00003ACC	E751 0000 0806		00000000	3026+	VL	v21, 0(R1)			
00003AD2	E310 5024 0014		00000024	3027+	LGF	R1, V2ADDR	load v2 source		
00003AD8	E761 0000 0806		00000000	3028+	VL	v22, 0(R1)	use v21 to test decoder		
00003ADE	E756 0010 2C5C			3029+	VISTR	V21, V22, 2, 1	test instruction		
00003AE4	B98D 0020			3030+	EPSW	R2, R0	extract psw		
00003AE8	5020 500C		0000000C	3031+	ST	R2, CCPSW	to save CC		
00003AEC	E750 5040 080E		00003AB0	3032+	VST	V21, V1064	save v1 output		
00003AF2	07FB			3033+	BR	R11	return		
00003AF4				3034+RE64	DC	0F	V1 for this test		
00003AF4				3035+	DROP	R5			
00003AF4	00000000 00000000			3036	DC	XL16' 00000000 00000000 00000000 00000000'	v1		
00003AFC	00000000 00000000								
00003B04	00000000 BBBB BBBB		3037		DC	XL16' 00000000 BBBB BBBB CCCCCCCC DDDDDDDD'	v2		
00003B0C	CCCCCCCC DDDDDDDD								

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3039 *	-----
				3040 *	case 3 - same value before and after zeros CS=1
				3041 *	-----
				3042 *	byte
				3043	VRR_A VISTR, 0, 1, 0
00003B18				3044+	DS OFD
00003B18		00003B18		3045+	USING *, R5
00003B18	00003B70			3046+T65	DC A(X65)
00003B1C	0041			3047+	DC H' 65'
00003B1E	00			3048+	DC X' 00'
00003B1F	00			3049+	DC HL1' 0'
00003B20	01			3050+	DC HL1' 1'
00003B21	00			3051+	DC HL1' 0'
00003B22	07			3052+	DC HL1' 7'
00003B24	00000000 00000000			3053+	DS 2F
00003B2C	FF			3054+	DC X' FF'
00003B2D	E5C9E2E3 D9404040			3055+	DC CL8' VISTR'
00003B38	00003B9C			3056+	DC A(RE65)
00003B3C	00003BAC			3057+	DC A(RE65+16)
00003B40	00003BBC			3058+	DC A(RE65+32)
00003B44	00000010			3059+	DC A(16)
00003B48	00003B9C			3060+REA65	DC A(RE65)
00003B50	00000000 00000000			3061+	DS FD
00003B58	00000000 00000000			3062+V1065	DS XL16
00003B60	00000000 00000000				
00003B68	00000000 00000000			3063+	DS FD
				3064+*	
00003B70				3065+X65	DS OF
00003B70	4110 8EF8		000010F8	3066+	LA R1, V1FUDGE
00003B74	E751 0000 0806		00000000	3067+	VL v21, 0(R1)
00003B7A	E310 5024 0014		00000024	3068+	LGF R1, V2ADDR
00003B80	E761 0000 0806		00000000	3069+	VL v22, 0(R1)
00003B86	E756 0010 0C5C			3070+	VISTR V21, V22, 0, 1
00003B8C	B98D 0020			3071+	EPSW R2, R0
00003B90	5020 500C		0000000C	3072+	ST R2, CCPSW
00003B94	E750 5040 080E		00003B58	3073+	VST V21, V1065
00003B9A	07FB			3074+	BR R11
00003B9C				3075+RE65	DC OF
00003B9C				3076+	DROP R5
00003B9C	88888888 88888888			3077	DC XL16' 88888888 88888888 88888888 00000000' v1
00003BA4	88888888 00000000				
00003BAC	88888888 88888888			3078	DC XL16' 88888888 88888888 88888888 00888888' v2
00003BB4	88888888 00888888				
				3079	
00003BC0				3080	VRR_A VISTR, 0, 1, 0
00003BC0		00003BC0		3081+	DS OFD
00003BC0	00003C18			3082+	USING *, R5
00003BC4	0042			3083+T66	DC A(X66)
00003BC6	00			3084+	DC H' 66'
00003BC7	00			3085+	DC X' 00'
00003BC8	01			3086+	DC HL1' 0'
00003BC9	00			3087+	DC HL1' 1'
00003BCA	07			3088+	DC HL1' 0'
00003BCC	00000000 00000000			3089+	DC HL1' 7'
00003BD4	FF			3090+	DS 2F
				3091+	DC X' FF'

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
00003BD5	E5C9E2E3 D9404040			3092+	DC	CL8' VISTR'	instruction name
00003BE0	00003C44			3093+	DC	A(RE66)	address of v1 result
00003BE4	00003C54			3094+	DC	A(RE66+16)	address of v2 source
00003BE8	00003C64			3095+	DC	A(RE66+32)	address of v3 source
00003BEC	00000010			3096+	DC	A(16)	result length
00003BF0	00003C44			3097+REA66	DC	A(RE66)	result address
00003BF8	00000000 00000000			3098+	DS	FD	gap
00003C00	00000000 00000000			3099+V1066	DS	XL16	V1 output
00003C08	00000000 00000000						
00003C10	00000000 00000000			3100+	DS	FD	gap
				3101+*			
00003C18				3102+X66	DS	OF	
00003C18	4110 8EF8		000010F8	3103+	LA	R1, V1FUDGE	load v21 fudge
00003C1C	E751 0000 0806		00000000	3104+	VL	v21, 0(R1)	
00003C22	E310 5024 0014		00000024	3105+	LGF	R1, V2ADDR	load v2 source
00003C28	E761 0000 0806		00000000	3106+	VL	v22, 0(R1)	use v21 to test decoder
00003C2E	E756 0010 0C5C			3107+	VISTR	V21, V22, 0, 1	test instruction
00003C34	B98D 0020			3108+	EPSW	R2, R0	extract psw
00003C38	5020 500C		0000000C	3109+	ST	R2, CCPSW	to save CC
00003C3C	E750 5040 080E		00003C00	3110+	VST	V21, V1066	save v1 output
00003C42	07FB			3111+	BR	R11	return
00003C44				3112+RE66	DC	OF	V1 for this test
00003C44				3113+	DROP	R5	
00003C44	88888888 88888888			3114	DC	XL16' 88888888 88888888 88000000 00000000'	v1
00003C4C	88000000 00000000						
00003C54	88888888 88888888			3115	DC	XL16' 88888888 88888888 88008880 88888888'	v2
00003C5C	88008880 88888888						
				3116			
				3117	VRR_A	VISTR, 0, 1, 0	
00003C68				3118+	DS	OFD	
00003C68		00003C68		3119+	USING	*, R5	base for test data and test routine
00003C68	00003CC0			3120+T67	DC	A(X67)	address of test routine
00003C6C	0043			3121+	DC	H' 67'	test number
00003C6E	00			3122+	DC	X' 00'	
00003C6F	00			3123+	DC	HL1' 0'	M3 used
00003C70	01			3124+	DC	HL1' 1'	M5 used
00003C71	00			3125+	DC	HL1' 0'	CC
00003C72	07			3126+	DC	HL1' 7'	CC failed mask
00003C74	00000000 00000000			3127+	DS	2F	extracted PSW after test (has CC)
00003C7C	FF			3128+	DC	X' FF'	extracted CC, if test failed
00003C7D	E5C9E2E3 D9404040			3129+	DC	CL8' VISTR'	instruction name
00003C88	00003CEC			3130+	DC	A(RE67)	address of v1 result
00003C8C	00003CFC			3131+	DC	A(RE67+16)	address of v2 source
00003C90	00003D0C			3132+	DC	A(RE67+32)	address of v3 source
00003C94	00000010			3133+	DC	A(16)	result length
00003C98	00003CEC			3134+REA67	DC	A(RE67)	result address
00003CA0	00000000 00000000			3135+	DS	FD	gap
00003CA8	00000000 00000000			3136+V1067	DS	XL16	V1 output
00003CB0	00000000 00000000						
00003CB8	00000000 00000000			3137+	DS	FD	gap
				3138+*			
00003CC0				3139+X67	DS	OF	
00003CC0	4110 8EF8		000010F8	3140+	LA	R1, V1FUDGE	load v21 fudge
00003CC4	E751 0000 0806		00000000	3141+	VL	v21, 0(R1)	
00003CCA	E310 5024 0014		00000024	3142+	LGF	R1, V2ADDR	load v2 source
00003CD0	E761 0000 0806		00000000	3143+	VL	v22, 0(R1)	use v21 to test decoder

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003CD6	E756 0010 0C5C			3144+	VISTR	V21, V22, 0, 1		test instruction	
00003CDC	B98D 0020			3145+	EPSW	R2, R0		extract psw	
00003CE0	5020 500C		0000000C	3146+	ST	R2, CCPSW		to save CC	
00003CE4	E750 5040 080E		00003CA8	3147+	VST	V21, V1067		save v1 output	
00003CEA	07FB			3148+	BR	R11		return	
00003CEC				3149+RE67	DC	0F		V1 for this test	
00003CEC				3150+	DROP	R5			
00003CEC	88888800 00000000			3151	DC	XL16' 88888800 00000000 00000000 00000000'		v1	
00003CF4	00000000 00000000								
00003CFC	88888800 88888888			3152	DC	XL16' 88888800 88888888 88888888 88888888'		v2	
00003D04	88888888 88888888								
00003D10				3153					
00003D10				3154	VRR_A	VISTR, 0, 1, 0			
00003D10		00003D10		3155+	DS	0FD			
00003D10	00003D68			3156+	USING	*, R5		base for test data and test routine	
00003D14	0044			3157+T68	DC	A(X68)		address of test routine	
00003D16	00			3158+	DC	H' 68'		test number	
00003D17	00			3159+	DC	X' 00'			
00003D18	01			3160+	DC	HL1' 0'		MB used	
00003D19	00			3161+	DC	HL1' 1'		M5 used	
00003D1A	07			3162+	DC	HL1' 0'		CC	
00003D1C	00000000 00000000			3163+	DC	HL1' 7'		CC failed mask	
00003D24	FF			3164+	DS	2F		extracted PSW after test (has CC)	
00003D25	E5C9E2E3 D9404040			3165+	DC	X' FF'		extracted CC, if test failed	
00003D30	00003D94			3166+	DC	CL8' VISTR'		instruction name	
00003D34	00003DA4			3167+	DC	A(RE68)		address of v1 result	
00003D38	00003DB4			3168+	DC	A(RE68+16)		address of v2 source	
00003D3C	00000010			3169+	DC	A(RE68+32)		address of v3 source	
00003D40	00003D94			3170+	DC	A(16)		result length	
00003D48	00000000 00000000			3171+REA68	DC	A(RE68)		result address	
00003D50	00000000 00000000			3172+	DS	FD		gap	
00003D58	00000000 00000000			3173+V1068	DS	XL16		V1 output	
00003D60	00000000 00000000			3174+	DS	FD		gap	
00003D68				3175+*					
00003D68	4110 8EF8		000010F8	3176+X68	DS	0F			
00003D6C	E751 0000 0806		00000000	3177+	LA	R1, V1FUDGE		load v21 fudge	
00003D72	E310 5024 0014		00000024	3178+	VL	v21, 0(R1)			
00003D78	E761 0000 0806		00000000	3179+	LGF	R1, V2ADDR		load v2 source	
00003D7E	E756 0010 0C5C			3180+	VL	v22, 0(R1)		use v21 to test decoder	
00003D84	B98D 0020			3181+	VISTR	V21, V22, 0, 1		test instruction	
00003D88	5020 500C		0000000C	3182+	EPSW	R2, R0		extract psw	
00003D8C	E750 5040 080E		00003D50	3183+	ST	R2, CCPSW		to save CC	
00003D92	07FB			3184+	VST	V21, V1068		save v1 output	
00003D94				3185+	BR	R11		return	
00003D94				3186+RE68	DC	0F		V1 for this test	
00003D94	88888888 88888888			3187+	DROP	R5			
00003D9C	88888888 00000000			3188	DC	XL16' 88888888 88888888 88888888 00000000'		v1	
00003DA4	88888888 88888888								
00003DAC	88888888 00880088			3189	DC	XL16' 88888888 88888888 88888888 00880088'		v2	
00003DB8				3190					
00003DB8		00003DB8		3191	VRR_A	VISTR, 0, 1, 0			
00003DB8	00003E10			3192+	DS	0FD			
				3193+	USING	*, R5		base for test data and test routine	
				3194+T69	DC	A(X69)		address of test routine	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003DBC	0045			3195+	DC	H' 69'		test number	
00003DBE	00			3196+	DC	X' 00'			
00003DBF	00			3197+	DC	HL1' 0'		M3 used	
00003DC0	01			3198+	DC	HL1' 1'		M5 used	
00003DC1	00			3199+	DC	HL1' 0'		CC	
00003DC2	07			3200+	DC	HL1' 7'		CC failed mask	
00003DC4	00000000	00000000		3201+	DS	2F		extracted PSW after test (has CC)	
00003DCC	FF			3202+	DC	X' FF'		extracted CC, if test failed	
00003DCD	E5C9E2E3	D9404040		3203+	DC	CL8' VISTR'		instruction name	
00003DD8	00003E3C			3204+	DC	A(RE69)		address of v1 result	
00003DDC	00003E4C			3205+	DC	A(RE69+16)		address of v2 source	
00003DE0	00003E5C			3206+	DC	A(RE69+32)		address of v3 source	
00003DE4	00000010			3207+	DC	A(16)		result length	
00003DE8	00003E3C			3208+REA69	DC	A(RE69)		result address	
00003DF0	00000000	00000000		3209+	DS	FD		gap	
00003DF8	00000000	00000000		3210+V1069	DS	XL16		V1 output	
00003E00	00000000	00000000							
00003E08	00000000	00000000		3211+	DS	FD		gap	
				3212+*					
00003E10				3213+X69	DS	0F			
00003E10	4110 8EF8		000010F8	3214+	LA	R1, V1FUDGE		load v21 fudge	
00003E14	E751 0000 0806		00000000	3215+	VL	v21, 0(R1)			
00003E1A	E310 5024 0014		00000024	3216+	LGF	R1, V2ADDR		load v2 source	
00003E20	E761 0000 0806		00000000	3217+	VL	v22, 0(R1)		use v21 to test decoder	
00003E26	E756 0010 0C5C			3218+	VISTR	V21, V22, 0, 1		test instruction	
00003E2C	B98D 0020			3219+	EPSW	R2, R0		extract psw	
00003E30	5020 500C		0000000C	3220+	ST	R2, CCPSW		to save CC	
00003E34	E750 5040 080E		00003DF8	3221+	VST	V21, V1069		save v1 output	
00003E3A	07FB			3222+	BR	R11		return	
00003E3C				3223+RE69	DC	0F		V1 for this test	
00003E3C				3224+	DROP	R5			
00003E3C	88888888	88888888		3225	DC	XL16' 88888888 88888888 88000000 00000000'		v1	
00003E44	88000000	00000000							
00003E4C	88888888	88888888		3226	DC	XL16' 88888888 88888888 88008880 00888888'		v2	
00003E54	88008880	00888888							
				3227					
00003E60				3228	VRR_A	VISTR, 0, 1, 0			
00003E60		00003E60		3229+	DS	0FD			
00003E60	00003EB8			3230+	USING	*, R5		base for test data and test routine	
00003E64	0046			3231+T70	DC	A(X70)		address of test routine	
00003E66	00			3232+	DC	H' 70'		test number	
00003E66	00			3233+	DC	X' 00'			
00003E67	00			3234+	DC	HL1' 0'		M3 used	
00003E68	01			3235+	DC	HL1' 1'		M5 used	
00003E69	00			3236+	DC	HL1' 0'		CC	
00003E6A	07			3237+	DC	HL1' 7'		CC failed mask	
00003E6C	00000000	00000000		3238+	DS	2F		extracted PSW after test (has CC)	
00003E74	FF			3239+	DC	X' FF'		extracted CC, if test failed	
00003E75	E5C9E2E3	D9404040		3240+	DC	CL8' VISTR'		instruction name	
00003E80	00003EE4			3241+	DC	A(RE70)		address of v1 result	
00003E84	00003EF4			3242+	DC	A(RE70+16)		address of v2 source	
00003E88	00003F04			3243+	DC	A(RE70+32)		address of v3 source	
00003E8C	00000010			3244+	DC	A(16)		result length	
00003E90	00003EE4			3245+REA70	DC	A(RE70)		result address	
00003E98	00000000	00000000		3246+	DS	FD		gap	
00003EA0	00000000	00000000		3247+V1070	DS	XL16		V1 output	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00003EA8	00000000 00000000								
00003EB0	00000000 00000000			3248+	DS	FD	gap		
				3249+*					
00003EB8				3250+X70	DS	0F			
00003EB8	4110 8EF8		000010F8	3251+	LA	R1, V1FUDGE	load v21 fudge		
00003EBC	E751 0000 0806		00000000	3252+	VL	v21, 0(R1)			
00003EC2	E310 5024 0014		00000024	3253+	LGF	R1, V2ADDR	load v2 source		
00003EC8	E761 0000 0806		00000000	3254+	VL	v22, 0(R1)	use v21 to test decoder		
00003ECE	E756 0010 0C5C			3255+	VISTR	V21, V22, 0, 1	test instruction		
00003ED4	B98D 0020			3256+	EPSW	R2, R0	extract psw		
00003ED8	5020 500C		0000000C	3257+	ST	R2, CCPSW	to save CC		
00003EDC	E750 5040 080E		00003EA0	3258+	VST	V21, V1070	save v1 output		
00003EE2	07FB			3259+	BR	R11	return		
00003EE4				3260+RE70	DC	0F	V1 for this test		
00003EE4				3261+	DROP	R5			
00003EE4	88888800 00000000			3262	DC	XL16' 88888800 00000000 00000000 00000000'	v1		
00003EEC	00000000 00000000								
00003EF4	88888800 88888888			3263	DC	XL16' 88888800 88888888 88880088 88888888'	v2		
00003EFC	88880088 88888888								
				3264					
				3265 *halfword					
				3266	VRR_A	VISTR, 1, 1, 0			
00003F08				3267+	DS	0FD			
00003F08		00003F08		3268+	USING	*, R5	base for test data and test routine		
00003F08	00003F60			3269+T71	DC	A(X71)	address of test routine		
00003F0C	0047			3270+	DC	H' 71'	test number		
00003F0E	00			3271+	DC	X' 00'			
00003F0F	01			3272+	DC	HL1' 1'	MB used		
00003F10	01			3273+	DC	HL1' 1'	M5 used		
00003F11	00			3274+	DC	HL1' 0'	CC		
00003F12	07			3275+	DC	HL1' 7'	CC failed mask		
00003F14	00000000 00000000			3276+	DS	2F	extracted PSW after test (has CC)		
00003F1C	FF			3277+	DC	X' FF'	extracted CC, if test failed		
00003F1D	E5C9E2E3 D9404040			3278+	DC	CL8' VISTR'	instruction name		
00003F28	00003F8C			3279+	DC	A(RE71)	address of v1 result		
00003F2C	00003F9C			3280+	DC	A(RE71+16)	address of v2 source		
00003F30	00003FAC			3281+	DC	A(RE71+32)	address of v3 source		
00003F34	00000010			3282+	DC	A(16)	result length		
00003F38	00003F8C			3283+REA71	DC	A(RE71)	result address		
00003F40	00000000 00000000			3284+	DS	FD	gap		
00003F48	00000000 00000000			3285+V1071	DS	XL16	V1 output		
00003F50	00000000 00000000								
00003F58	00000000 00000000			3286+	DS	FD	gap		
				3287+*					
00003F60				3288+X71	DS	0F			
00003F60	4110 8EF8		000010F8	3289+	LA	R1, V1FUDGE	load v21 fudge		
00003F64	E751 0000 0806		00000000	3290+	VL	v21, 0(R1)			
00003F6A	E310 5024 0014		00000024	3291+	LGF	R1, V2ADDR	load v2 source		
00003F70	E761 0000 0806		00000000	3292+	VL	v22, 0(R1)	use v21 to test decoder		
00003F76	E756 0010 1C5C			3293+	VISTR	V21, V22, 1, 1	test instruction		
00003F7C	B98D 0020			3294+	EPSW	R2, R0	extract psw		
00003F80	5020 500C		0000000C	3295+	ST	R2, CCPSW	to save CC		
00003F84	E750 5040 080E		00003F48	3296+	VST	V21, V1071	save v1 output		
00003F8A	07FB			3297+	BR	R11	return		
00003F8C				3298+RE71	DC	0F	V1 for this test		
00003F8C				3299+	DROP	R5			

LOC	OBJECT CODE	ADDR1	ADDR2	STMT						
00003F8C	88888888 88888888			3300	DC	XL16'	88888888 88888888 88888888 00000000'	v1		
00003F94	88888888 00000000									
00003F9C	88888888 88888888			3301	DC	XL16'	88888888 88888888 88888888 00008888'	v2		
00003FA4	88888888 00008888									
				3302						
00003FB0				3303	VRR_A	VISTR, 1, 1, 0				
00003FB0		00003FB0		3304+	DS	OFD				
00003FB0	00004008			3305+	USING	*, R5		base for test data and test routine		
00003FB4	0048			3306+T72	DC	A(X72)		address of test routine		
00003FB6	00			3307+	DC	H' 72'		test number		
00003FB7	01			3308+	DC	X' 00'				
00003FB8	01			3309+	DC	HL1' 1'		MB used		
00003FB8	01			3310+	DC	HL1' 1'		M5 used		
00003FB9	00			3311+	DC	HL1' 0'		CC		
00003FBA	07			3312+	DC	HL1' 7'		CC failed mask		
00003FBC	00000000 00000000			3313+	DS	2F		extracted PSW after test (has CC)		
00003FC4	FF			3314+	DC	X' FF'		extracted CC, if test failed		
00003FC5	E5C9E2E3 D9404040			3315+	DC	CL8' VISTR'		instruction name		
00003FD0	00004034			3316+	DC	A(RE72)		address of v1 result		
00003FD4	00004044			3317+	DC	A(RE72+16)		address of v2 source		
00003FD8	00004054			3318+	DC	A(RE72+32)		address of v3 source		
00003FDC	00000010			3319+	DC	A(16)		result length		
00003FE0	00004034			3320+REA72	DC	A(RE72)		result address		
00003FE8	00000000 00000000			3321+	DS	FD		gap		
00003FF0	00000000 00000000			3322+V1072	DS	XL16		V1 output		
00003FF8	00000000 00000000									
00004000	00000000 00000000			3323+	DS	FD		gap		
				3324+*						
00004008				3325+X72	DS	OF				
00004008	4110 8EF8		000010F8	3326+	LA	R1, V1FUDGE		load v21 fudge		
0000400C	E751 0000 0806		00000000	3327+	VL	v21, 0(R1)				
00004012	E310 5024 0014		00000024	3328+	LGF	R1, V2ADDR		load v2 source		
00004018	E761 0000 0806		00000000	3329+	VL	v22, 0(R1)		use v21 to test decoder		
0000401E	E756 0010 1C5C			3330+	VISTR	V21, V22, 1, 1		test instruction		
00004024	B98D 0020			3331+	EPSW	R2, R0		extract psw		
00004028	5020 500C		0000000C	3332+	ST	R2, CCPSW		to save CC		
0000402C	E750 5040 080E		00003FF0	3333+	VST	V21, V1072		save v1 output		
00004032	07FB			3334+	BR	R11		return		
00004034				3335+RE72	DC	OF		V1 for this test		
00004034				3336+	DROP	R5				
00004034	88888888 00000000			3337	DC	XL16' 88888888 00000000 00000000 00000000'	v1			
0000403C	00000000 00000000									
00004044	88888888 00008888			3338	DC	XL16' 88888888 00008888 88888888 88888888'	v2			
0000404C	88888888 88888888									
				3339						
00004058				3340	VRR_A	VISTR, 1, 1, 0				
00004058		00004058		3341+	DS	OFD				
00004058	000040B0			3342+	USING	*, R5		base for test data and test routine		
0000405C	0049			3343+T73	DC	A(X73)		address of test routine		
0000405E	00			3344+	DC	H' 73'		test number		
0000405E	00			3345+	DC	X' 00'				
0000405F	01			3346+	DC	HL1' 1'		MB used		
00004060	01			3347+	DC	HL1' 1'		M5 used		
00004061	00			3348+	DC	HL1' 0'		CC		
00004062	07			3349+	DC	HL1' 7'		CC failed mask		
00004064	00000000 00000000			3350+	DS	2F		extracted PSW after test (has CC)		

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000406C	FF			3351+	DC	X' FF'	extracted CC, if test failed
0000406D	E5C9E2E3 D9404040			3352+	DC	CL8' VISTR'	instruction name
00004078	000040DC			3353+	DC	A(RE73)	address of v1 result
0000407C	000040EC			3354+	DC	A(RE73+16)	address of v2 source
00004080	000040FC			3355+	DC	A(RE73+32)	address of v3 source
00004084	00000010			3356+	DC	A(16)	result length
00004088	000040DC			3357+REA73	DC	A(RE73)	result address
00004090	00000000 00000000			3358+	DS	FD	gap
00004098	00000000 00000000			3359+V1073	DS	XL16	V1 output
000040A0	00000000 00000000						
000040A8	00000000 00000000			3360+	DS	FD	gap
				3361+*			
000040B0				3362+X73	DS	OF	
000040B0	4110 8EF8		000010F8	3363+	LA	R1, V1FUDGE	load v21 fudge
000040B4	E751 0000 0806		00000000	3364+	VL	v21, 0(R1)	
000040BA	E310 5024 0014		00000024	3365+	LGF	R1, V2ADDR	load v2 source
000040C0	E761 0000 0806		00000000	3366+	VL	v22, 0(R1)	use v21 to test decoder
000040C6	E756 0010 1C5C			3367+	VISTR	V21, V22, 1, 1	test instruction
000040CC	B98D 0020			3368+	EPSW	R2, R0	extract psw
000040D0	5020 500C		0000000C	3369+	ST	R2, CCPSW	to save CC
000040D4	E750 5040 080E		00004098	3370+	VST	V21, V1073	save v1 output
000040DA	07FB			3371+	BR	R11	return
000040DC				3372+RE73	DC	OF	V1 for this test
000040DC				3373+	DROP	R5	
000040DC	88888888 88888888			3374	DC	XL16' 88888888 88888888 00000000 00000000'	v1
000040E4	00000000 00000000						
000040EC	88888888 88888888			3375	DC	XL16' 88888888 88888888 00000888 00008888'	v2
000040F4	00000888 00008888						
				3376			
00004100				3377	VRR_A	VISTR, 1, 1, 0	
00004100		00004100		3378+	DS	OFD	
00004100	00004158			3379+	USING	*, R5	base for test data and test routine
00004104	004A			3380+T74	DC	A(X74)	address of test routine
00004106	00			3381+	DC	H' 74'	test number
00004106	00			3382+	DC	X' 00'	
00004107	01			3383+	DC	HL1' 1'	M3 used
00004108	01			3384+	DC	HL1' 1'	M5 used
00004109	00			3385+	DC	HL1' 0'	CC
0000410A	07			3386+	DC	HL1' 7'	CC failed mask
0000410C	00000000 00000000			3387+	DS	2F	extracted PSW after test (has CC)
00004114	FF			3388+	DC	X' FF'	extracted CC, if test failed
00004115	E5C9E2E3 D9404040			3389+	DC	CL8' VISTR'	instruction name
00004120	00004184			3390+	DC	A(RE74)	address of v1 result
00004124	00004194			3391+	DC	A(RE74+16)	address of v2 source
00004128	000041A4			3392+	DC	A(RE74+32)	address of v3 source
0000412C	00000010			3393+	DC	A(16)	result length
00004130	00004184			3394+REA74	DC	A(RE74)	result address
00004138	00000000 00000000			3395+	DS	FD	gap
00004140	00000000 00000000			3396+V1074	DS	XL16	V1 output
00004148	00000000 00000000						
00004150	00000000 00000000			3397+	DS	FD	gap
				3398+*			
00004158				3399+X74	DS	OF	
00004158	4110 8EF8		000010F8	3400+	LA	R1, V1FUDGE	load v21 fudge
0000415C	E751 0000 0806		00000000	3401+	VL	v21, 0(R1)	
00004162	E310 5024 0014		00000024	3402+	LGF	R1, V2ADDR	load v2 source

LOC	OBJECT CODE	ADDR1	ADDR2	STMT					
00004168	E761 0000 0806		00000000	3403+	VL	v22, 0(R1)	use v21 to test decoder		
0000416E	E756 0010 1C5C			3404+	VISTR	V21, V22, 1, 1	test instruction		
00004174	B98D 0020			3405+	EPSW	R2, R0	extract psw		
00004178	5020 500C		0000000C	3406+	ST	R2, CCPSW	to save CC		
0000417C	E750 5040 080E		00004140	3407+	VST	V21, V1074	save v1 output		
00004182	07FB			3408+	BR	R11	return		
00004184				3409+RE74	DC	0F	V1 for this test		
00004184				3410+	DROP	R5			
00004184	88880000 00000000			3411	DC	XL16' 88880000 00000000 00000000 00000000'	v1		
0000418C	00000000 00000000								
00004194	88880000 88888888			3412	DC	XL16' 88880000 88888888 00000888 00008888'	v2		
0000419C	00000888 00008888								
				3413	*	-----			
				3414	*	case 4 - misc	CS=1		
				3415	*	-----			
				3416					
				3417	VRR_A	VISTR, 0, 1, 0			
000041A8				3418+	DS	0FD			
000041A8		000041A8		3419+	USING	*, R5	base for test data and test routine		
000041A8	00004200			3420+T75	DC	A(X75)	address of test routine		
000041AC	004B			3421+	DC	H' 75'	test number		
000041AE	00			3422+	DC	X' 00'			
000041AF	00			3423+	DC	HL1' 0'	MB used		
000041B0	01			3424+	DC	HL1' 1'	M5 used		
000041B1	00			3425+	DC	HL1' 0'	CC		
000041B2	07			3426+	DC	HL1' 7'	CC failed mask		
000041B4	00000000 00000000			3427+	DS	2F	extracted PSW after test (has CC)		
000041BC	FF			3428+	DC	X' FF'	extracted CC, if test failed		
000041BD	E5C9E2E3 D9404040			3429+	DC	CL8' VISTR'	instruction name		
000041C8	0000422C			3430+	DC	A(RE75)	address of v1 result		
000041CC	0000423C			3431+	DC	A(RE75+16)	address of v2 source		
000041D0	0000424C			3432+	DC	A(RE75+32)	address of v3 source		
000041D4	00000010			3433+	DC	A(16)	result length		
000041D8	0000422C			3434+REA75	DC	A(RE75)	result address		
000041E0	00000000 00000000			3435+	DS	FD	gap		
000041E8	00000000 00000000			3436+V1075	DS	XL16	V1 output		
000041F0	00000000 00000000								
000041F8	00000000 00000000			3437+	DS	FD	gap		
				3438+*					
00004200				3439+X75	DS	0F			
00004200	4110 8EF8		000010F8	3440+	LA	R1, V1FUDGE	load v21 fudge		
00004204	E751 0000 0806		00000000	3441+	VL	v21, 0(R1)			
0000420A	E310 5024 0014		00000024	3442+	LGF	R1, V2ADDR	load v2 source		
00004210	E761 0000 0806		00000000	3443+	VL	v22, 0(R1)	use v21 to test decoder		
00004216	E756 0010 0C5C			3444+	VISTR	V21, V22, 0, 1	test instruction		
0000421C	B98D 0020			3445+	EPSW	R2, R0	extract psw		
00004220	5020 500C		0000000C	3446+	ST	R2, CCPSW	to save CC		
00004224	E750 5040 080E		000041E8	3447+	VST	V21, V1075	save v1 output		
0000422A	07FB			3448+	BR	R11	return		
0000422C				3449+RE75	DC	0F	V1 for this test		
0000422C				3450+	DROP	R5			
0000422C	88838182 84868700			3451	DC	XL16' 88838182 84868700 00000000 00000000'	v1		
00004234	00000000 00000000								
0000423C	88838182 84868700			3452	DC	XL16' 88838182 84868700 81880000 000D1111'	v2		
00004244	81880000 000D1111								
				3453					

LOC	OBJECT CODE	ADDR1	ADDR2	STMT
				3458 *
				3459 * table of pointers to individual tests
				3460 *
00004254				3461 E7TESTS DS OF
				3462 PTTABLE
00004254				3463+TTABLE DS OF
00004254	00001118			3464+ DC A(T1) test address
00004258	000011C0			3465+ DC A(T2) test address
0000425C	00001268			3466+ DC A(T3) test address
00004260	00001310			3467+ DC A(T4) test address
00004264	000013B8			3468+ DC A(T5) test address
00004268	00001460			3469+ DC A(T6) test address
0000426C	00001508			3470+ DC A(T7) test address
00004270	000015B0			3471+ DC A(T8) test address
00004274	00001658			3472+ DC A(T9) test address
00004278	00001700			3473+ DC A(T10) test address
0000427C	000017A8			3474+ DC A(T11) test address
00004280	00001850			3475+ DC A(T12) test address
00004284	000018F8			3476+ DC A(T13) test address
00004288	000019A0			3477+ DC A(T14) test address
0000428C	00001A48			3478+ DC A(T15) test address
00004290	00001AF0			3479+ DC A(T16) test address
00004294	00001B98			3480+ DC A(T17) test address
00004298	00001C40			3481+ DC A(T18) test address
0000429C	00001CE8			3482+ DC A(T19) test address
000042A0	00001D90			3483+ DC A(T20) test address
000042A4	00001E38			3484+ DC A(T21) test address
000042A8	00001EE0			3485+ DC A(T22) test address
000042AC	00001F88			3486+ DC A(T23) test address
000042B0	00002030			3487+ DC A(T24) test address
000042B4	000020D8			3488+ DC A(T25) test address
000042B8	00002180			3489+ DC A(T26) test address
000042BC	00002228			3490+ DC A(T27) test address
000042C0	000022D0			3491+ DC A(T28) test address
000042C4	00002378			3492+ DC A(T29) test address
000042C8	00002420			3493+ DC A(T30) test address
000042CC	000024C8			3494+ DC A(T31) test address
000042D0	00002570			3495+ DC A(T32) test address
000042D4	00002618			3496+ DC A(T33) test address
000042D8	000026C0			3497+ DC A(T34) test address
000042DC	00002768			3498+ DC A(T35) test address
000042E0	00002810			3499+ DC A(T36) test address
000042E4	000028B8			3500+ DC A(T37) test address
000042E8	00002960			3501+ DC A(T38) test address
000042EC	00002A08			3502+ DC A(T39) test address
000042F0	00002AB0			3503+ DC A(T40) test address
000042F4	00002B58			3504+ DC A(T41) test address
000042F8	00002C00			3505+ DC A(T42) test address
000042FC	00002CA8			3506+ DC A(T43) test address
00004300	00002D50			3507+ DC A(T44) test address
00004304	00002DF8			3508+ DC A(T45) test address
00004308	00002EA0			3509+ DC A(T46) test address
0000430C	00002F48			3510+ DC A(T47) test address
00004310	00002FF0			3511+ DC A(T48) test address
00004314	00003098			3512+ DC A(T49) test address
00004318	00003140			3513+ DC A(T50) test address

LOC	OBJECT CODE	ADDR1	ADDR2	STMT			
0000431C	000031E8			3514+	DC	A(T51)	test address
00004320	00003290			3515+	DC	A(T52)	test address
00004324	00003338			3516+	DC	A(T53)	test address
00004328	000033E0			3517+	DC	A(T54)	test address
0000432C	00003488			3518+	DC	A(T55)	test address
00004330	00003530			3519+	DC	A(T56)	test address
00004334	000035D8			3520+	DC	A(T57)	test address
00004338	00003680			3521+	DC	A(T58)	test address
0000433C	00003728			3522+	DC	A(T59)	test address
00004340	000037D0			3523+	DC	A(T60)	test address
00004344	00003878			3524+	DC	A(T61)	test address
00004348	00003920			3525+	DC	A(T62)	test address
0000434C	000039C8			3526+	DC	A(T63)	test address
00004350	00003A70			3527+	DC	A(T64)	test address
00004354	00003B18			3528+	DC	A(T65)	test address
00004358	00003BC0			3529+	DC	A(T66)	test address
0000435C	00003C68			3530+	DC	A(T67)	test address
00004360	00003D10			3531+	DC	A(T68)	test address
00004364	00003DB8			3532+	DC	A(T69)	test address
00004368	00003E60			3533+	DC	A(T70)	test address
0000436C	00003F08			3534+	DC	A(T71)	test address
00004370	00003FB0			3535+	DC	A(T72)	test address
00004374	00004058			3536+	DC	A(T73)	test address
00004378	00004100			3537+	DC	A(T74)	test address
0000437C	000041A8			3538+	DC	A(T75)	test address
				3539+*			
00004380	00000000			3540+	DC	A(0)	end of table
00004384	00000000			3541+	DC	A(0)	end of table
				3542			
00004388	00000000			3543	DC	F' 0'	END OF TABLE
0000438C	00000000			3544	DC	F' 0'	

LOC	OBJECT CODE	ADDR1	ADDR2	STMT	
				3546 *****	
				3547 * Register equates	
				3548 *****	
		00000000	00000001	3550 R0	EQU 0
		00000001	00000001	3551 R1	EQU 1
		00000002	00000001	3552 R2	EQU 2
		00000003	00000001	3553 R3	EQU 3
		00000004	00000001	3554 R4	EQU 4
		00000005	00000001	3555 R5	EQU 5
		00000006	00000001	3556 R6	EQU 6
		00000007	00000001	3557 R7	EQU 7
		00000008	00000001	3558 R8	EQU 8
		00000009	00000001	3559 R9	EQU 9
		0000000A	00000001	3560 R10	EQU 10
		0000000B	00000001	3561 R11	EQU 11
		0000000C	00000001	3562 R12	EQU 12
		0000000D	00000001	3563 R13	EQU 13
		0000000E	00000001	3564 R14	EQU 14
		0000000F	00000001	3565 R15	EQU 15
				3567 *****	
				3568 * Register equates	
				3569 *****	
		00000000	00000001	3571 V0	EQU 0
		00000001	00000001	3572 V1	EQU 1
		00000002	00000001	3573 V2	EQU 2
		00000003	00000001	3574 V3	EQU 3
		00000004	00000001	3575 V4	EQU 4
		00000005	00000001	3576 V5	EQU 5
		00000006	00000001	3577 V6	EQU 6
		00000007	00000001	3578 V7	EQU 7
		00000008	00000001	3579 V8	EQU 8
		00000009	00000001	3580 V9	EQU 9
		0000000A	00000001	3581 V10	EQU 10
		0000000B	00000001	3582 V11	EQU 11
		0000000C	00000001	3583 V12	EQU 12
		0000000D	00000001	3584 V13	EQU 13
		0000000E	00000001	3585 V14	EQU 14
		0000000F	00000001	3586 V15	EQU 15
		00000010	00000001	3587 V16	EQU 16
		00000011	00000001	3588 V17	EQU 17
		00000012	00000001	3589 V18	EQU 18
		00000013	00000001	3590 V19	EQU 19
		00000014	00000001	3591 V20	EQU 20
		00000015	00000001	3592 V21	EQU 21

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES														
BEGIN	I	00000200	2	151	117	147	148	149											
CC	U	00000009	1	512	262														
CCFOUND	X	00000014	1	518	249	269													
CCMASK	U	0000000A	1	513	219														
CCMSG	U	0000031C	1	236	231														
CCPRTEXP	C	00001098	1	477	266														
CCPRTGOT	C	000010A8	1	480	273														
CCPRTLNE	C	00001055	16	472	482	276													
CCPRTLNG	U	00000055	1	482	275														
CCPRTNAME	C	00001082	8	475	259														
CCPRTNUM	C	00001065	3	473	257														
CCPSW	F	0000000C	4	517	246	684	721	758	796	833	870	908	945	982	1023	1060	1097		
					1134	1171	1208	1245	1282	1319	1356	1393	1430	1467	1504	1541	1578		
					1616	1653	1690	1727	1764	1801	1838	1875	1912	1950	1987	2024	2061		
					2098	2140	2177	2214	2251	2288	2325	2362	2399	2436	2473	2510	2547		
					2584	2621	2660	2697	2734	2771	2808	2845	2882	2920	2957	2994	3031		
					3072	3109	3146	3183	3220	3257	3295	3332	3369	3406	3446				
CTRL0	F	00000554	4	415	161	162	163	164											
DECNUM	C	000010D6	16	492	254	256	263	265	270	272	292	294	301	303	308	310			
E7TEST	4	00000000	88	506	210														
E7TESTS	F	00004254	4	3461	203														
EDIT	X	000010AA	18	487	255	264	271	293	302	309									
ENDTEST	U	00000428	1	330	208														
EOJ	I	00000538	4	405	196	333													
EOJPSW	D	00000528	8	403	405														
FAILCONT	U	00000418	1	320															
FAILED	F	00001000	4	445	280	322	331												
FAILMSG	U	000003B0	1	290	226														
FAILPSW	D	00000540	8	407	409														
FAILTEST	I	00000550	4	409	334														
FB0001	F	00000280	8	180	184	185	187												
IMAGE	1	00000000	17296	0															
K	U	00000400	1	429	430	431	432												
K64	U	00010000	1	431															
M3	U	00000007	1	510	300														
M5	U	00000008	1	511	240	307													
MB	U	00100000	1	432															
MSG	I	00000470	4	365	195	348													
MSGCMD	C	000004BE	9	395	378	379													
MSGMSG	C	000004C7	95	396	372	393	370												
MSGMVC	I	000004B8	6	393	376														
MSGOK	I	00000486	2	374	371														
MSGRET	I	000004A6	4	389	382	385													
MSGSAVE	F	000004AC	4	392	368	389													
NEXTE7	U	000002D4	1	205	229	325													
OPNAME	C	00000015	8	520	259	297													
PAGE	U	00001000	1	430															
PRT3	C	000010C0	18	490	255	256	257	264	265	266	271	272	273	293	294	295	302		
					303	304	309	310	311										
PRTLNE	C	00001008	16	454	464	314													
PRTLNG	U	0000004D	1	464	313														
PRTM3	C	00001044	3	459	304														
PRTM5	C	00001051	3	462	311														
PRTNAME	C	00001033	8	457	297														
PRTNUM	C	00001018	3	455	295														
RO	U	00000000	1	3550	111	161	164	184	186	187	188	193	212	213	275	279	280		

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES												
R1	U	00000001	1	3551	313	321	322	347	349	365	368	370	372	374	389	683	720
					757	795	832	869	907	944	981	1022	1059	1096	1133	1170	1207
					1244	1281	1318	1355	1392	1429	1466	1503	1540	1577	1615	1652	1689
					1726	1763	1800	1837	1874	1911	1949	1986	2023	2060	2097	2139	2176
					2213	2250	2287	2324	2361	2398	2435	2472	2509	2546	2583	2620	2659
					2696	2733	2770	2807	2844	2881	2919	2956	2993	3030	3071	3108	3145
					3182	3219	3256	3294	3331	3368	3405	3445					
					194	219	220	221	224	225	240	241	246	247	248	249	276
					314	331	332	379	393	678	679	680	681	715	716	717	718
					752	753	754	755	790	791	792	793	827	828	829	830	864
					865	866	867	902	903	904	905	939	940	941	942	976	977
					978	979	1017	1018	1019	1020	1054	1055	1056	1057	1091	1092	1093
					1094	1128	1129	1130	1131	1165	1166	1167	1168	1202	1203	1204	1205
					1239	1240	1241	1242	1276	1277	1278	1279	1313	1314	1315	1316	1350
					1351	1352	1353	1387	1388	1389	1390	1424	1425	1426	1427	1461	1462
					1463	1464	1498	1499	1500	1501	1535	1536	1537	1538	1572	1573	1574
					1575	1610	1611	1612	1613	1647	1648	1649	1650	1684	1685	1686	1687
					1721	1722	1723	1724	1758	1759	1760	1761	1795	1796	1797	1798	1832
					1833	1834	1835	1869	1870	1871	1872	1906	1907	1908	1909	1944	1945
					1946	1947	1981	1982	1983	1984	2018	2019	2020	2021	2055	2056	2057
					2058	2092	2093	2094	2095	2134	2135	2136	2137	2171	2172	2173	2174
					2208	2209	2210	2211	2245	2246	2247	2248	2282	2283	2284	2285	2319
					2320	2321	2322	2356	2357	2358	2359	2393	2394	2395	2396	2430	2431
					2432	2433	2467	2468	2469	2470	2504	2505	2506	2507	2541	2542	2543
					2544	2578	2579	2580	2581	2615	2616	2617	2618	2654	2655	2656	2657
					2691	2692	2693	2694	2728	2729	2730	2731	2765	2766	2767	2768	2802
					2803	2804	2805	2839	2840	2841	2842	2876	2877	2878	2879	2914	2915
					2916	2917	2951	2952	2953	2954	2988	2989	2990	2991	3025	3026	3027
3028	3066	3067	3068	3069	3103	3104	3105	3106	3140	3141	3142	3143					
3177	3178	3179	3180	3214	3215	3216	3217	3251	3252	3253	3254	3289					
3290	3291	3292	3326	3327	3328	3329	3363	3364	3365	3366	3400	3401					
3402	3403	3440	3441	3442	3443												
R10	U	0000000A	1	3560	149	158	159										
R11	U	0000000B	1	3561	216	217	686	723	760	798	835	872	910	947	984	1025	1062
					1099	1136	1173	1210	1247	1284	1321	1358	1395	1432	1469	1506	1543
					1580	1618	1655	1692	1729	1766	1803	1840	1877	1914	1952	1989	2026
					2063	2100	2142	2179	2216	2253	2290	2327	2364	2401	2438	2475	2512
					2549	2586	2623	2662	2699	2736	2773	2810	2847	2884	2922	2959	2996
					3033	3074	3111	3148	3185	3222	3259	3297	3334	3371	3408	3448	
R12	U	0000000C	1	3562	203	206	228	324									
R13	U	0000000D	1	3563													
R14	U	0000000E	1	3564													
R15	U	0000000F	1	3565	277	315	342	352	353								
R2	U	00000002	1	3552	195	253	254	261	262	263	268	269	270	291	292	299	300
					301	306	307	308	347	348	349	366	368	374	375	376	378
					384	389	390	683	684	720	721	757	758	795	796	832	833
					869	870	907	908	944	945	981	982	1022	1023	1059	1060	1096
					1097	1133	1134	1170	1171	1207	1208	1244	1245	1281	1282	1318	1319
					1355	1356	1392	1393	1429	1430	1466	1467	1503	1504	1540	1541	1577
					1578	1615	1616	1652	1653	1689	1690	1726	1727	1763	1764	1800	1801
					1837	1838	1874	1875	1911	1912	1949	1950	1986	1987	2023	2024	2060
					2061	2097	2098	2139	2140	2176	2177	2213	2214	2250	2251	2287	2288
					2324	2325	2361	2362	2398	2399	2435	2436	2472	2473	2509	2510	2546
					2547	2583	2584	2620	2621	2659	2660	2696	2697	2733	2734	2770	2771
					2807	2808	2844	2845	2881	2882	2919	2920	2956	2957	2993	2994	3030
					3031	3071	3072	3108	3109	3145	3146	3182	3183	3219	3220	3256	3257

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES				
RE43	F	00002D2C	4	2254	2235	2236	2237	2239	
RE44	F	00002DD4	4	2291	2272	2273	2274	2276	
RE45	F	00002E7C	4	2328	2309	2310	2311	2313	
RE46	F	00002F24	4	2365	2346	2347	2348	2350	
RE47	F	00002FCC	4	2402	2383	2384	2385	2387	
RE48	F	00003074	4	2439	2420	2421	2422	2424	
RE49	F	0000311C	4	2476	2457	2458	2459	2461	
RE5	F	0000143C	4	836	817	818	819	821	
RE50	F	000031C4	4	2513	2494	2495	2496	2498	
RE51	F	0000326C	4	2550	2531	2532	2533	2535	
RE52	F	00003314	4	2587	2568	2569	2570	2572	
RE53	F	000033BC	4	2624	2605	2606	2607	2609	
RE54	F	00003464	4	2663	2644	2645	2646	2648	
RE55	F	0000350C	4	2700	2681	2682	2683	2685	
RE56	F	000035B4	4	2737	2718	2719	2720	2722	
RE57	F	0000365C	4	2774	2755	2756	2757	2759	
RE58	F	00003704	4	2811	2792	2793	2794	2796	
RE59	F	000037AC	4	2848	2829	2830	2831	2833	
RE6	F	000014E4	4	873	854	855	856	858	
RE60	F	00003854	4	2885	2866	2867	2868	2870	
RE61	F	000038FC	4	2923	2904	2905	2906	2908	
RE62	F	000039A4	4	2960	2941	2942	2943	2945	
RE63	F	00003A4C	4	2997	2978	2979	2980	2982	
RE64	F	00003AF4	4	3034	3015	3016	3017	3019	
RE65	F	00003B9C	4	3075	3056	3057	3058	3060	
RE66	F	00003C44	4	3112	3093	3094	3095	3097	
RE67	F	00003CEC	4	3149	3130	3131	3132	3134	
RE68	F	00003D94	4	3186	3167	3168	3169	3171	
RE69	F	00003E3C	4	3223	3204	3205	3206	3208	
RE7	F	0000158C	4	911	892	893	894	896	
RE70	F	00003EE4	4	3260	3241	3242	3243	3245	
RE71	F	00003F8C	4	3298	3279	3280	3281	3283	
RE72	F	00004034	4	3335	3316	3317	3318	3320	
RE73	F	000040DC	4	3372	3353	3354	3355	3357	
RE74	F	00004184	4	3409	3390	3391	3392	3394	
RE75	F	0000422C	4	3449	3430	3431	3432	3434	
RE8	F	00001634	4	948	929	930	931	933	
RE9	F	000016DC	4	985	966	967	968	970	
REA1	A	00001148	4	672					
REA10	A	00001730	4	1011					
REA11	A	000017D8	4	1048					
REA12	A	00001880	4	1085					
REA13	A	00001928	4	1122					
REA14	A	000019D0	4	1159					
REA15	A	00001A78	4	1196					
REA16	A	00001B20	4	1233					
REA17	A	00001BC8	4	1270					
REA18	A	00001C70	4	1307					
REA19	A	00001D18	4	1344					
REA2	A	000011F0	4	709					
REA20	A	00001DC0	4	1381					
REA21	A	00001E68	4	1418					
REA22	A	00001F10	4	1455					
REA23	A	00001FB8	4	1492					
REA24	A	00002060	4	1529					
REA25	A	00002108	4	1566					

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
REA26	A	000021B0	4	1604	
REA27	A	00002258	4	1641	
REA28	A	00002300	4	1678	
REA29	A	000023A8	4	1715	
REA3	A	00001298	4	746	
REA30	A	00002450	4	1752	
REA31	A	000024F8	4	1789	
REA32	A	000025A0	4	1826	
REA33	A	00002648	4	1863	
REA34	A	000026F0	4	1900	
REA35	A	00002798	4	1938	
REA36	A	00002840	4	1975	
REA37	A	000028E8	4	2012	
REA38	A	00002990	4	2049	
REA39	A	00002A38	4	2086	
REA4	A	00001340	4	784	
REA40	A	00002AE0	4	2128	
REA41	A	00002B88	4	2165	
REA42	A	00002C30	4	2202	
REA43	A	00002CD8	4	2239	
REA44	A	00002D80	4	2276	
REA45	A	00002E28	4	2313	
REA46	A	00002ED0	4	2350	
REA47	A	00002F78	4	2387	
REA48	A	00003020	4	2424	
REA49	A	000030C8	4	2461	
REA5	A	000013E8	4	821	
REA50	A	00003170	4	2498	
REA51	A	00003218	4	2535	
REA52	A	000032C0	4	2572	
REA53	A	00003368	4	2609	
REA54	A	00003410	4	2648	
REA55	A	000034B8	4	2685	
REA56	A	00003560	4	2722	
REA57	A	00003608	4	2759	
REA58	A	000036B0	4	2796	
REA59	A	00003758	4	2833	
REA6	A	00001490	4	858	
REA60	A	00003800	4	2870	
REA61	A	000038A8	4	2908	
REA62	A	00003950	4	2945	
REA63	A	000039F8	4	2982	
REA64	A	00003AA0	4	3019	
REA65	A	00003B48	4	3060	
REA66	A	00003BF0	4	3097	
REA67	A	00003C98	4	3134	
REA68	A	00003D40	4	3171	
REA69	A	00003DE8	4	3208	
REA7	A	00001538	4	896	
REA70	A	00003E90	4	3245	
REA71	A	00003F38	4	3283	
REA72	A	00003FE0	4	3320	
REA73	A	00004088	4	3357	
REA74	A	00004130	4	3394	
REA75	A	000041D8	4	3434	
REA8	A	000015E0	4	933	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES	
REA9	A	00001688	4	970		
READDR	A	00000030	4	525	224	
REG2LOW	U	000000DD	1	435		
REG2PATT	U	AABBCCDD	1	434		
RELEN	A	0000002C	4	524		
RPTDWSAV	D	00000460	8	358	347	349
RPTERROR	I	00000436	4	342	277	315
RPTSAVE	F	00000454	4	355	342	352
RPTSVR5	F	00000458	4	356	343	351
SKL0001	U	0000004E	1	177	193	
SKT0001	C	0000022A	20	174	177	194
SVOLDPSW	U	00000140	0	113		
T1	A	00001118	4	658	3464	
T10	A	00001700	4	997	3473	
T11	A	000017A8	4	1034	3474	
T12	A	00001850	4	1071	3475	
T13	A	000018F8	4	1108	3476	
T14	A	000019A0	4	1145	3477	
T15	A	00001A48	4	1182	3478	
T16	A	00001AF0	4	1219	3479	
T17	A	00001B98	4	1256	3480	
T18	A	00001C40	4	1293	3481	
T19	A	00001CE8	4	1330	3482	
T2	A	000011C0	4	695	3465	
T20	A	00001D90	4	1367	3483	
T21	A	00001E38	4	1404	3484	
T22	A	00001EE0	4	1441	3485	
T23	A	00001F88	4	1478	3486	
T24	A	00002030	4	1515	3487	
T25	A	000020D8	4	1552	3488	
T26	A	00002180	4	1590	3489	
T27	A	00002228	4	1627	3490	
T28	A	000022D0	4	1664	3491	
T29	A	00002378	4	1701	3492	
T3	A	00001268	4	732	3466	
T30	A	00002420	4	1738	3493	
T31	A	000024C8	4	1775	3494	
T32	A	00002570	4	1812	3495	
T33	A	00002618	4	1849	3496	
T34	A	000026C0	4	1886	3497	
T35	A	00002768	4	1924	3498	
T36	A	00002810	4	1961	3499	
T37	A	000028B8	4	1998	3500	
T38	A	00002960	4	2035	3501	
T39	A	00002A08	4	2072	3502	
T4	A	00001310	4	770	3467	
T40	A	00002AB0	4	2114	3503	
T41	A	00002B58	4	2151	3504	
T42	A	00002C00	4	2188	3505	
T43	A	00002CA8	4	2225	3506	
T44	A	00002D50	4	2262	3507	
T45	A	00002DF8	4	2299	3508	
T46	A	00002EA0	4	2336	3509	
T47	A	00002F48	4	2373	3510	
T48	A	00002FF0	4	2410	3511	
T49	A	00003098	4	2447	3512	

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES													
T5	A	000013B8	4	807	3468													
T50	A	00003140	4	2484	3513													
T51	A	000031E8	4	2521	3514													
T52	A	00003290	4	2558	3515													
T53	A	00003338	4	2595	3516													
T54	A	000033E0	4	2634	3517													
T55	A	00003488	4	2671	3518													
T56	A	00003530	4	2708	3519													
T57	A	000035D8	4	2745	3520													
T58	A	00003680	4	2782	3521													
T59	A	00003728	4	2819	3522													
T6	A	00001460	4	844	3469													
T60	A	000037D0	4	2856	3523													
T61	A	00003878	4	2894	3524													
T62	A	00003920	4	2931	3525													
T63	A	000039C8	4	2968	3526													
T64	A	00003A70	4	3005	3527													
T65	A	00003B18	4	3046	3528													
T66	A	00003BC0	4	3083	3529													
T67	A	00003C68	4	3120	3530													
T68	A	00003D10	4	3157	3531													
T69	A	00003DB8	4	3194	3532													
T7	A	00001508	4	882	3470													
T70	A	00003E60	4	3231	3533													
T71	A	00003F08	4	3269	3534													
T72	A	00003FB0	4	3306	3535													
T73	A	00004058	4	3343	3536													
T74	A	00004100	4	3380	3537													
T75	A	000041A8	4	3420	3538													
T8	A	000015B0	4	919	3471													
T9	A	00001658	4	956	3472													
TESTCC	I	00000318	4	231	221													
TESTING	F	00001004	4	446	213													
TESTREST	U	00000300	1	223	242	282												
TNUM	H	00000004	2	508	212	253	291											
TSUB	A	00000000	4	507	216													
TTABLE	F	00004254	4	3463														
V0	U	00000000	1	3571														
V1	U	00000001	1	3572														
V10	U	0000000A	1	3581														
V11	U	0000000B	1	3582														
V12	U	0000000C	1	3583														
V13	U	0000000D	1	3584														
V14	U	0000000E	1	3585														
V15	U	0000000F	1	3586														
V16	U	00000010	1	3587														
V17	U	00000011	1	3588														
V18	U	00000012	1	3589														
V19	U	00000013	1	3590														
V1ADDR	A	00000020	4	521														
V1FUDGE	X	000010F8	16	499	215	678	715	752	790	827	864	902	939	976	1017	1054	1091	
					1128	1165	1202	1239	1276	1313	1350	1387	1424	1461	1498	1535	1572	
					1610	1647	1684	1721	1758	1795	1832	1869	1906	1944	1981	2018	2055	
					2092	2134	2171	2208	2245	2282	2319	2356	2393	2430	2467	2504	2541	
					2578	2615	2654	2691	2728	2765	2802	2839	2876	2914	2951	2988	3025	
					3066	3103	3140	3177	3214	3251	3289	3326	3363	3400	3440			

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES
V101	X	00001158	16	674	685
V1010	X	00001740	16	1013	1024
V1011	X	000017E8	16	1050	1061
V1012	X	00001890	16	1087	1098
V1013	X	00001938	16	1124	1135
V1014	X	000019E0	16	1161	1172
V1015	X	00001A88	16	1198	1209
V1016	X	00001B30	16	1235	1246
V1017	X	00001BD8	16	1272	1283
V1018	X	00001C80	16	1309	1320
V1019	X	00001D28	16	1346	1357
V102	X	00001200	16	711	722
V1020	X	00001DD0	16	1383	1394
V1021	X	00001E78	16	1420	1431
V1022	X	00001F20	16	1457	1468
V1023	X	00001FC8	16	1494	1505
V1024	X	00002070	16	1531	1542
V1025	X	00002118	16	1568	1579
V1026	X	000021C0	16	1606	1617
V1027	X	00002268	16	1643	1654
V1028	X	00002310	16	1680	1691
V1029	X	000023B8	16	1717	1728
V103	X	000012A8	16	748	759
V1030	X	00002460	16	1754	1765
V1031	X	00002508	16	1791	1802
V1032	X	000025B0	16	1828	1839
V1033	X	00002658	16	1865	1876
V1034	X	00002700	16	1902	1913
V1035	X	000027A8	16	1940	1951
V1036	X	00002850	16	1977	1988
V1037	X	000028F8	16	2014	2025
V1038	X	000029A0	16	2051	2062
V1039	X	00002A48	16	2088	2099
V104	X	00001350	16	786	797
V1040	X	00002AF0	16	2130	2141
V1041	X	00002B98	16	2167	2178
V1042	X	00002C40	16	2204	2215
V1043	X	00002CE8	16	2241	2252
V1044	X	00002D90	16	2278	2289
V1045	X	00002E38	16	2315	2326
V1046	X	00002EE0	16	2352	2363
V1047	X	00002F88	16	2389	2400
V1048	X	00003030	16	2426	2437
V1049	X	000030D8	16	2463	2474
V105	X	000013F8	16	823	834
V1050	X	00003180	16	2500	2511
V1051	X	00003228	16	2537	2548
V1052	X	000032D0	16	2574	2585
V1053	X	00003378	16	2611	2622
V1054	X	00003420	16	2650	2661
V1055	X	000034C8	16	2687	2698
V1056	X	00003570	16	2724	2735
V1057	X	00003618	16	2761	2772
V1058	X	000036C0	16	2798	2809
V1059	X	00003768	16	2835	2846
V106	X	000014A0	16	860	871

SYMBOL	TYPE	VALUE	LENGTH	DEFN	REFERENCES					
X42	F	00002C58	4	2207	2188					
X43	F	00002D00	4	2244	2225					
X44	F	00002DA8	4	2281	2262					
X45	F	00002E50	4	2318	2299					
X46	F	00002EF8	4	2355	2336					
X47	F	00002FA0	4	2392	2373					
X48	F	00003048	4	2429	2410					
X49	F	000030F0	4	2466	2447					
X5	F	00001410	4	826	807					
X50	F	00003198	4	2503	2484					
X51	F	00003240	4	2540	2521					
X52	F	000032E8	4	2577	2558					
X53	F	00003390	4	2614	2595					
X54	F	00003438	4	2653	2634					
X55	F	000034E0	4	2690	2671					
X56	F	00003588	4	2727	2708					
X57	F	00003630	4	2764	2745					
X58	F	000036D8	4	2801	2782					
X59	F	00003780	4	2838	2819					
X6	F	000014B8	4	863	844					
X60	F	00003828	4	2875	2856					
X61	F	000038D0	4	2913	2894					
X62	F	00003978	4	2950	2931					
X63	F	00003A20	4	2987	2968					
X64	F	00003AC8	4	3024	3005					
X65	F	00003B70	4	3065	3046					
X66	F	00003C18	4	3102	3083					
X67	F	00003CC0	4	3139	3120					
X68	F	00003D68	4	3176	3157					
X69	F	00003E10	4	3213	3194					
X7	F	00001560	4	901	882					
X70	F	00003EB8	4	3250	3231					
X71	F	00003F60	4	3288	3269					
X72	F	00004008	4	3325	3306					
X73	F	000040B0	4	3362	3343					
X74	F	00004158	4	3399	3380					
X75	F	00004200	4	3439	3420					
X8	F	00001608	4	938	919					
X9	F	000016B0	4	975	956					
XC0001	U	000002D0	1	197	189					
ZVE7TST	J	00000000	17296	110	113	115	119	123	444	111
=A(E7TESTS)	A	0000056C	4	421	203					
=AL2(L' MSGMSG)	R	0000057A	2	425	370					
=D' 1'	D	00000560	8	419	241					
=F' 1'	F	00000574	4	423	279	321				
=F' 64'	F	00000568	4	420	188					
=H' 0'	H	00000578	2	424	365					
=XL4' 3'	X	00000570	4	422	248					

MACRO	DEFN	REFERENCES																
FCHECK PTTABLE VRR_A	63	170																
	611	3462																
	546	655	692	729	767	804	841	879	916	953	994	1031	1068	1105	1142	1179	1216	1253
		1290	1327	1364	1401	1438	1475	1512	1549	1587	1624	1661	1698	1735	1772	1809	1846	1883
		1921	1958	1995	2032	2069	2111	2148	2185	2222	2259	2296	2333	2370	2407	2444	2481	2518
		2555	2592	2631	2668	2705	2742	2779	2816	2853	2891	2928	2965	3002	3043	3080	3117	3154
		3191	3228	3266	3303	3340	3377	3417										

DESC	SYMBOL	SIZE	POS	ADDR
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Entry: 0

Image	IMAGE	17296	0000-438F	0000-438F
Regi on		17296	0000-438F	0000-438F
CSECT	ZVE7TST	17296	0000-438F	0000-438F

STMT	FILE NAME
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1	/home/tn529/sharedvfp/tests/zvector-e7-08-VISTR.asm
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**** NO ERRORS FOUND ****